

SPIRE SPT EMC Test Report

Ref: SPIRE-RAL-REP-003164

Issue: 1.0

Date: 17/11/2008

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Change Control

Issue	Change	Date
0.1	As initially issued for discussion during JPL telecon	
1.0	Issued for IFAR Co-location meeting	17/11/2008

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1. Introduction

This document reports on the analysis of the EMC tests carried out within the scope of the Herschel/SPIRE SPT tests at ESTEC from 20/08/2008 to 23/08/2008.

2. Reference and Applicable Documents

RD	Name	Doc Number
RD 1	SPIRE SPT EMC CS Pre-calibration test	SPIRE-RAL-REP-003039
RD 2	SPIRE PFM5 EMC Test Report	SPIRE-RAL-REP-002852
RD 3	SPIRE CS Test Levels for SPT	SPIRE-RAL-NOT-003041
RD 4	SPIRE IST Specific Performance Test Procedures	SPIRE-RAL-PRC-002704, Iss. 3
RD 5	Herschel FM Radiated EMC Test in Clean Room Facility Data Report	ETS-REP-EMC-2574, Iss 2
RD 6	NHSC / IPAC SPIRE wiki site https://nhscdmz1.ipac.caltech.edu/pmwiki/pmwiki.php/Spire/HomePage	N/A

3. Test Configuration

3.1 EUT Summary

Item	Description
FPU	PFM
Cryoharness	FM
WIH	FM
DCU	PFM
PSU	PFM
FCU	PFM
DPU	PFM
DPU 28V Power Harness	PFM
FCU/PSU 28V Power Harness	PFM with in-line test adaptor
SVM	PFM
PCDU	PFM

3.2 Test Equipment

Item	Description
Test Adaptor	DB01-J04 as per Figure 2 and Figure 3
BCI Clamp	8-50MHz F-130A
Current Clamp Probe	8-50MHz F-16
Signal generator	8-100MHz Agilent HP 33250
RF Amplifier	8-100MHz Amplifier Research 50WD1000
Spectrum Analyzer	HP4395A
Digital Oscilloscope	With isolated inputs

Item

Test equipment benches / supports etc.
Inline power meter

Description

Sufficient bench space and/or secure locations to mount the test equipment close to the Test Adaptor
R&S NRP

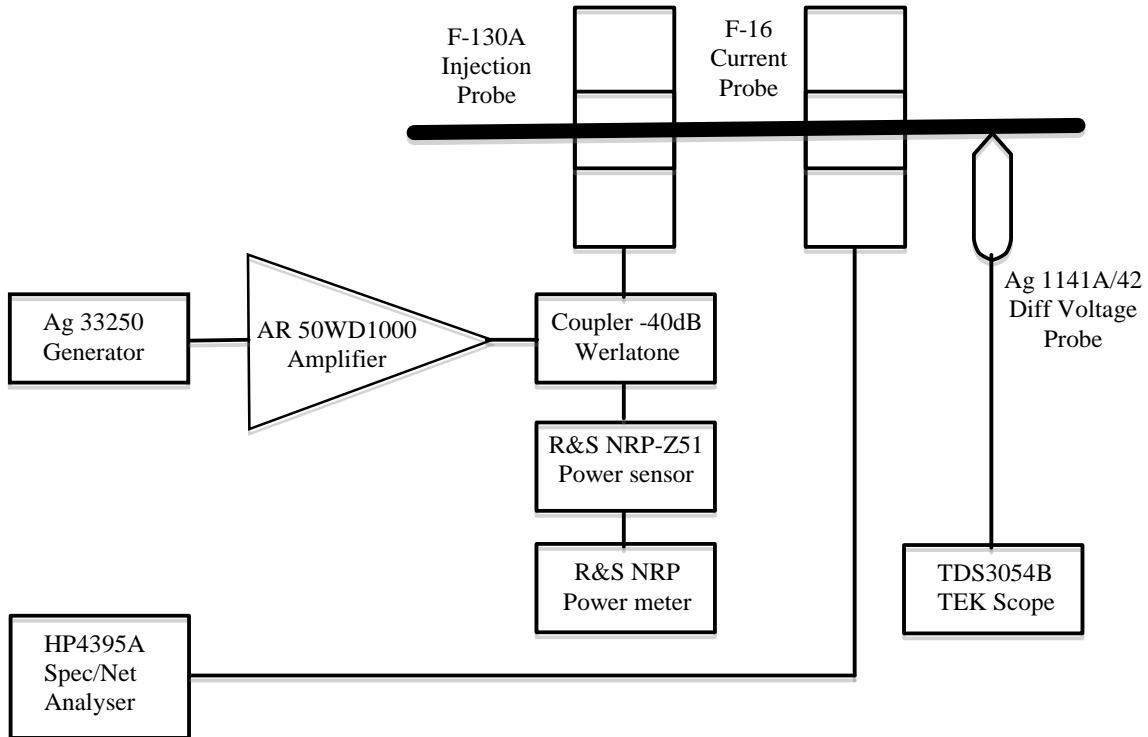


Figure 1 – Schematic of conducted susceptibility test setup

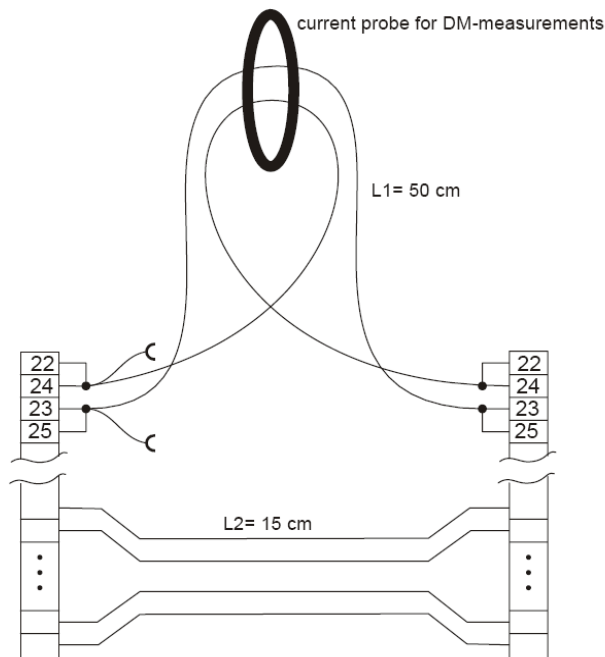


Figure 2 – Test adaptor configuration. Wires to be 20AWG

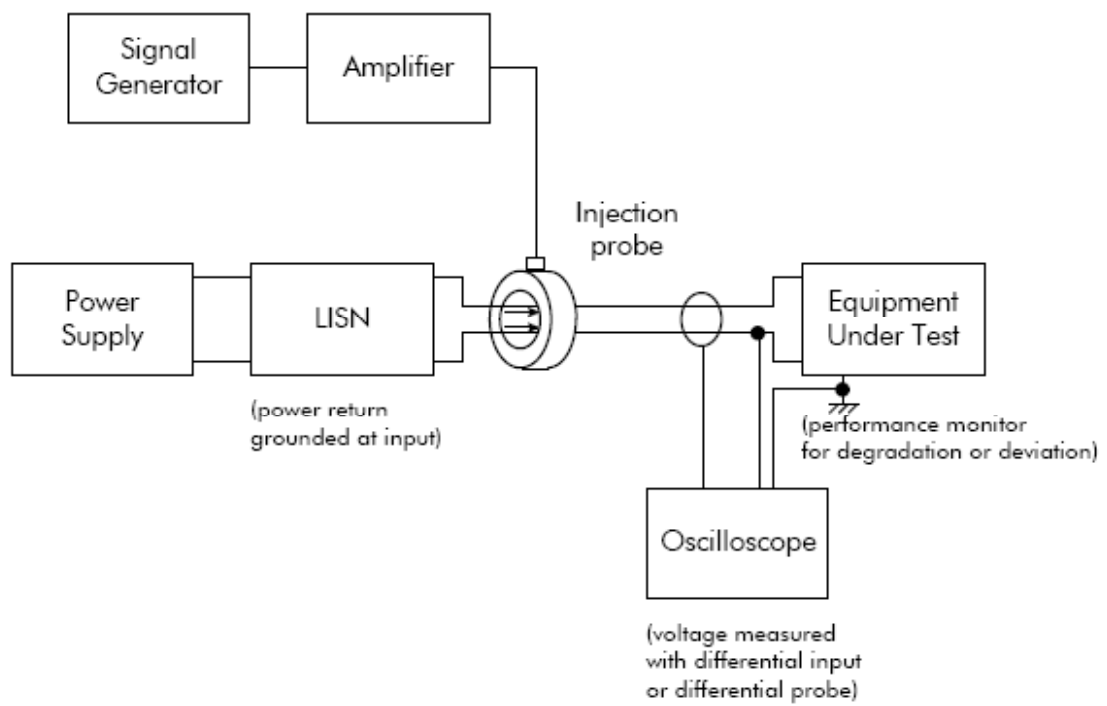


Figure 5 - CM configuration

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4. Test Sequence

Test Description	ObsID
CS DM Phot. mode	0xB00014BE
CS DM Spect. Mode	0xB00014C7
CS CM Phot. Mode	0xB00014D8
CS CM Spect. Mode	0xB00014E1
RS test, Spect. Mode Vertical Polarization	0xB00014E3
RS test, Phot. Mode Vertical Polarization	0xB00014EB (Step 1)
RS test, Phot. Mode Horizontal Polarization	0xB00014EB (Step 2)

5. Discussion and Conclusions

5.1 Radiated Emissions

A measurement of the ambient E-Field in the clean room environment was added to the SPT procedure for the instruments when it was decided that there was to be no spacecraft RS testing with the Herschel instruments in their most sensitive modes in the Maxwell facility. In its place, the revised approach to RS testing of SPIRE in the Herschel cryostat foresaw that a comparison of;

1. the E-Field spectrum measured during the RE tests in the Maxwell facility with the instruments/spacecraft in their most noisy modes,
2. measurements of the ambient levels during the SPT test, and
3. measurements of the detector noise levels during the SPT with the detectors in their most sensitive mode,

would provide the necessary information to provide an indication of the level of auto-compatibility of SPIRE with the rest of the Herschel spacecraft. For both test setups, the field was measured in a location close to the SPIRE Cryoharness. For information only, the results of the E-Field measurements are reported in Appendix 4. In the frequency band of 10-100MHz, where SPIRE has been found to be most susceptible to EMI in the EQM and SPT2 test, the levels are close to each other except for a narrow range around 30MHz, where the levels in the SPT tests are 10-20 dB lower than the tests in the Maxwell facility. This implies that the EM environment in the SPT was more benign in this band than the RE test in the Maxwell facility. One possible explanation for the discrepancy between the measurements in the Maxwell facility and the clean room was the presence of cryo-GSE and aluminium scaffolding which could afford a level of electromagnetic shielding/attenuation to the environment near to the SPIRE cryoharnesses at certain frequencies. The discrepancy could also be explained by subtle differences in the location and precise geometry of the measurement antennas in the two configurations.

During the SPIRE SPT, the noise performance of the instrument was measured under various bias levels and frequencies. The results are documented in RD6. For the Photometer, the noise levels as indicated by the criteria of NEP are slightly better than the levels measured during ILT (PFM5 in particular). Overall, the spectrometer noise performance is comparable with the performance seen in ILT, although the SLW array shows slightly higher noise levels. This excess noise is described as being due to "signal wiggling" in the time domain, and therefore confined to the low frequency portion of the detector response spectrum. This would give rise to an increase in the 1/f noise floor of the detectors. There is an indication from the noise measurements that there is excess optical power on some of the detectors (PSW, PMW, PLW and SSW).

The conclusions therefore from the RE and noise measurements are as follows:

- The ambient levels measured during the SPT test are slightly lower in some spectral bands (in particular around 30MHz), and therefore there is a negative margin on the field amplitudes with respect to the RE test in some portions of the spectrum

- The detector noise performance does not indicate any major compliance issues and is in-line with the ILT performance results
- Within the caveats stated, SPIRE has been shown auto-compatibility with Herschel in the clean room environment.

5.2 Susceptibility Tests

The detector data collected during the radiated and conducted susceptibility tests was processed according to the following procedure:

1. The start and end times of the period during which EMI was injected was determined from the instrument housekeeping telemetry
2. The detector science data for this period was extracted from the database and separated into ten second segments.
3. A second order polynomial was fitted to each of these timelines and then subtracted from the data in an attempt to remove the DC offset and compensate for thermal drifts in the data
4. The Power Spectral Density of each of these traces was calculated and then averaged across all the ten second data segments.
5. The average PSD was estimated from the overall rms signal level and the signal bandwidth of the measurement.

The data is presented in two formats;

1. 2D X-Y Plots of the average PSD against the test frequency. These plots allow quick identification of detector channels which demonstrate an increase in the overall noise amplitude under the test.
2. 2D contour plots of the PSD with frequency on the horizontal axis, test number on the vertical axis and plot colour representing PSD.

There are several features of the detector science data need to be explained when interpreting the results.

1. The detector output occasionally shows an impulse response to an unknown stimulation. The rise time of this is less than the sampling period. The recovery time is longer, but much shorter than the thermal time constant of the bolometers. This behaviour was seen on several occasions. The effect of this is to indicate a large increase in the noise level in the detector, particularly in the X-Y noise plots. As this behaviour is known to occur randomly during nominal detector operation, it is assumed that it is not correlated with the EMI injection.
2. Temperature fluctuations within the cryostat will in general influence the thermal equilibrium of the instrument and cause temperature fluctuations in the 300-mK system. These fluctuations are identified by a change in the level and/or slope of the DC offset of all the detectors in the array.
3. Apart from the normal detectors which are sensitive to sub-mm optical sources, there are also several extra detectors in each array which are not optically sensitive. These include, (1) dark pixels which are identical to the normal detectors apart from the fact that they have no feed horns to couple radiation, (2) thermistor detectors which are directly mounted on the 300-mK bath and (3) resistor channels which have identical readout to the other detectors, but have a constant impedance and therefore no response to temperature changes. These different detector channels can be used to discriminate between different types of power coupled onto the detectors.

5.3 Conducted Susceptibility

The process results from the Differential mode tests are presented in Appendix 1 and the processed results from the Common Mode tests are presented in Appendix 2.

The following general remarks and conclusions can be made:

- In the DM test of the Photometer detectors, an apparent susceptibility appears at a test injection frequency of ~ 24 MHz. This has been identified as a being due to a change in temperature of a non-optical source, most probably the lid. In particular, it is noted that the non-optical detectors show no response to the disturbance. Furthermore, as the disturbance is identified in the PLW detector array and not, the PMW or PSW arrays, it can be concluded that the temperature of the source is less than ~ 10K, which makes the lid of the cryostat a likely candidate. It should be noted that the spacecraft thermometry of the lid is not capable of measuring these levels of temperature fluctuations.
- The spectrogrammes for the DM spectrometer tests show narrow band spectral lines at an intensity level higher than the general noise levels. This is similar to the response of the PMW detectors to a continuous, un-modulated conducted DM disturbance during the PFM5 ILT test where such a feature was seen at ~1.5Hz. Careful examination of the data reveals that the spectral features are present during the reference cases before and after the disturbance injection, and therefore the source of the features cannot be correlated with EMI. The source of the disturbance could possibly be attributed to microphonics but no definite conclusions can be made.
- Several instances of detectors suffering from impulse response have been observed. They are identified in the tables of power spectral density vs. test frequency.
- Several detectors show excess noise, but are known to have degraded performance and show no correlation with the injected EMI.
- In the Photometer CM PLW spectrogrammes show an apparent increase in the noise spectral density at low detector signal frequencies. This noise increases as the injected frequency increases. This excess noise is attributed to temperature fluctuations of an object which is optically coupled to the detector arrays. The basis for this conclusion is the fact that the disturbances are confined to the optically active detectors on the PLW array and that the band of the noise is very low (in the 100 mHz range) which corresponds to the expected periods of temperature fluctuations in the cryostat and not related to the EMI disturbance. Furthermore, the level of the amplitude of the excess noise does not change between the highest injection frequency case (50MHz) and the last reference test when the injection was switched off.
- Apart from the anomalies noted above, no correlation of the detector noise can be made with the injected CM or DM EMI.
- Given that the level of the injected disturbance was more than 6dB above the levels measured on the SPIRE FCU primary power lines during the Spacecraft CE tests and that previous susceptibilities have shown a power law dependency, it can be concluded that there is at least 12dB of margin.

5.4 Radiated Susceptibility

Three separate RS E-Field tests were carried out; two in photometer mode: one with Vertical polarization and the other in Vertical polarization. The last test was in spectrometer mode vertical polarization. The process test results are reported in Appendix 4. The following comments and conclusions are noted:

- The general comments and conclusions for the radiated tests are similar to those for the conducted test in that the excess noise seen on the detectors can be attributed to temperature fluctuations of objects optically coupled to the detectors. The exception to this

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is the behaviour of DP1 and DP2 which showed variations in the level of noise (in the low frequency end of the detector response spectrum).

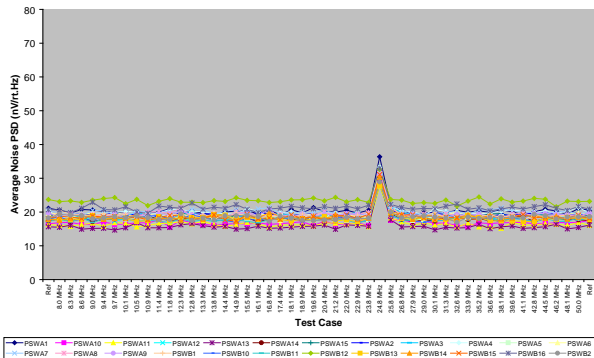
- There is a considerable level of un-certainty in the injected levels due to the presence of cryo-GSE and aluminium scaffolding in close proximity to the radiating antenna. This could either raise or lower the local field strength in the proximity of the SPIRE cryoharness.
- Given these comments, it can be concluded that the instrument does not show any serious radiated susceptibilities.

6. Appendix 1: CS Differential Mode Detailed Results

6.1 CS Differential Mode – Photometer (0xB00014BE)

6.1.1 Noise PSD (using 49 seconds of detector data)

CS DM Photometer Mode Average PSD Across PSW, PMW and PLW Arrays
(49 Second step length)



PSW

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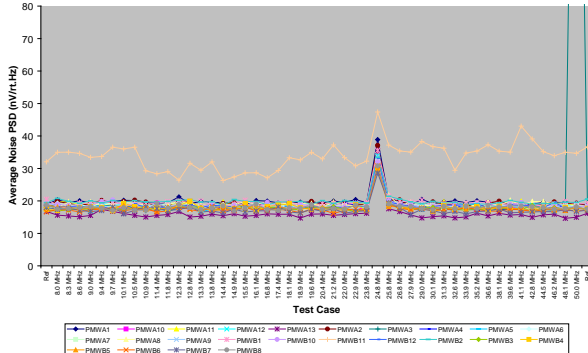
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CS DM Photometer Mode Average PSD Across PSW, PMW and PLW Arrays (49 Second step length)



PMW B11 Noisy; PMW A3 "spikes"

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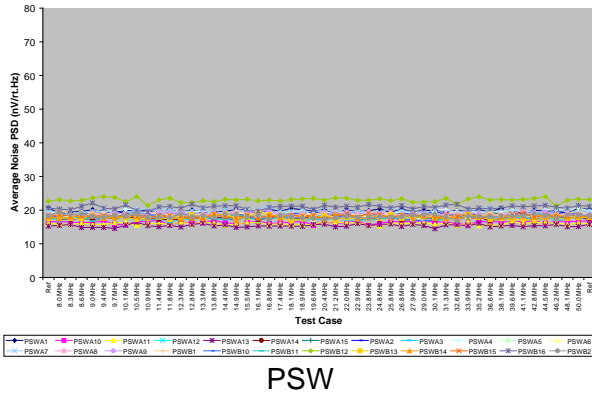
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6.1.2 Noise PSD (Averaged using N 10 second "chunks" of detector data)

CS DM Photometer Mode Average PSD Across PSW, PMW and PLW Arrays
(10 Second step length – Ensemble averaged)



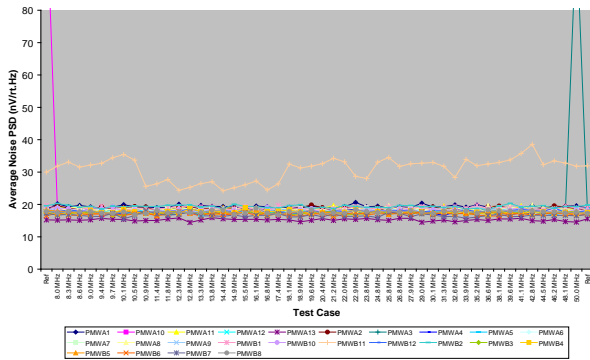
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PMW B11 Noisy; PMW **A10** and A3 “spike”

6.1.3 PSW Spectrogrammes

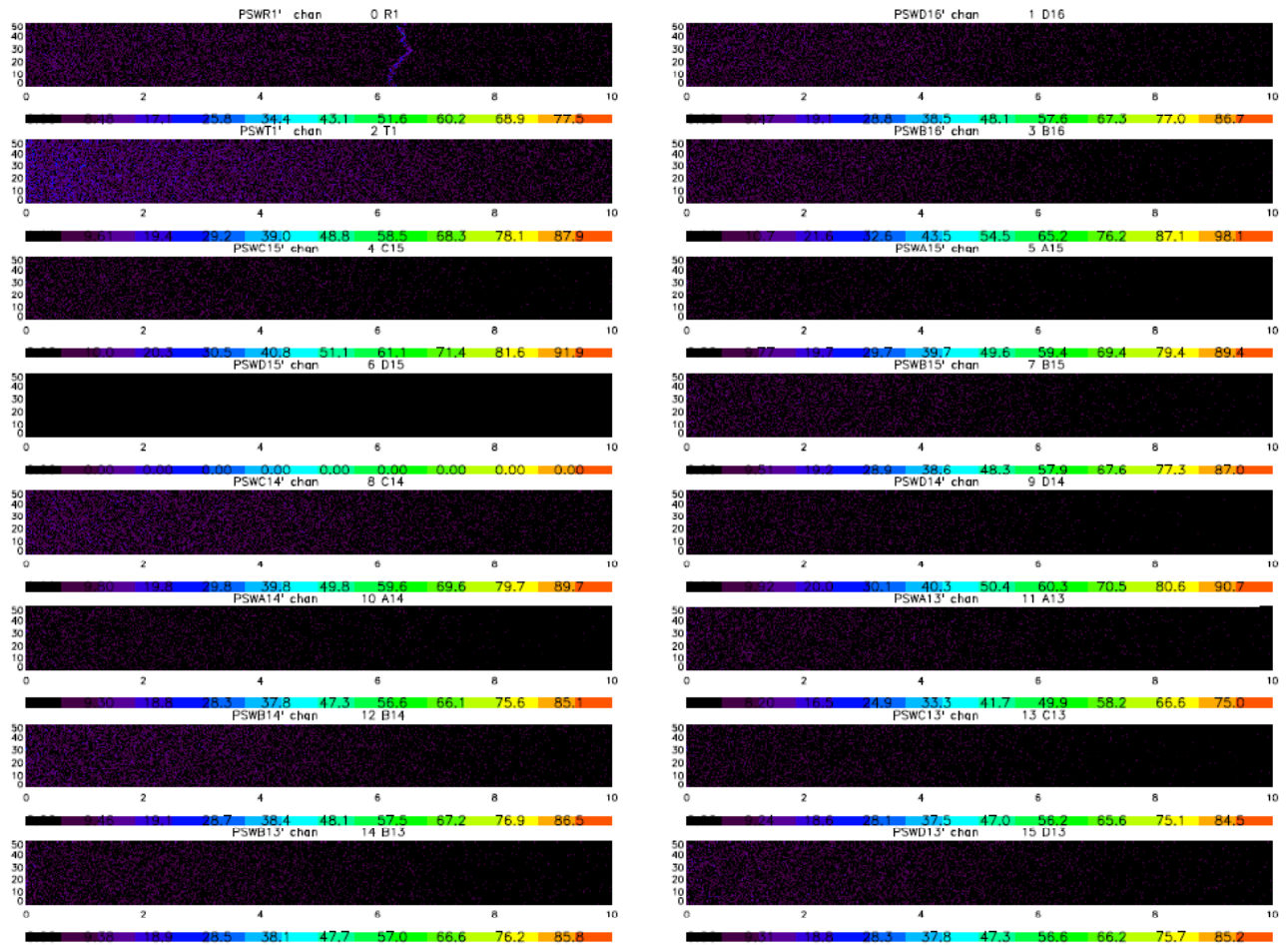


Figure 6 – PSW R1 shows spectral feature. Feature present in reference tests.

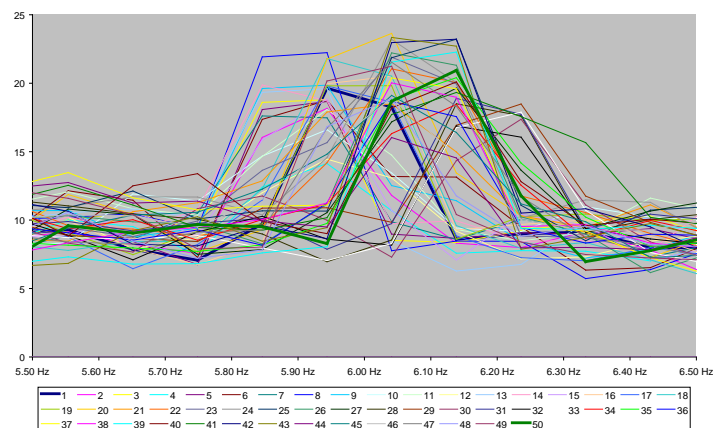


Figure 7 - PSW R1 spectra. Reference tests; Steps 1 and 50 (highlighted blue and green) show spectra feature during the rest of the test indicating that there is no excess EMI on the detector

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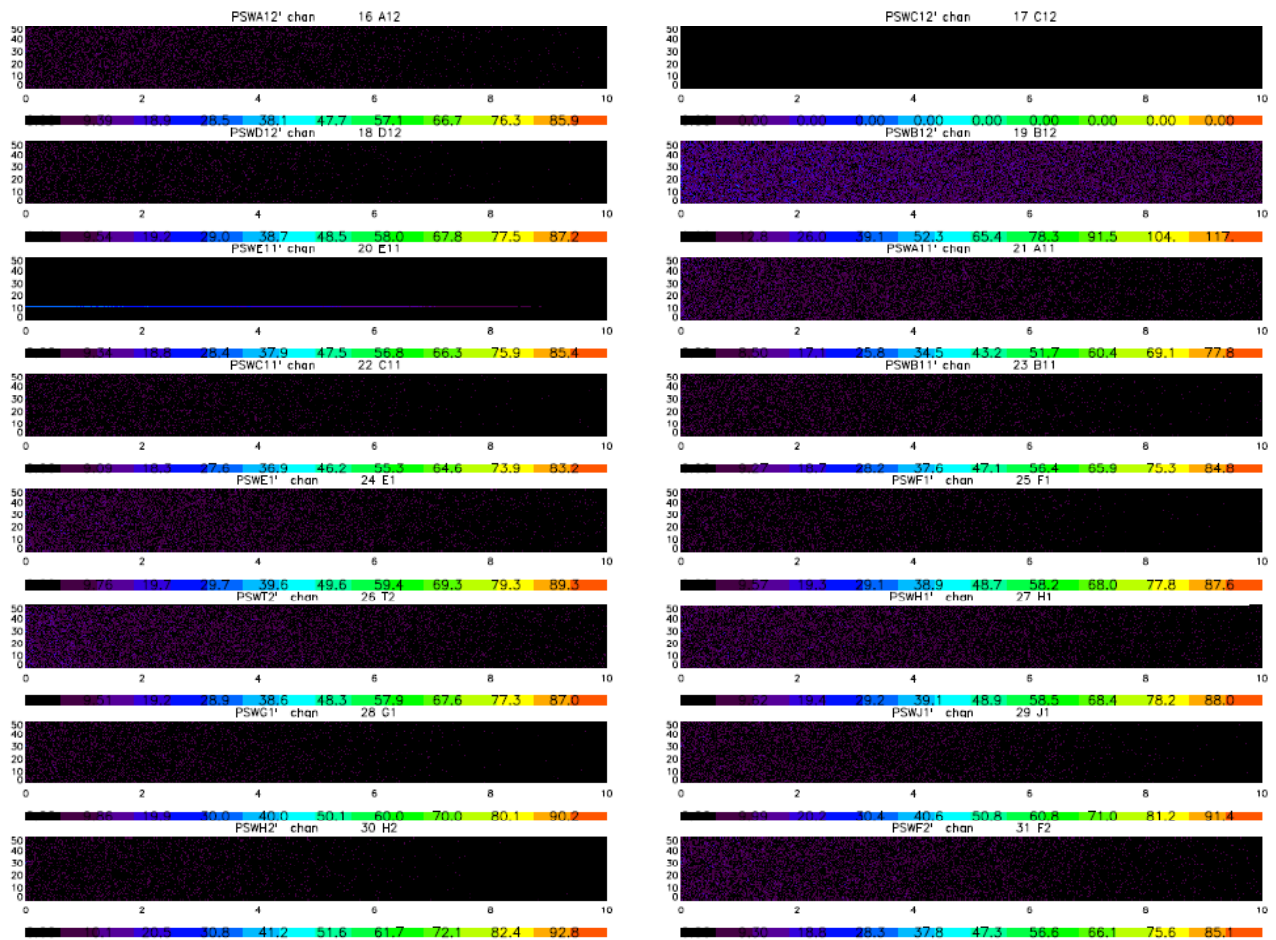


Figure 8 – Detector PSW E11“drops out”

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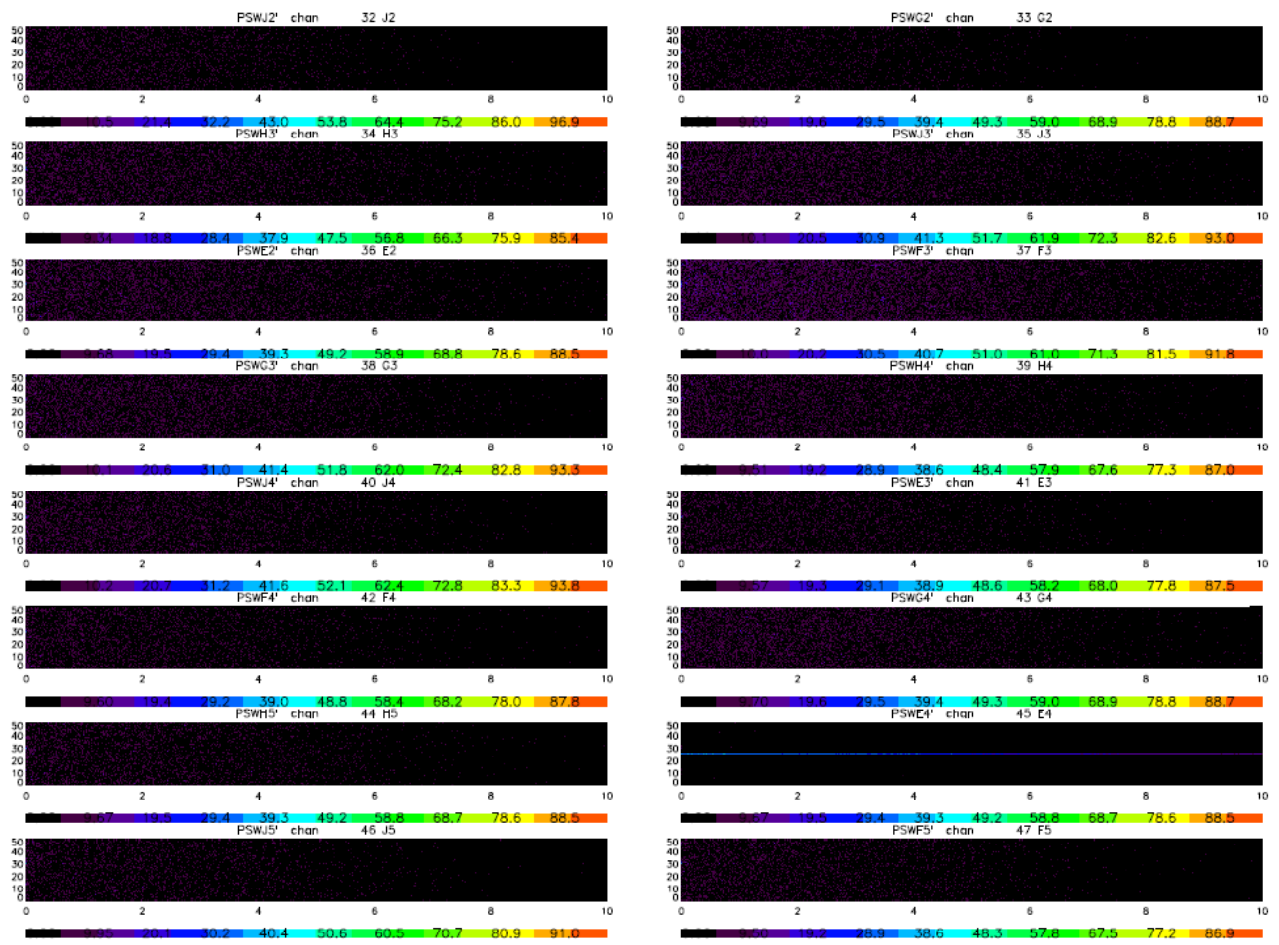


Figure 9 – PSW E4 shows a “drop out”

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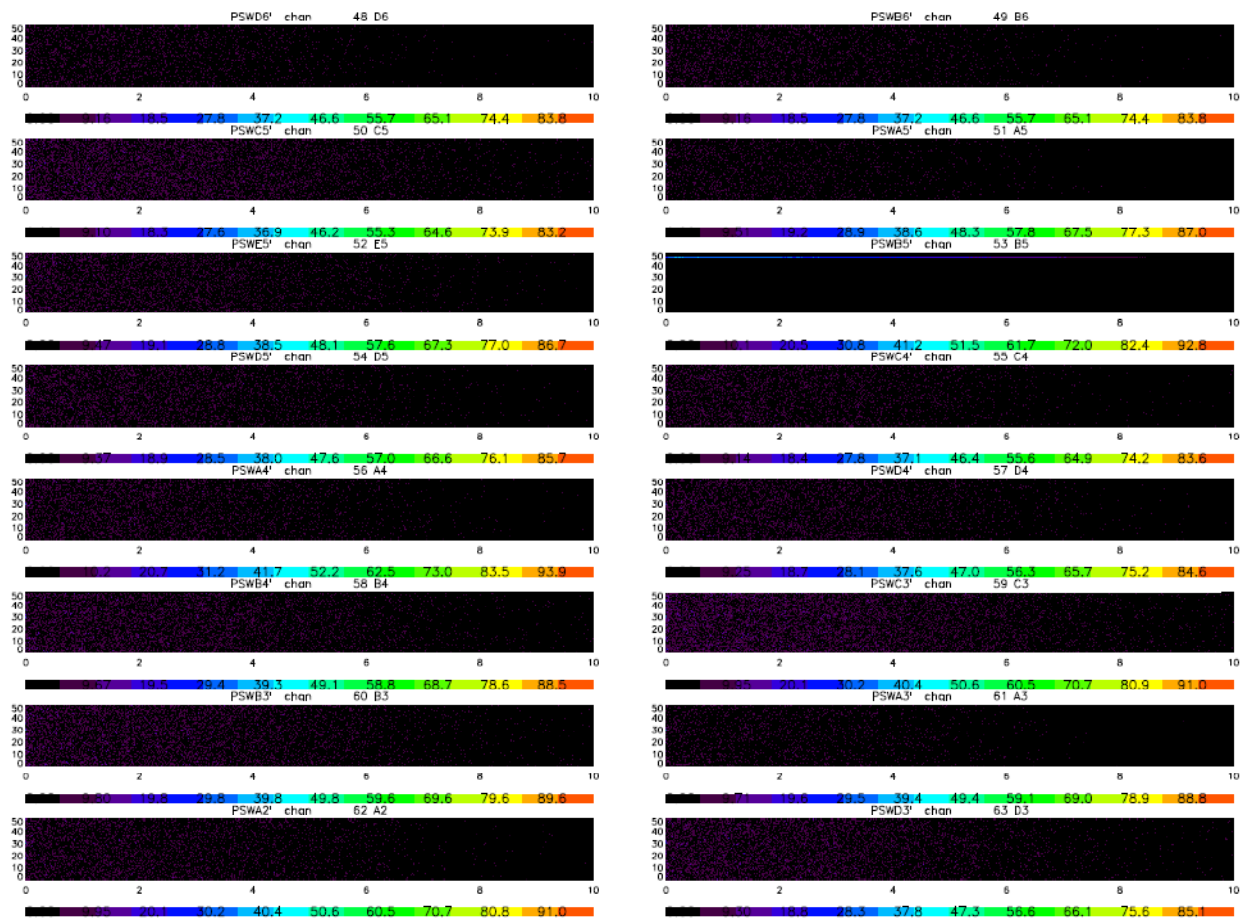


Figure 10

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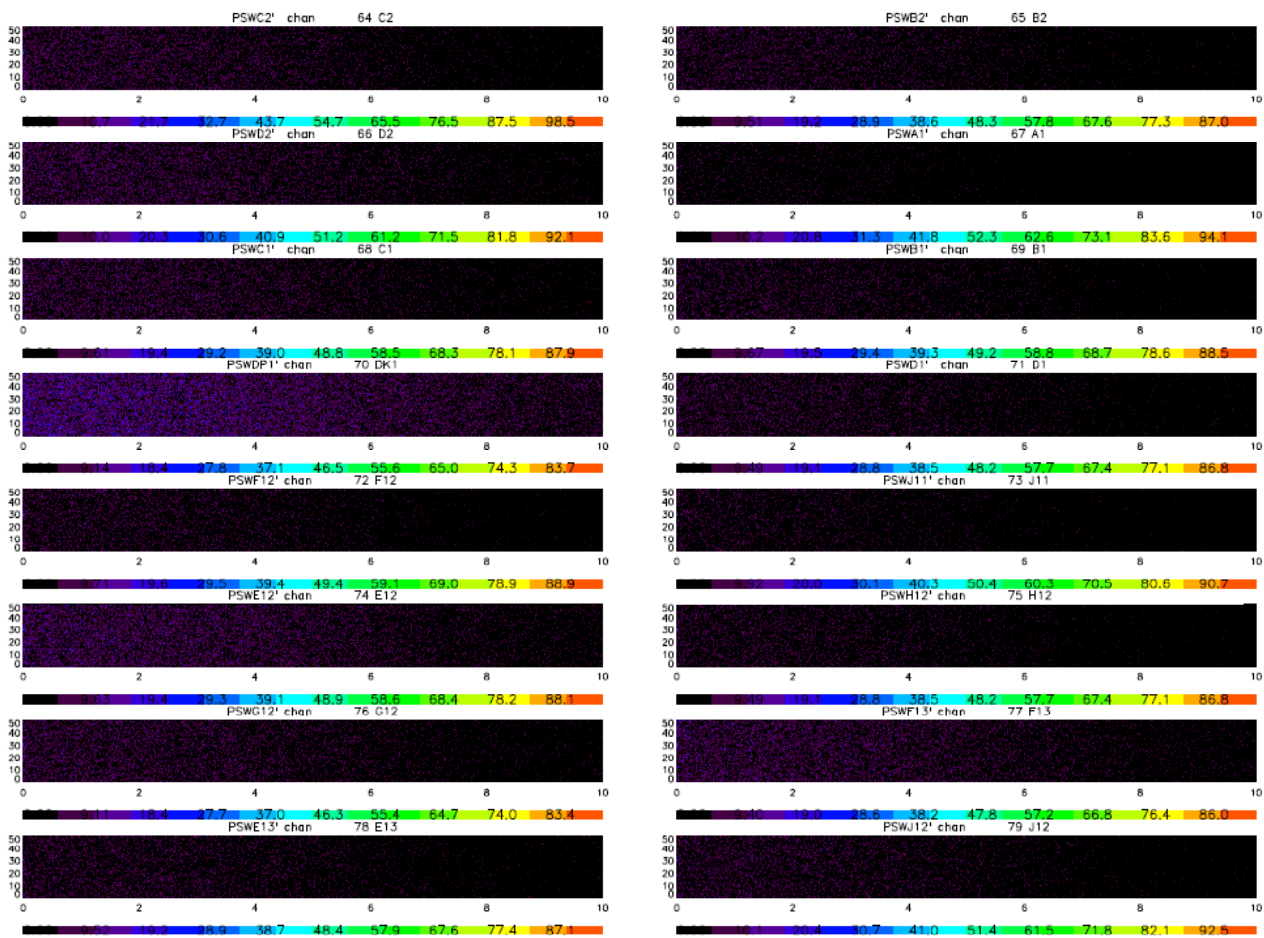


Figure 11

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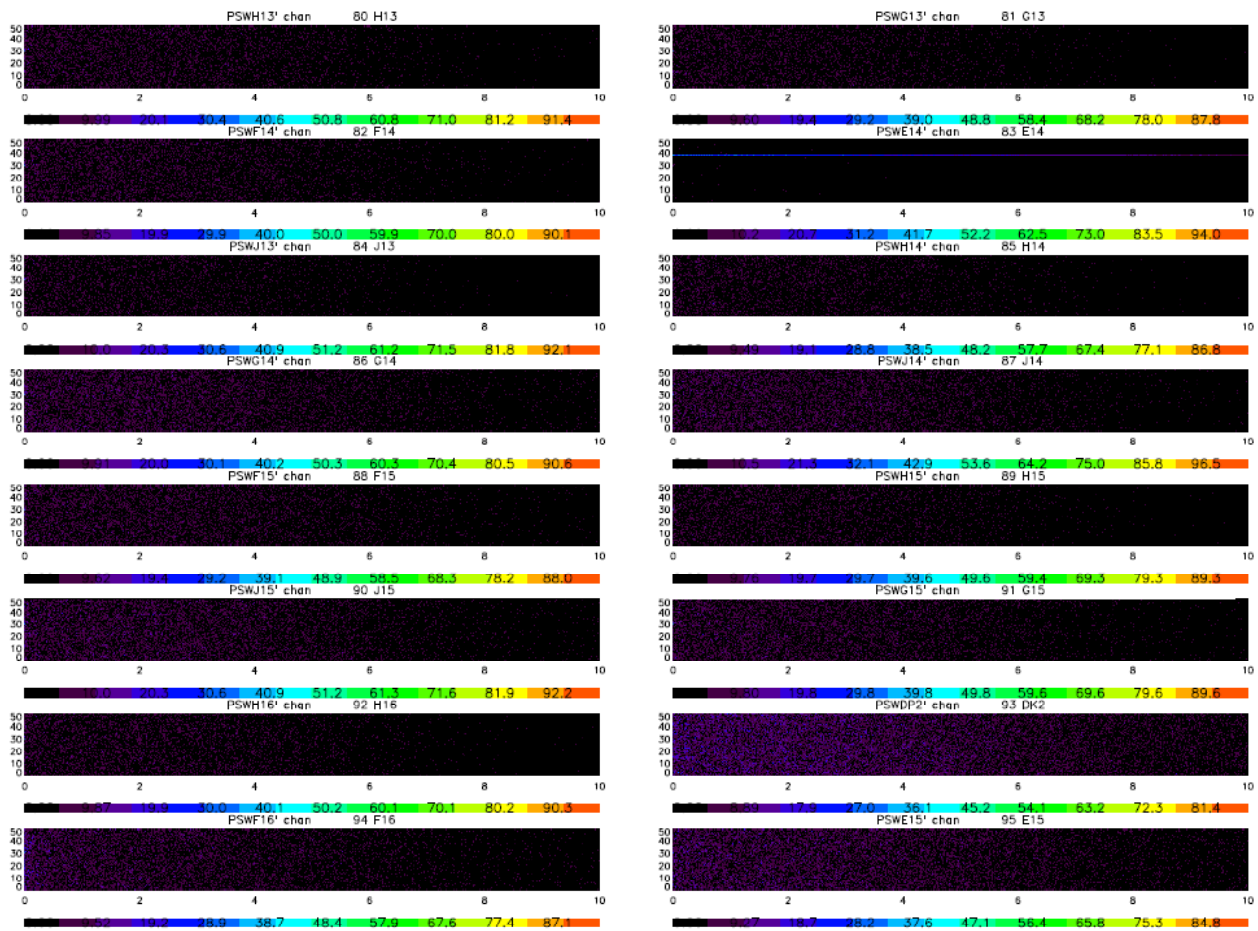


Figure 12

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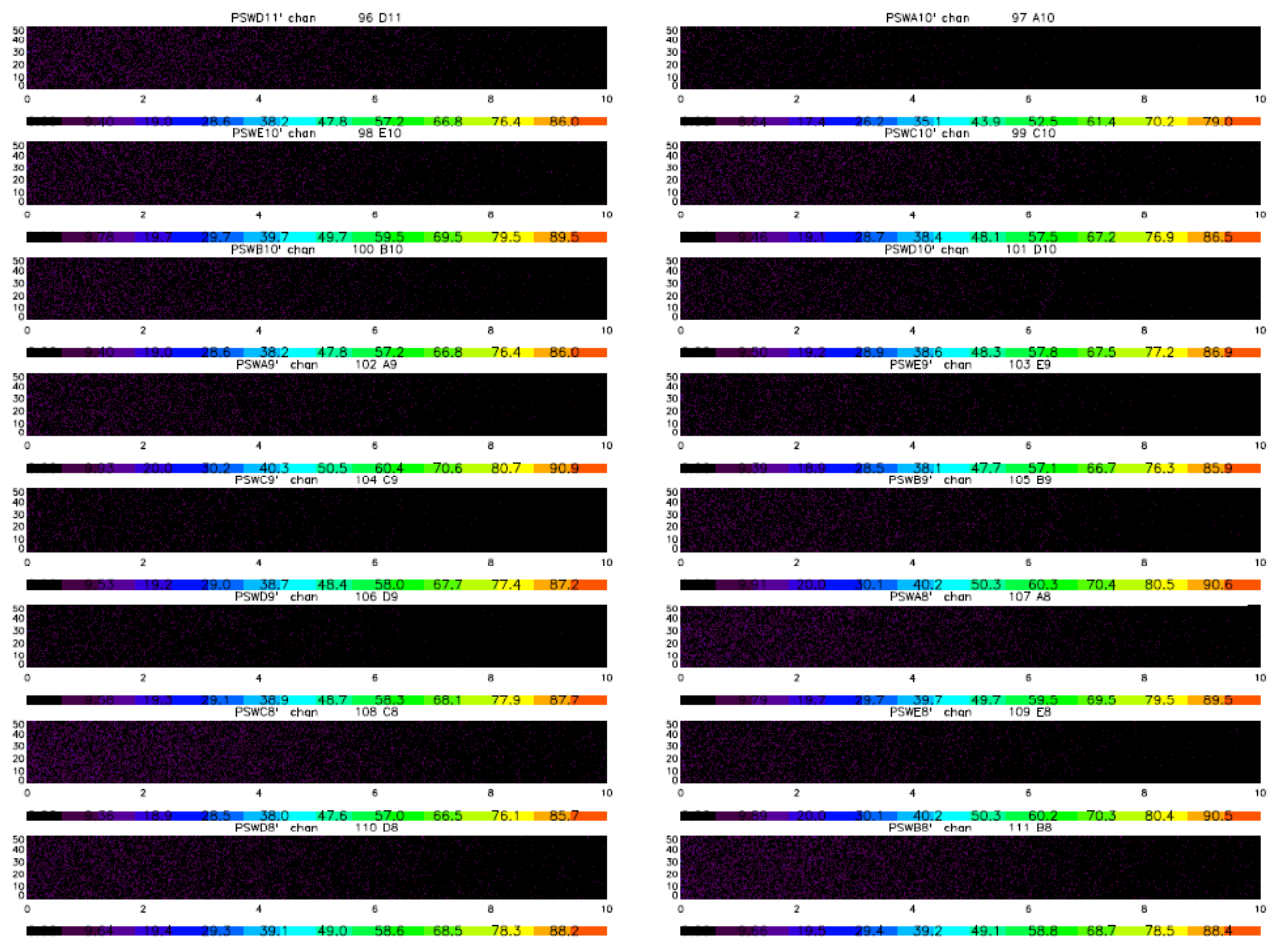


Figure 13

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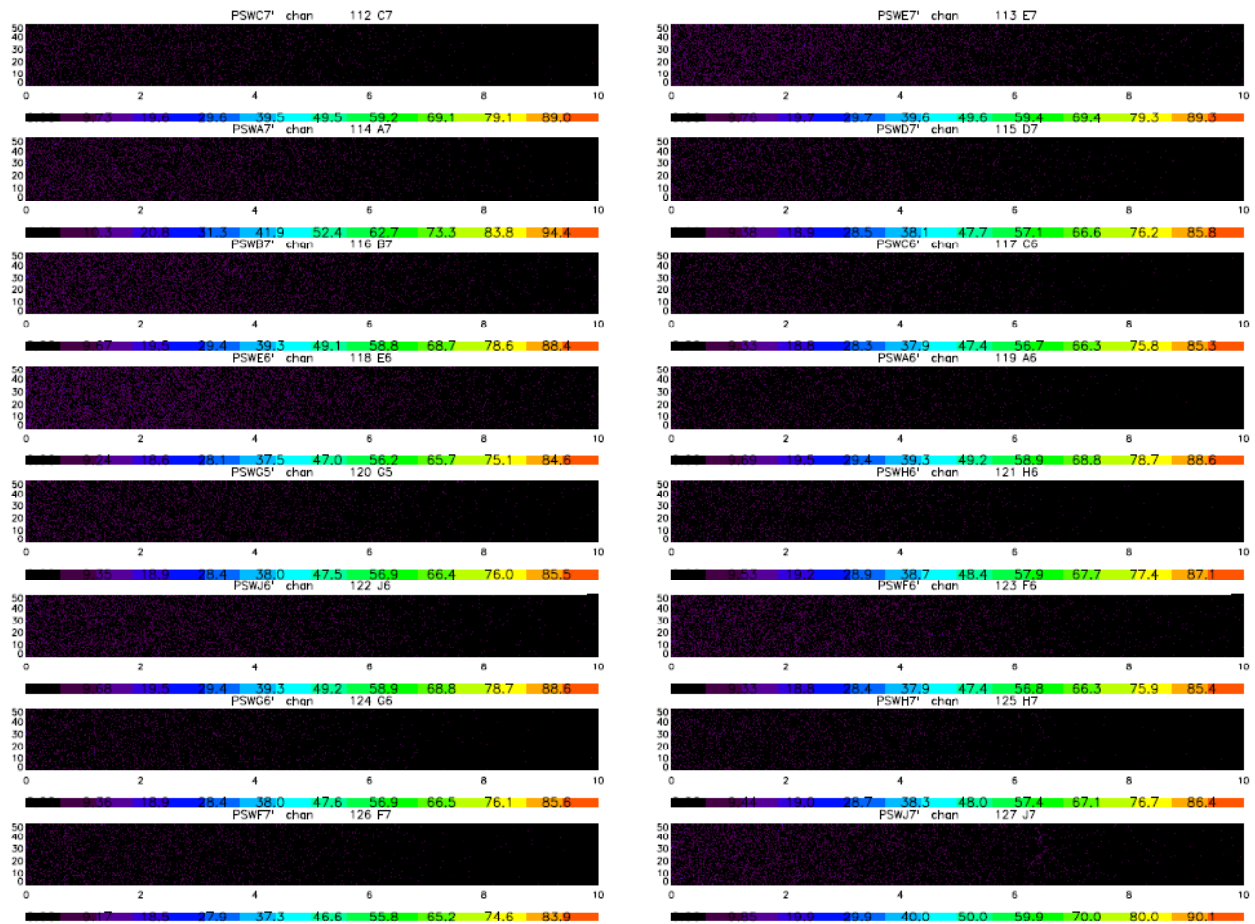


Figure 14

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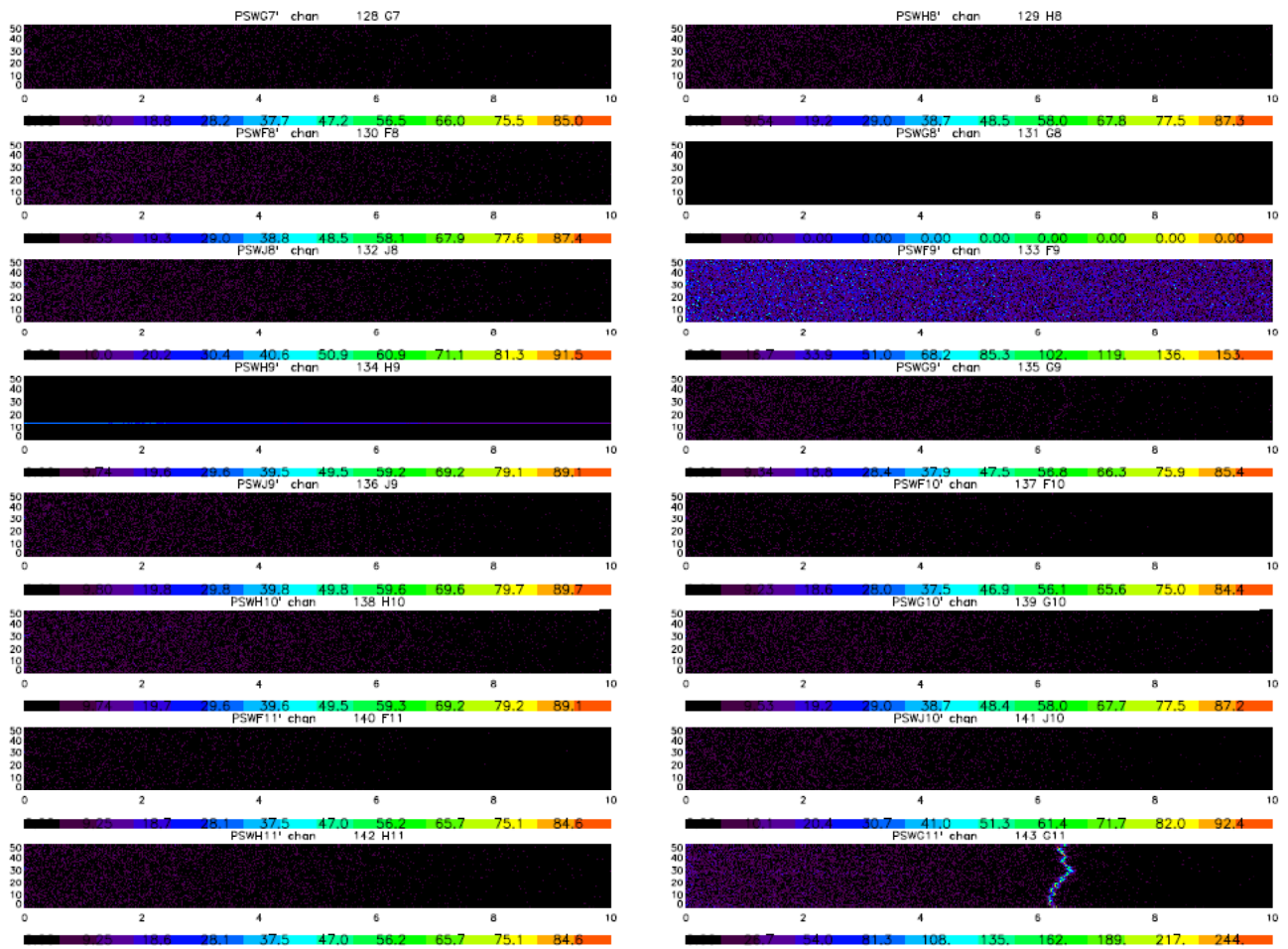


Figure 15

6.1.4 PMW Spectrogrammes

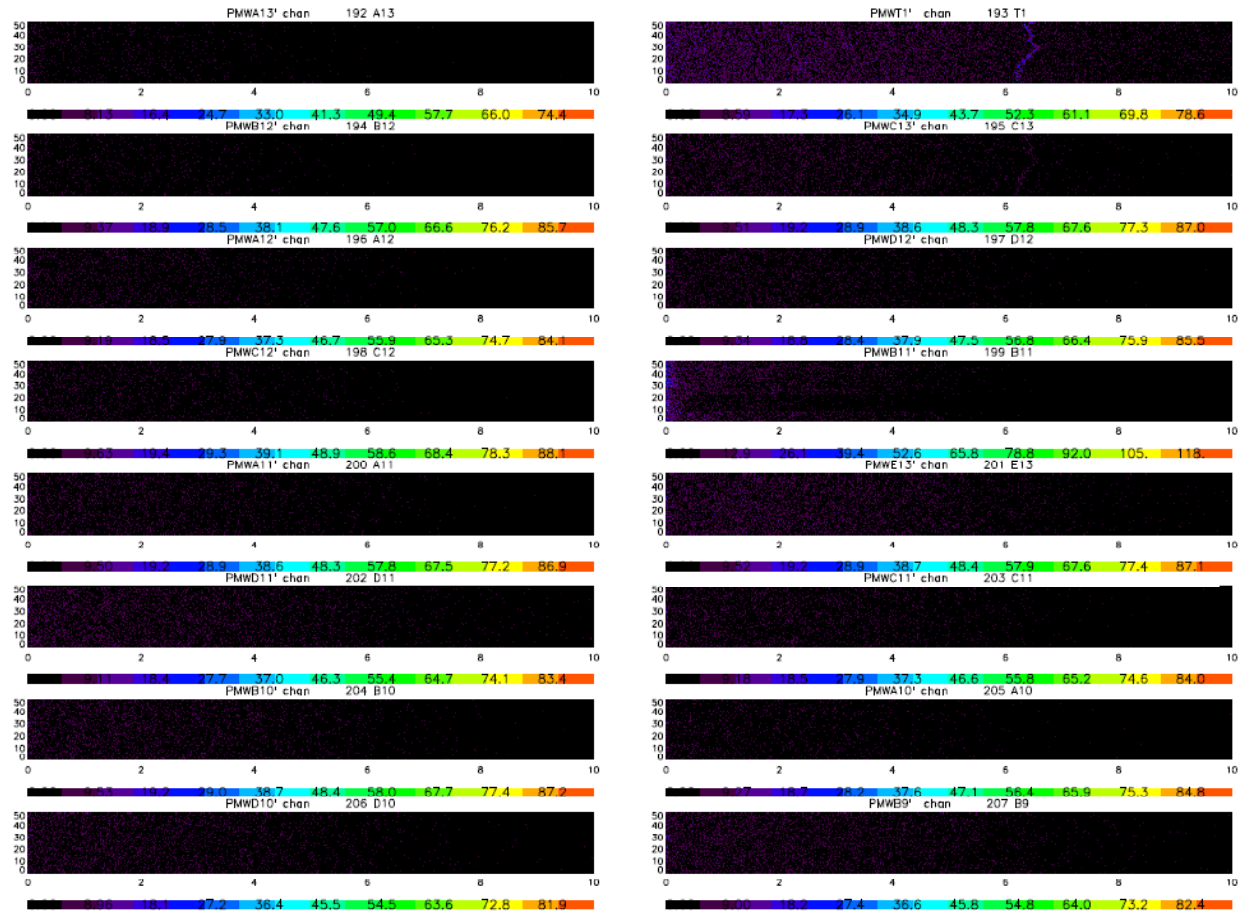


Figure 16

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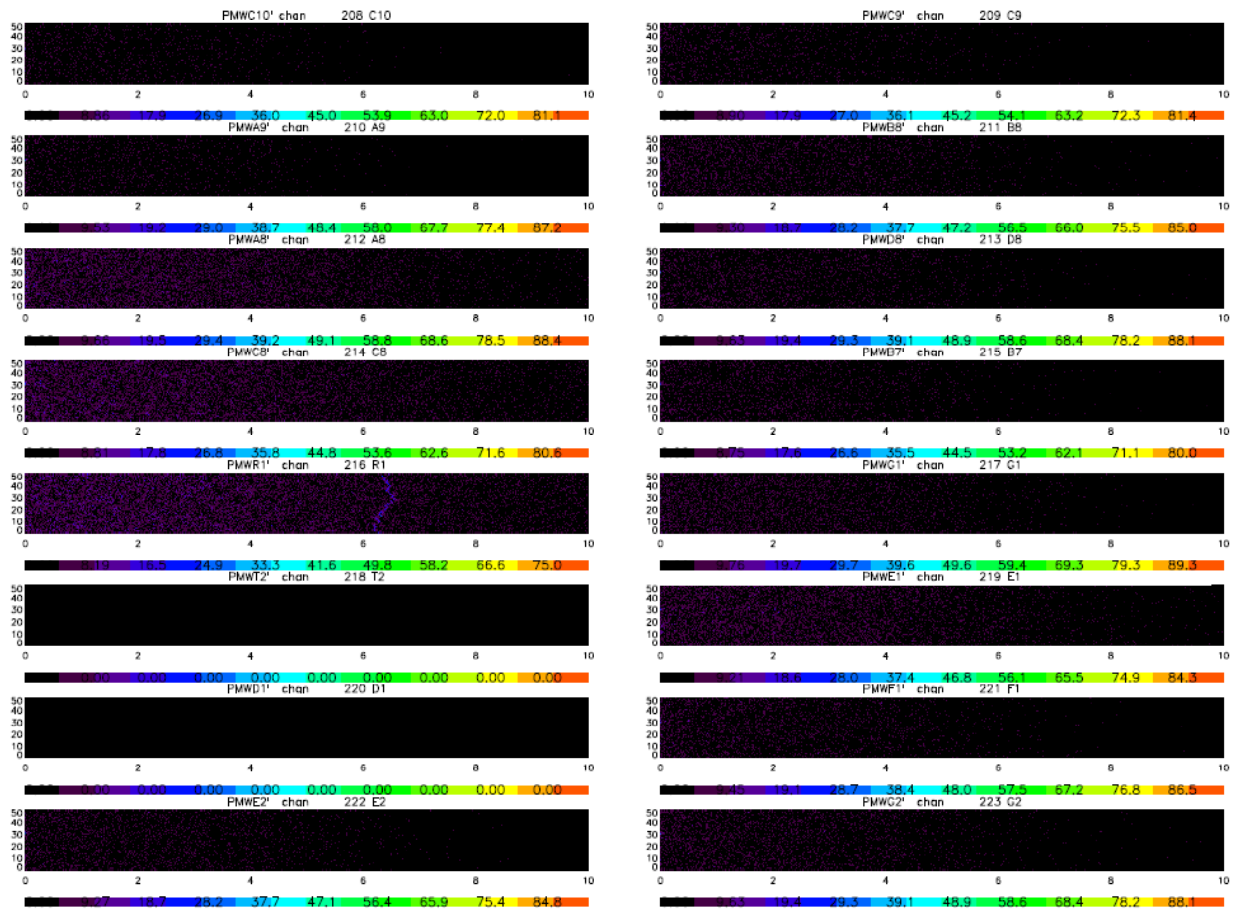


Figure 17

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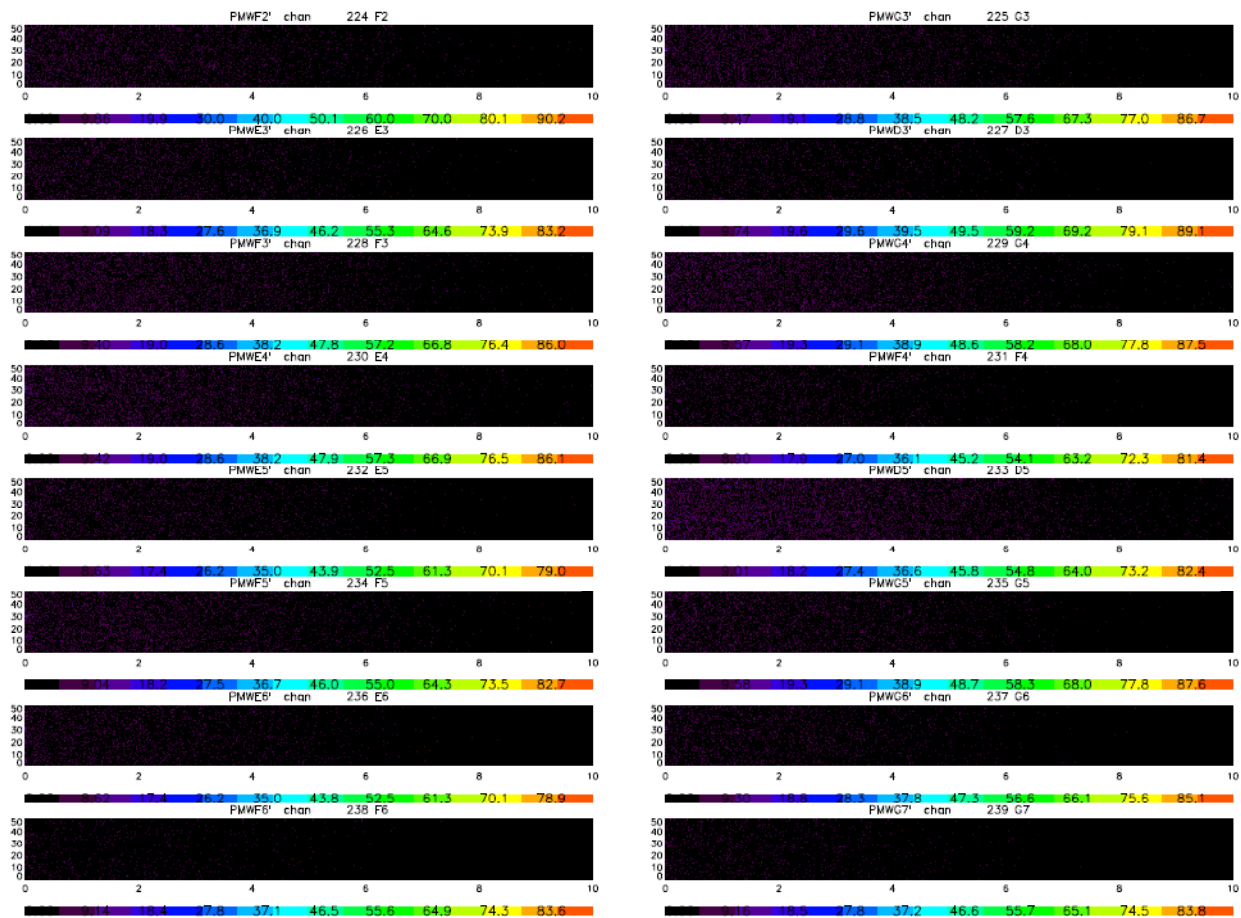


Figure 18

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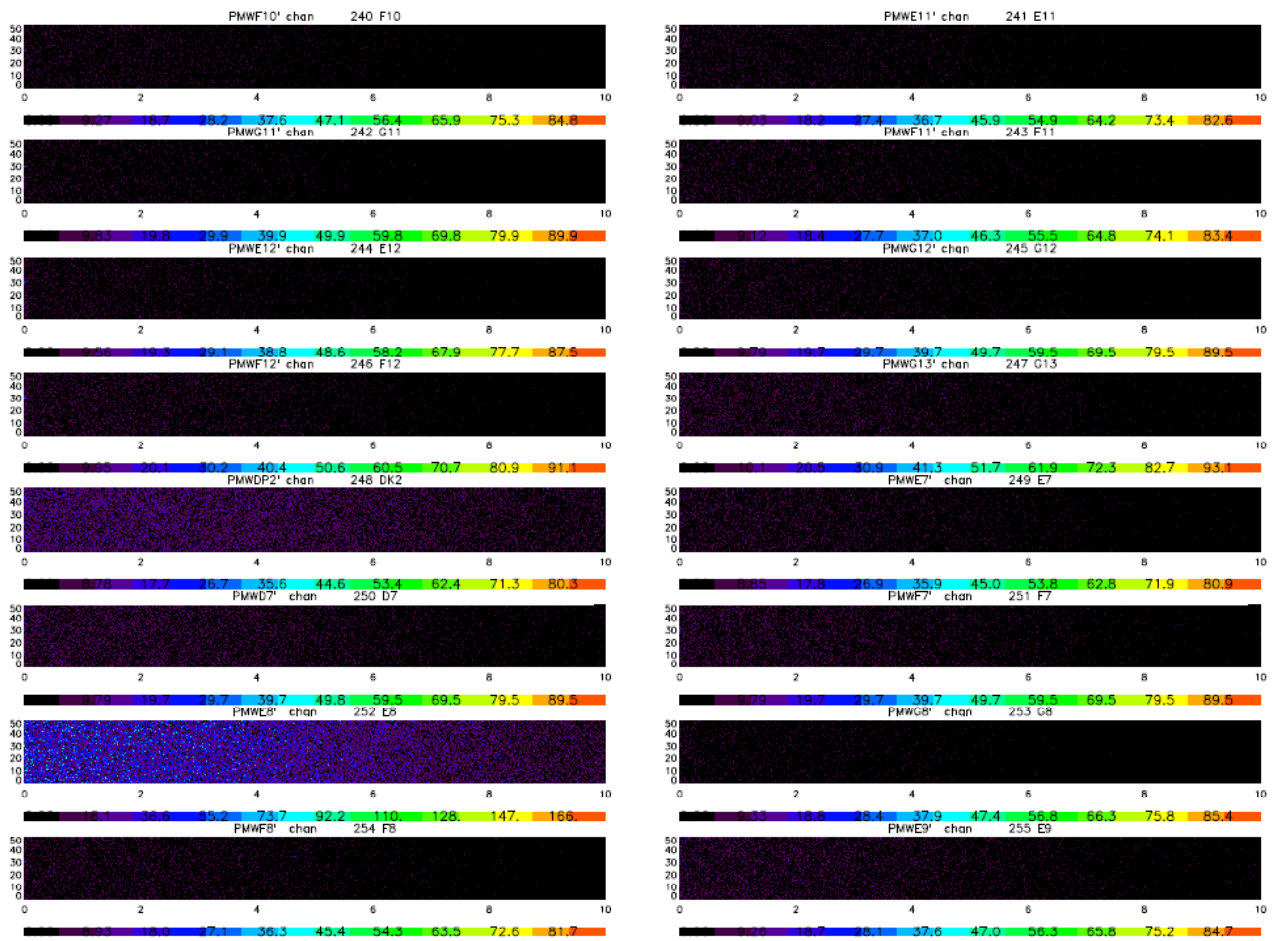


Figure 19

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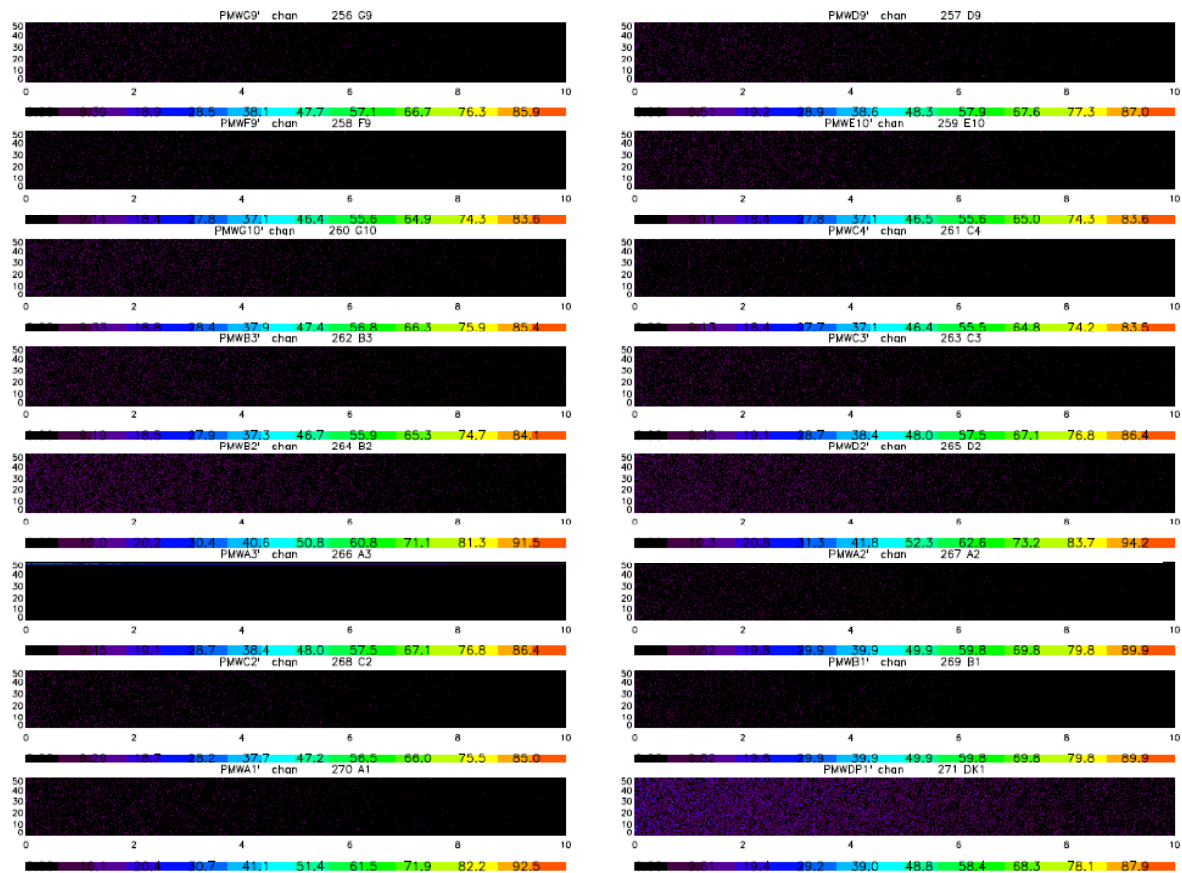


Figure 20

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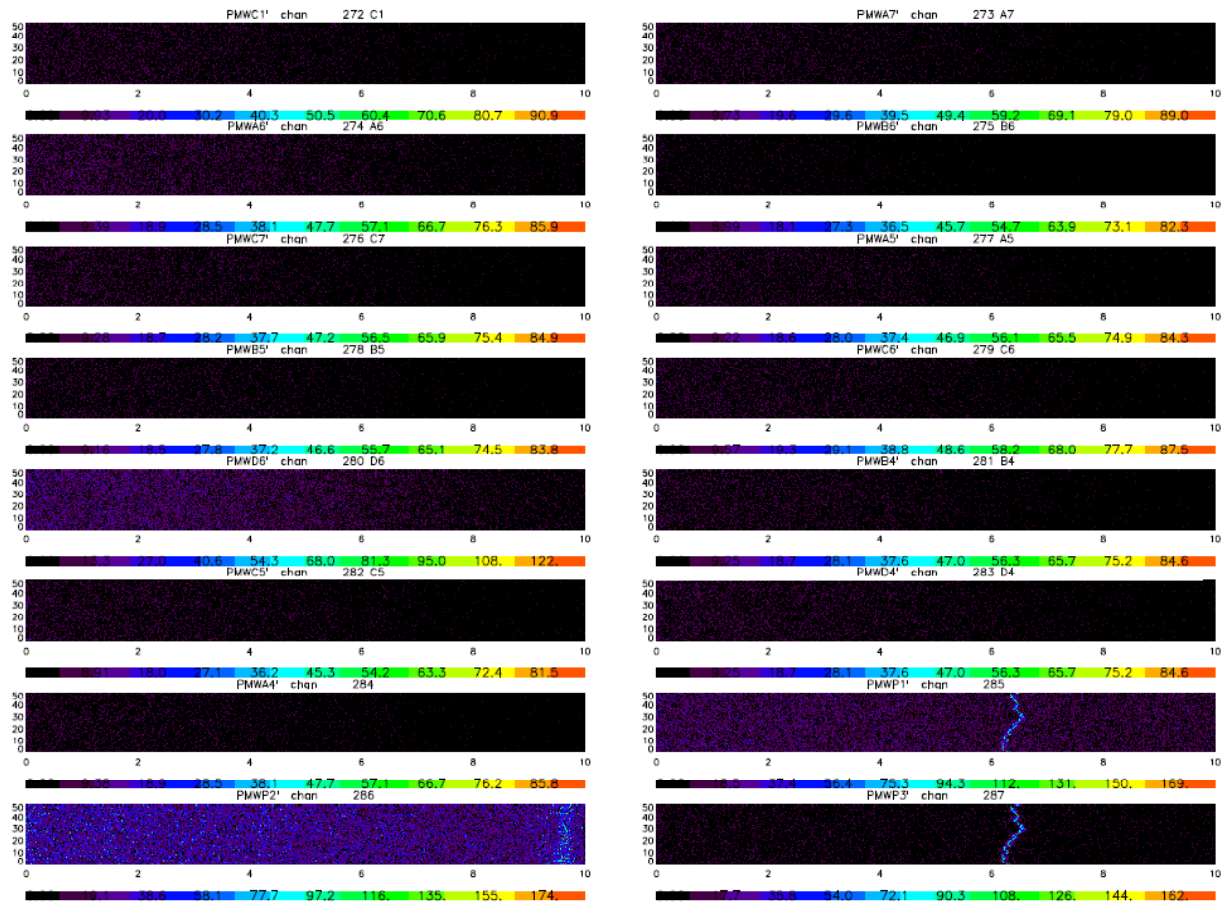


Figure 21

6.1.5 PLW Spectrogrammes

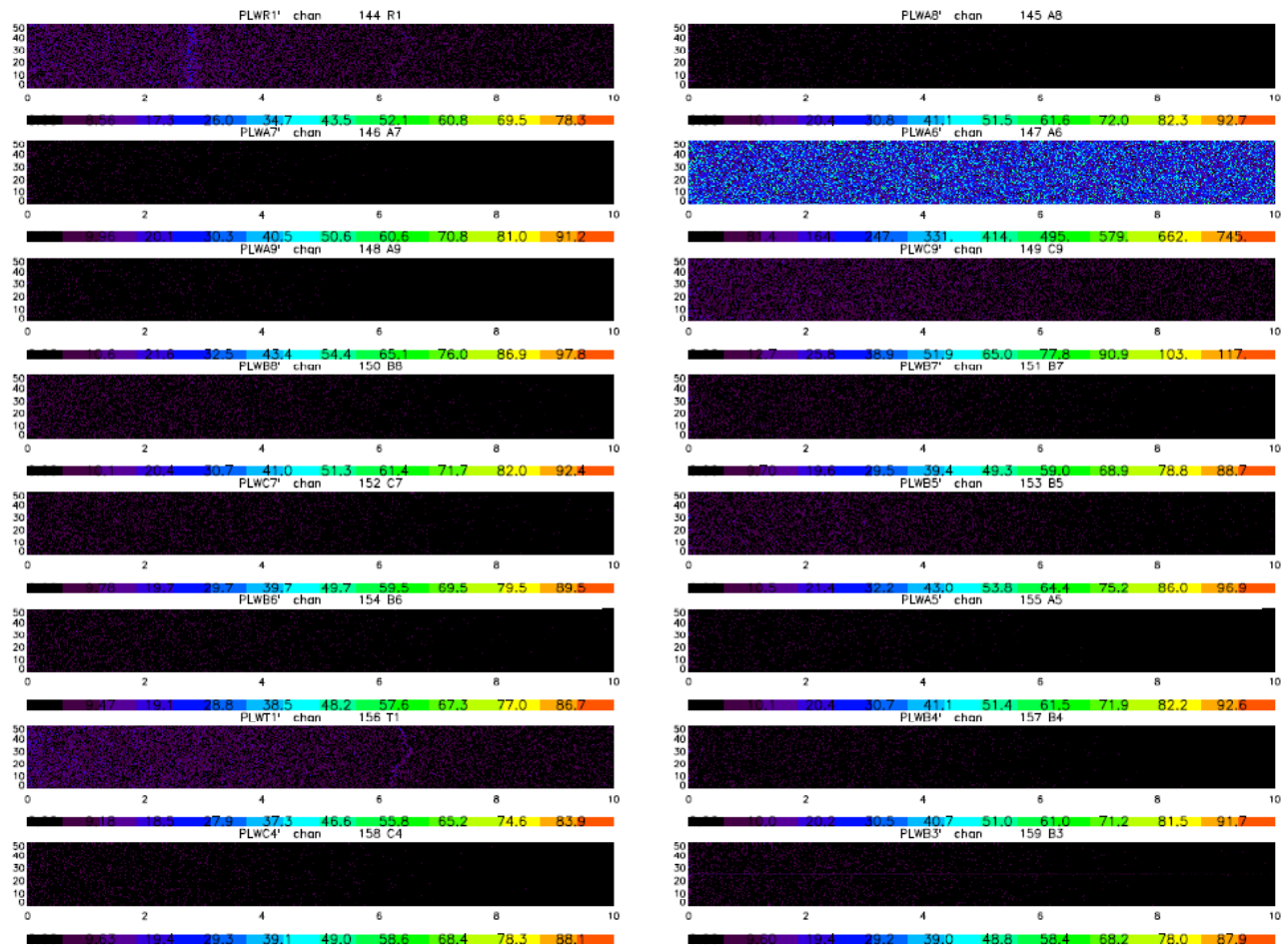


Figure 22

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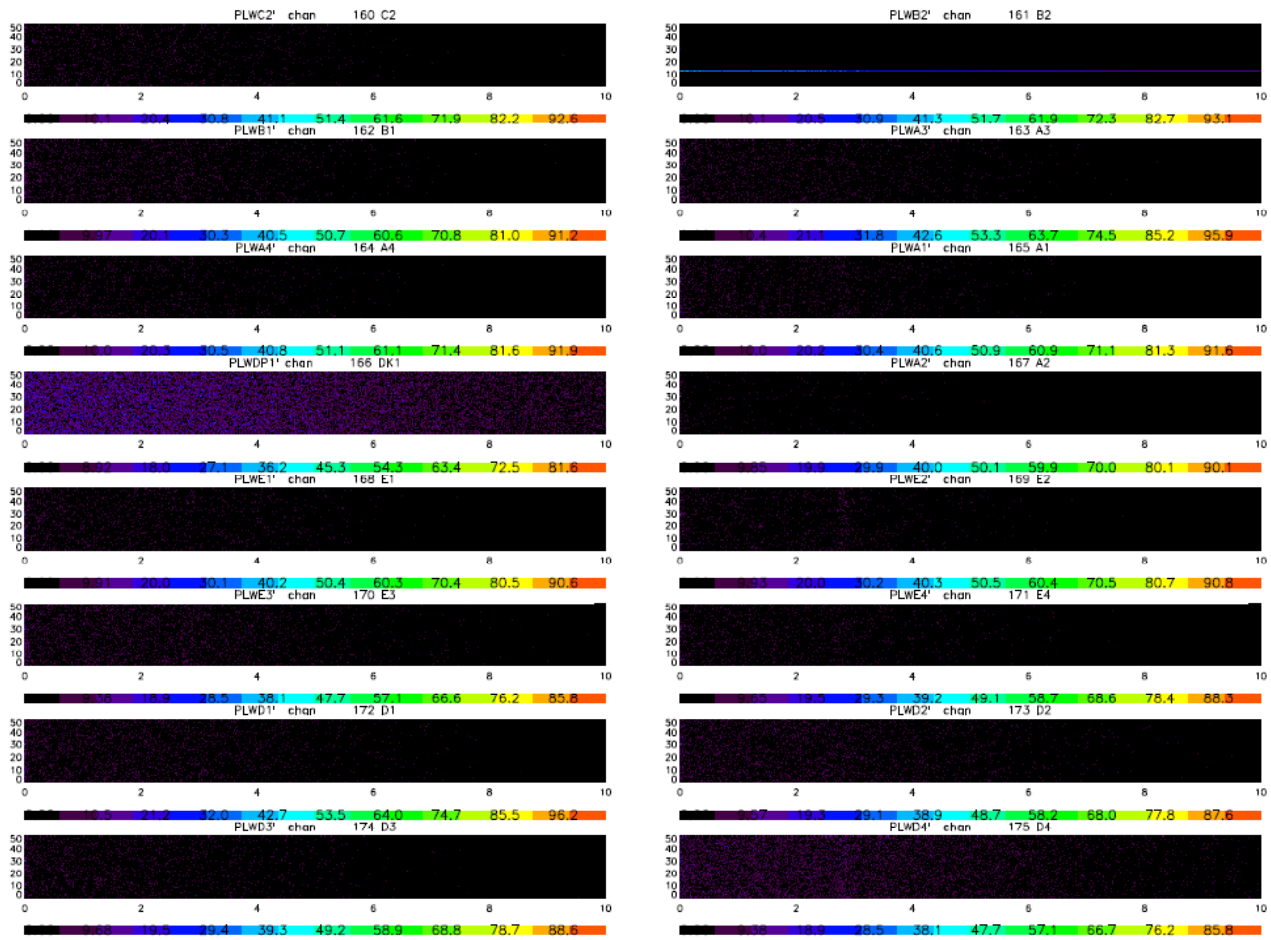


Figure 23

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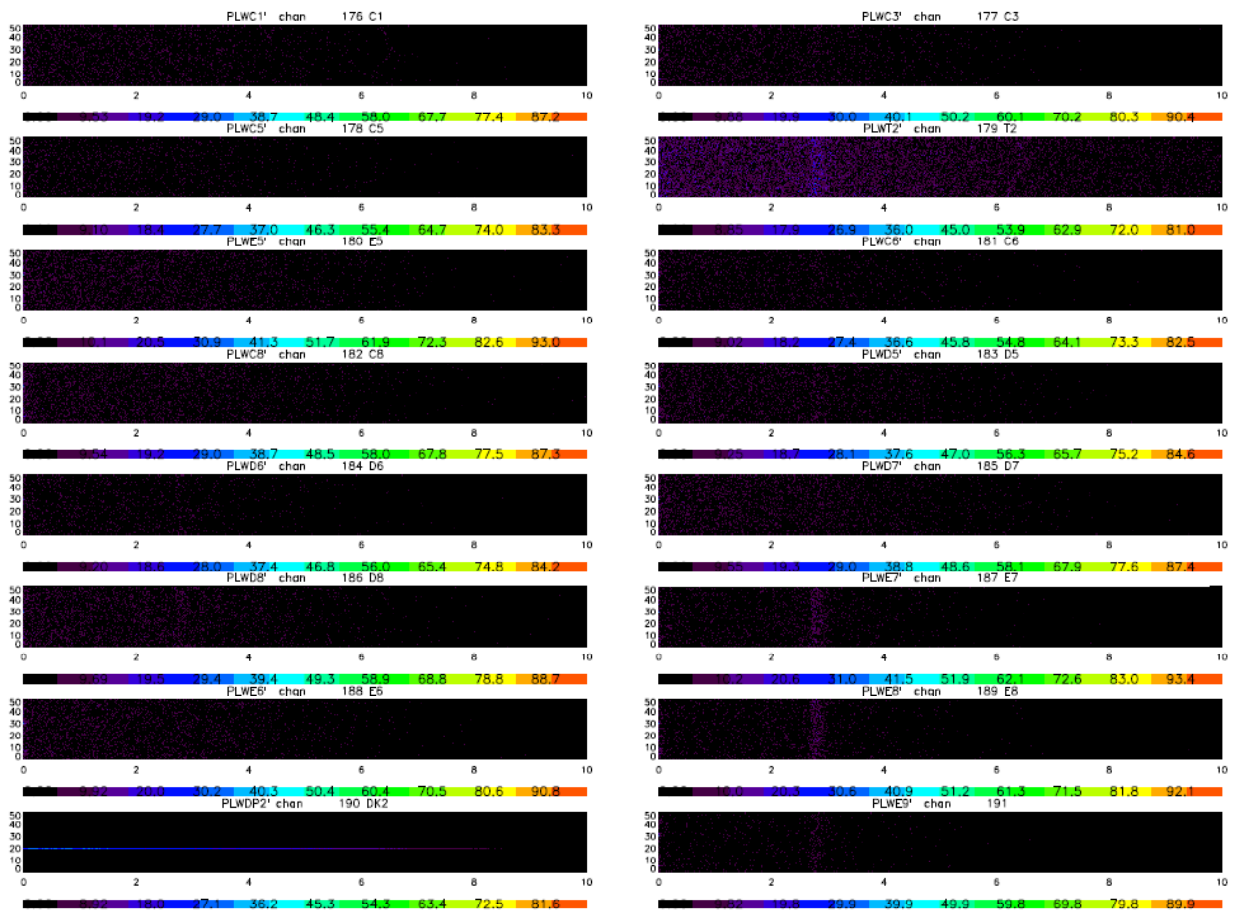


Figure 24

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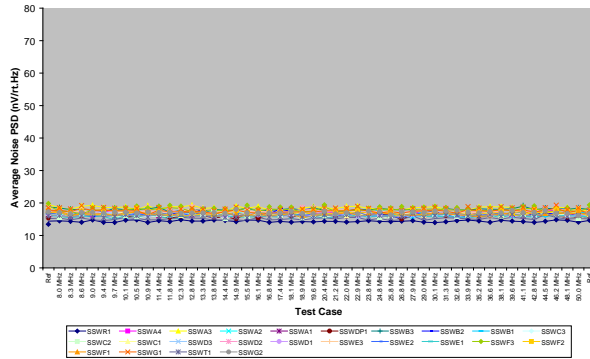
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6.2 CS Differential Mode – Spectrometer (0xB00014C7)

6.2.1 Noise PSD (Averaged using N 10 second “chunks” of detector data)

SSW-1



6.2.2 SSW and SLW Spectrogrammes

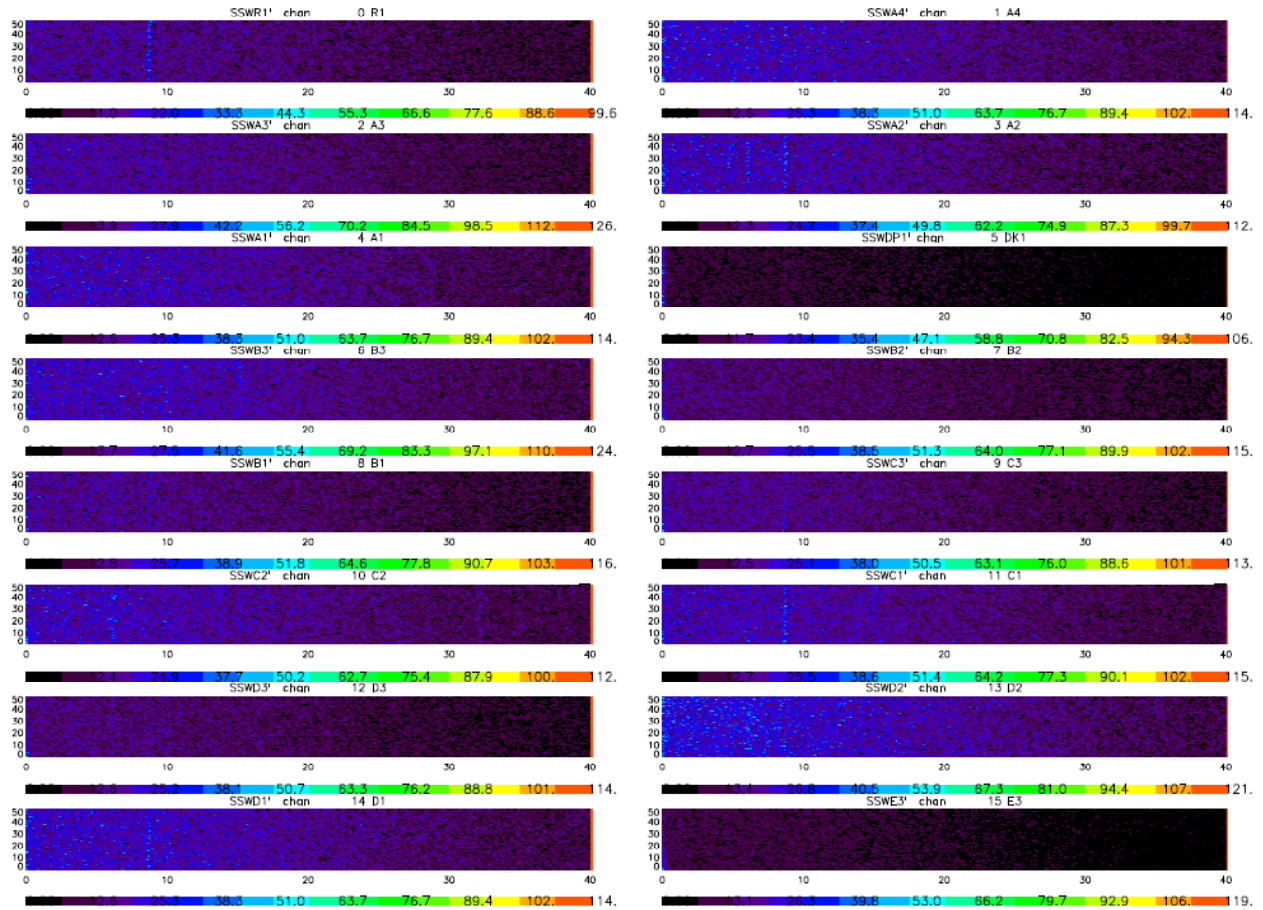


Figure 25

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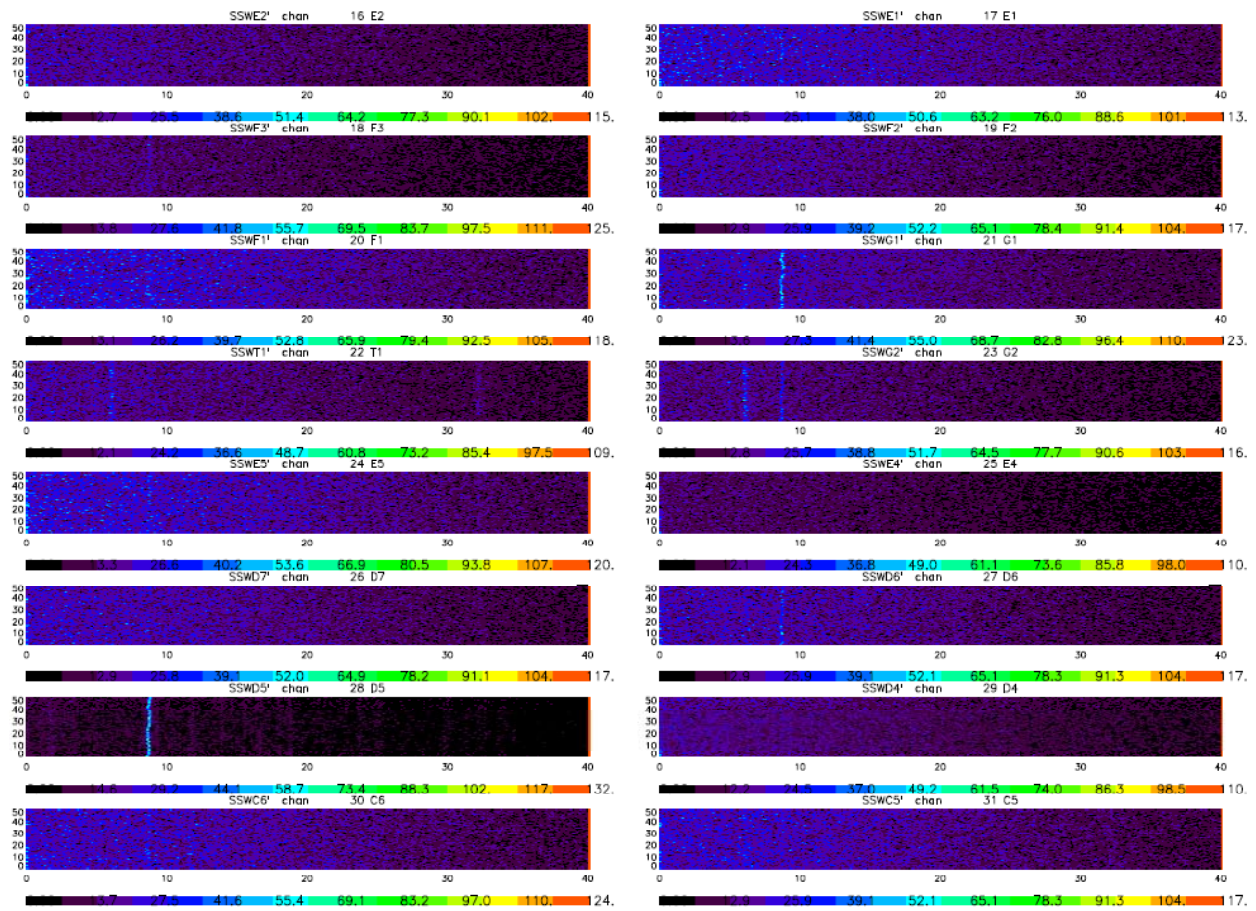


Figure 26

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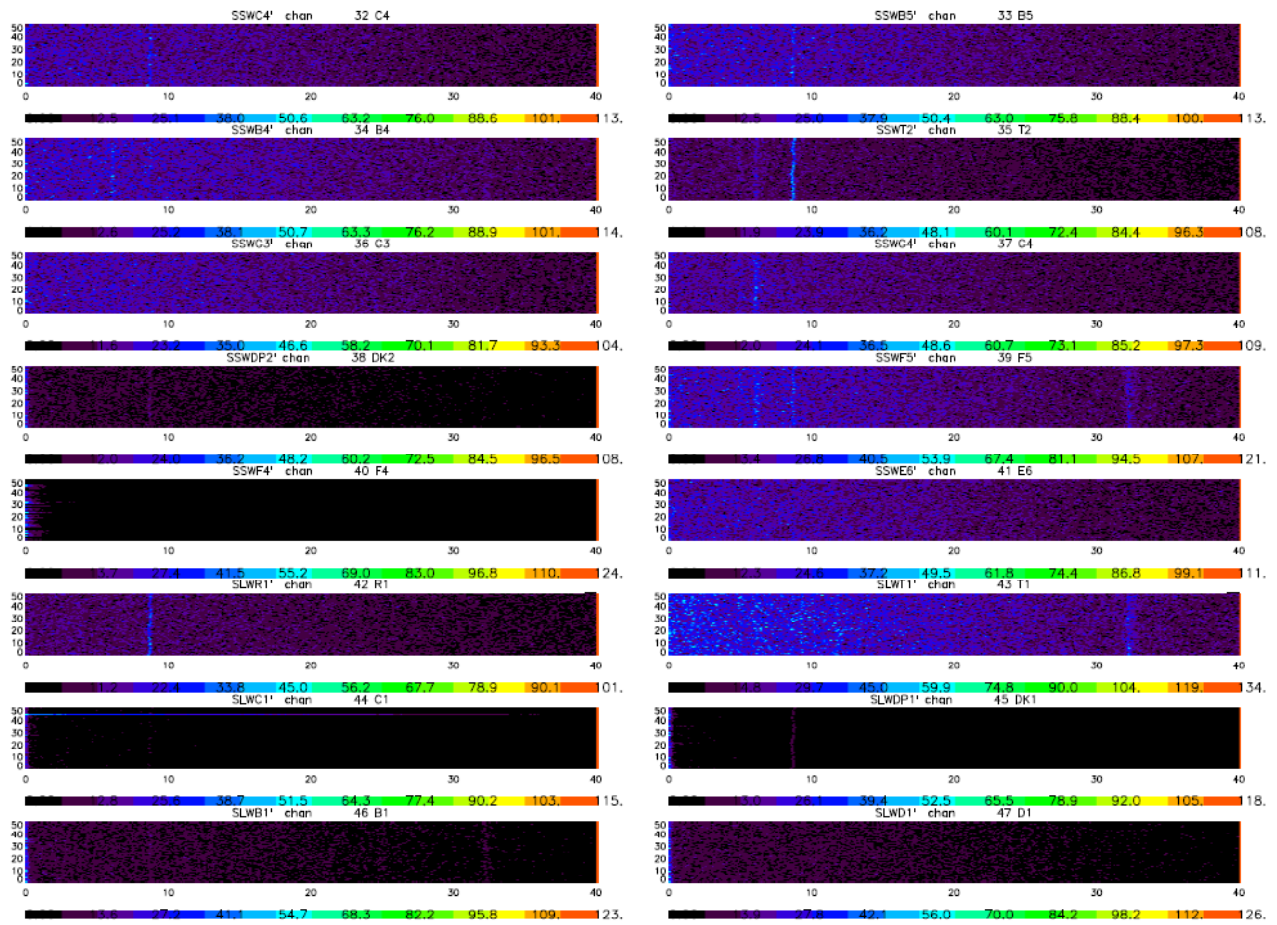


Figure 27

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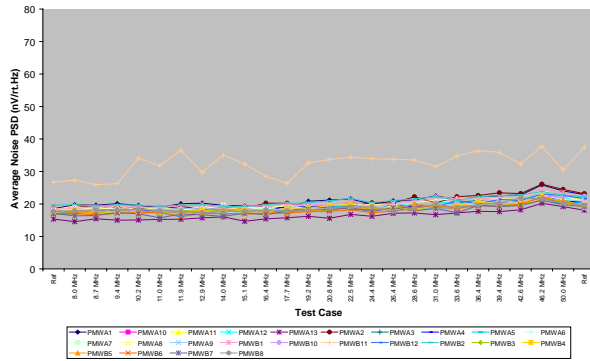
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PMW (A1-B8)



PMW-B11 shows excess noise @ ~ 30nV/√Hz

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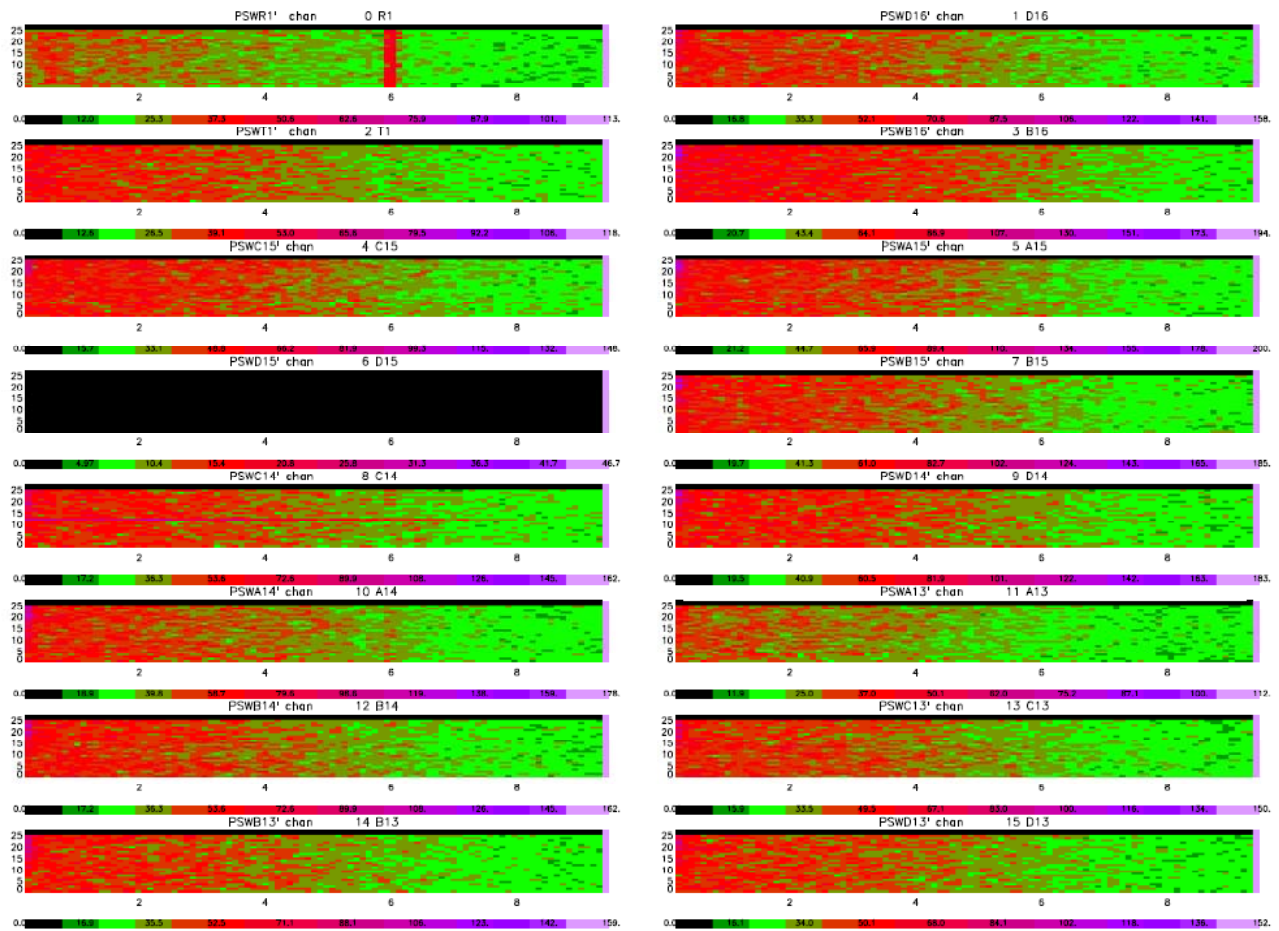


Figure 30

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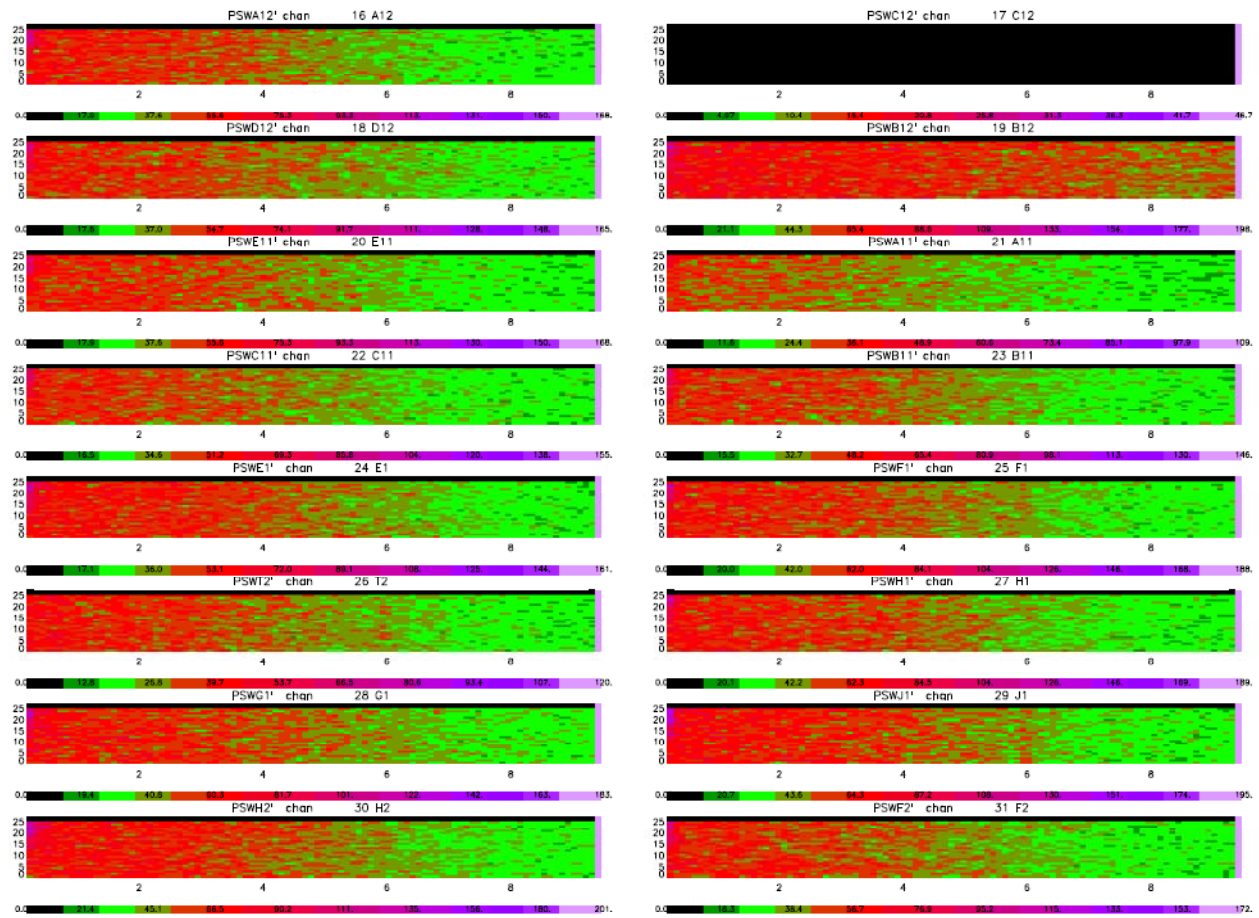


Figure 31

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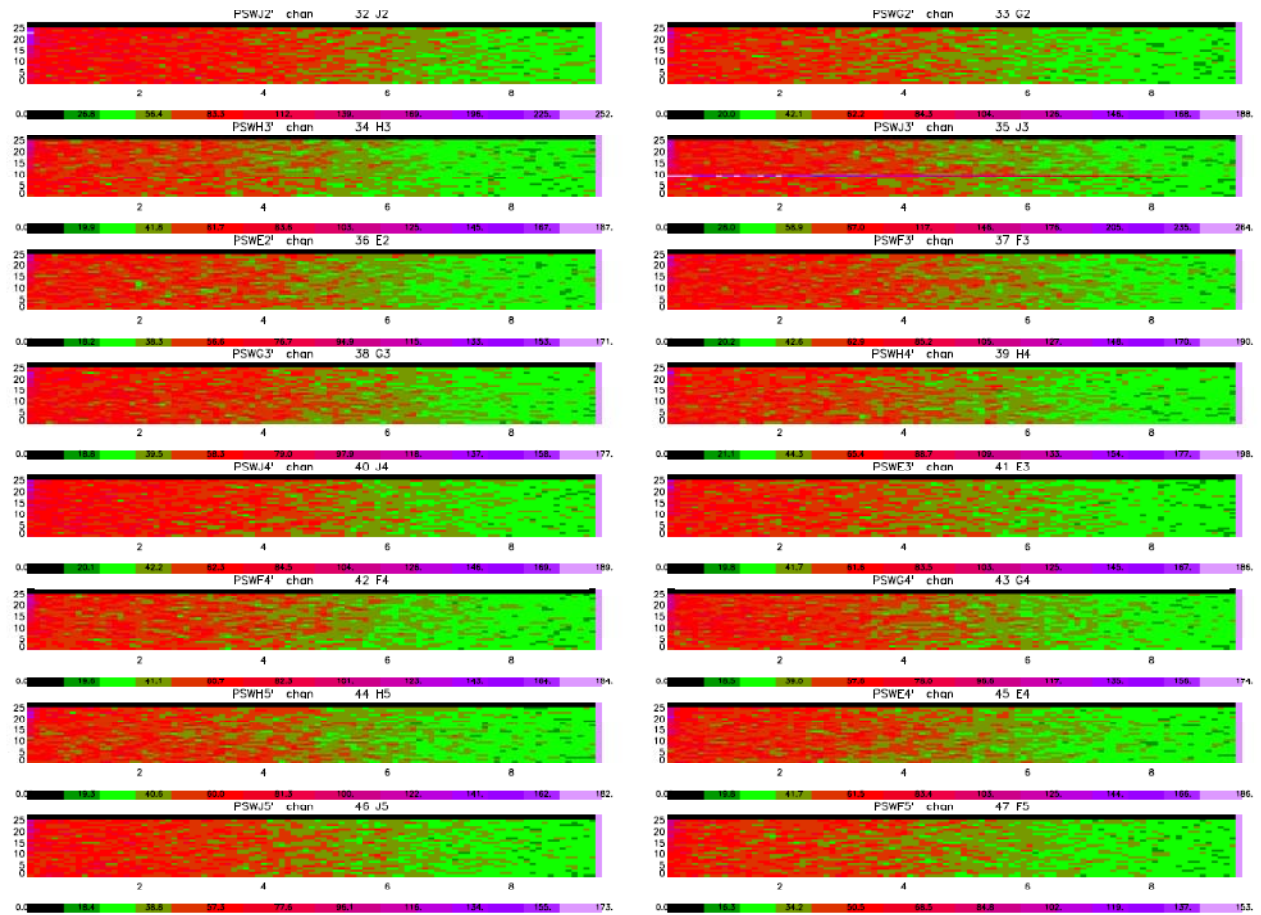


Figure 32

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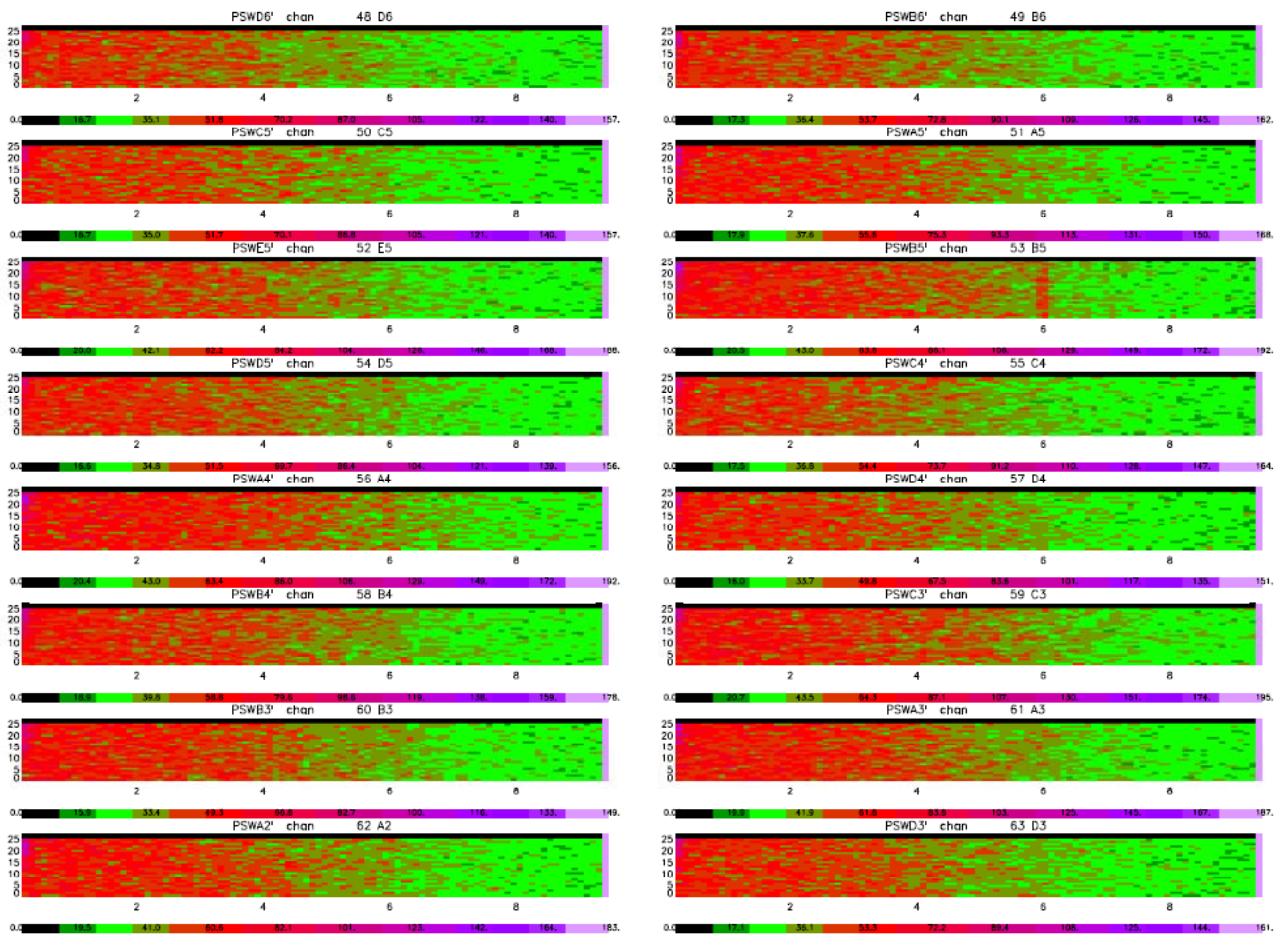


Figure 33

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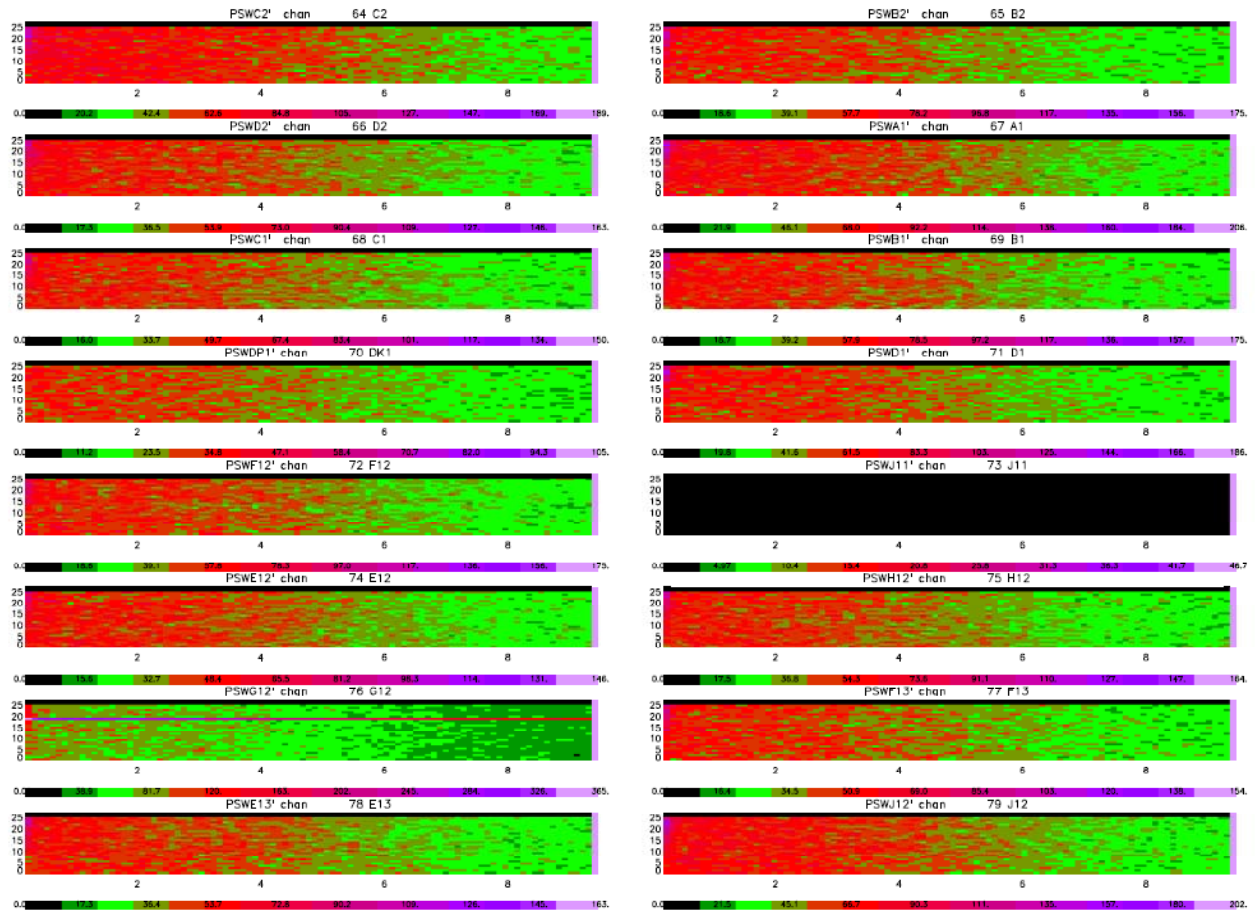


Figure 34

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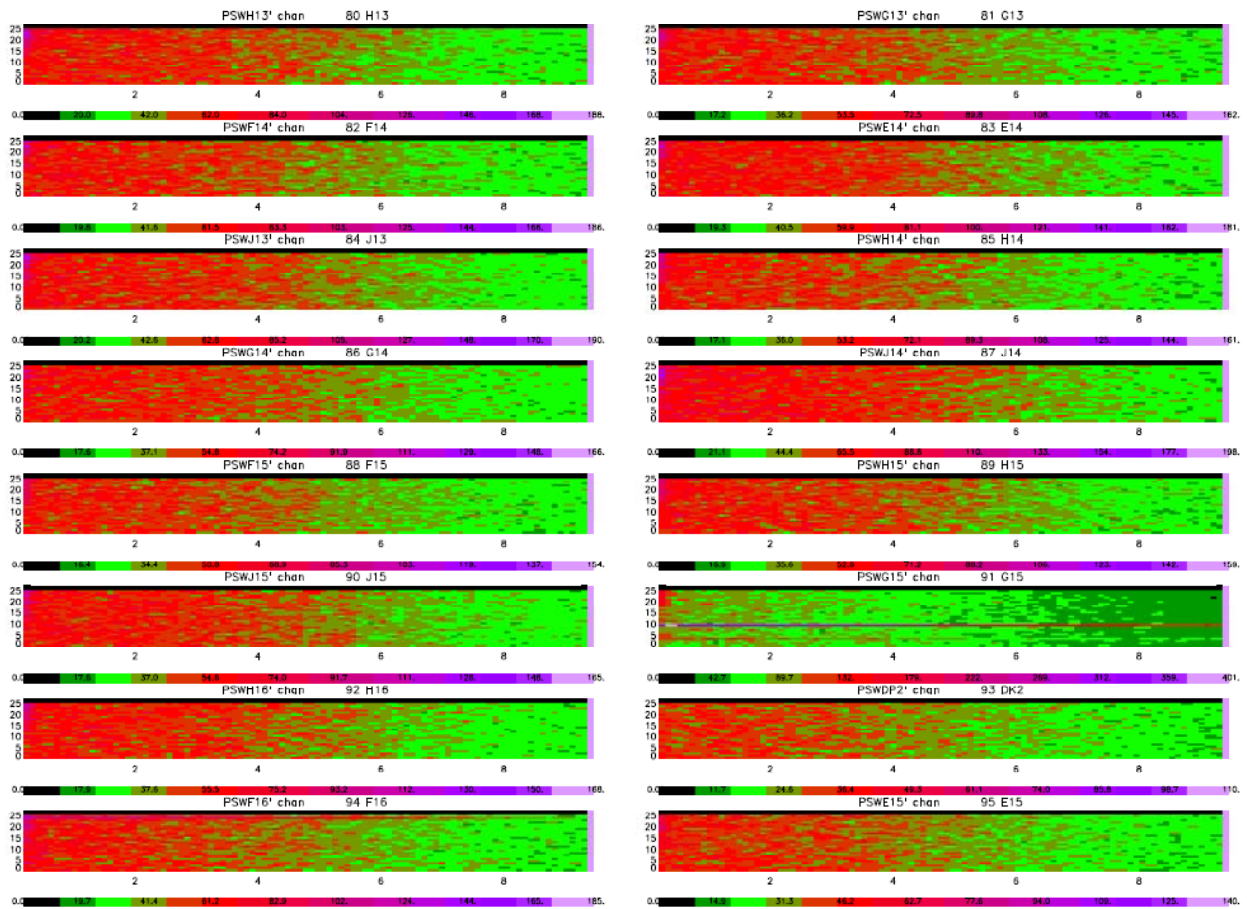


Figure 35

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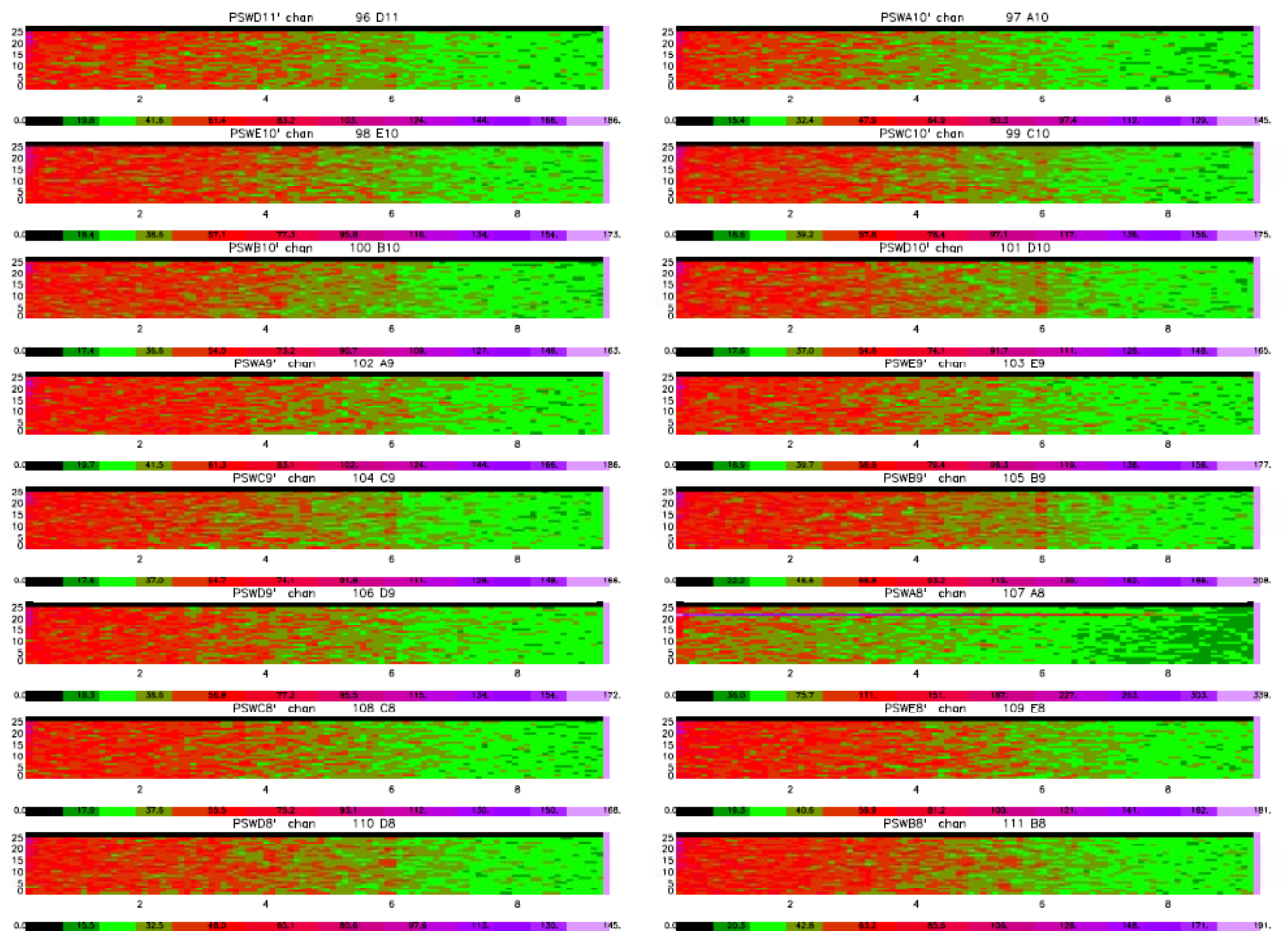


Figure 36

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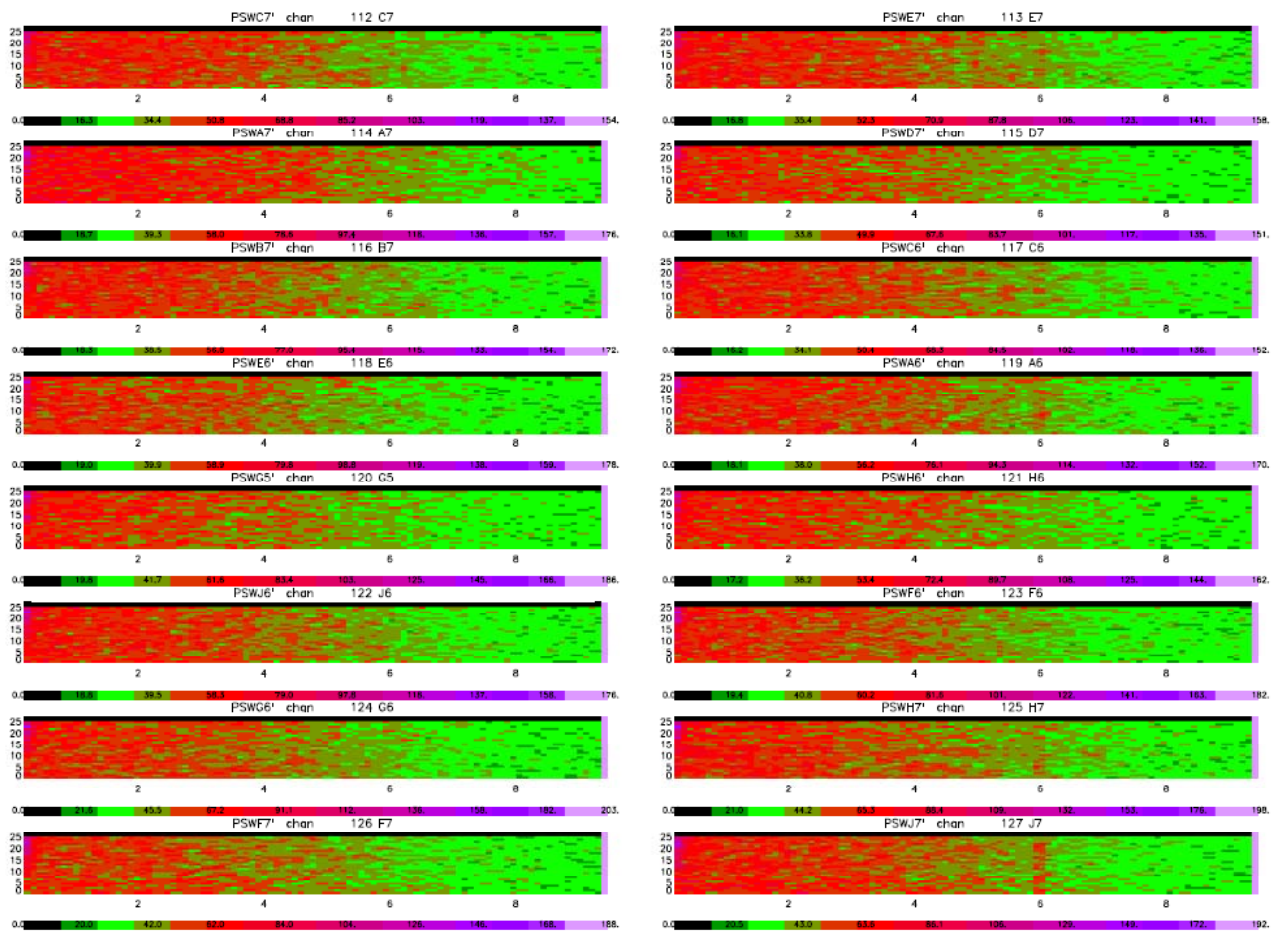


Figure 37

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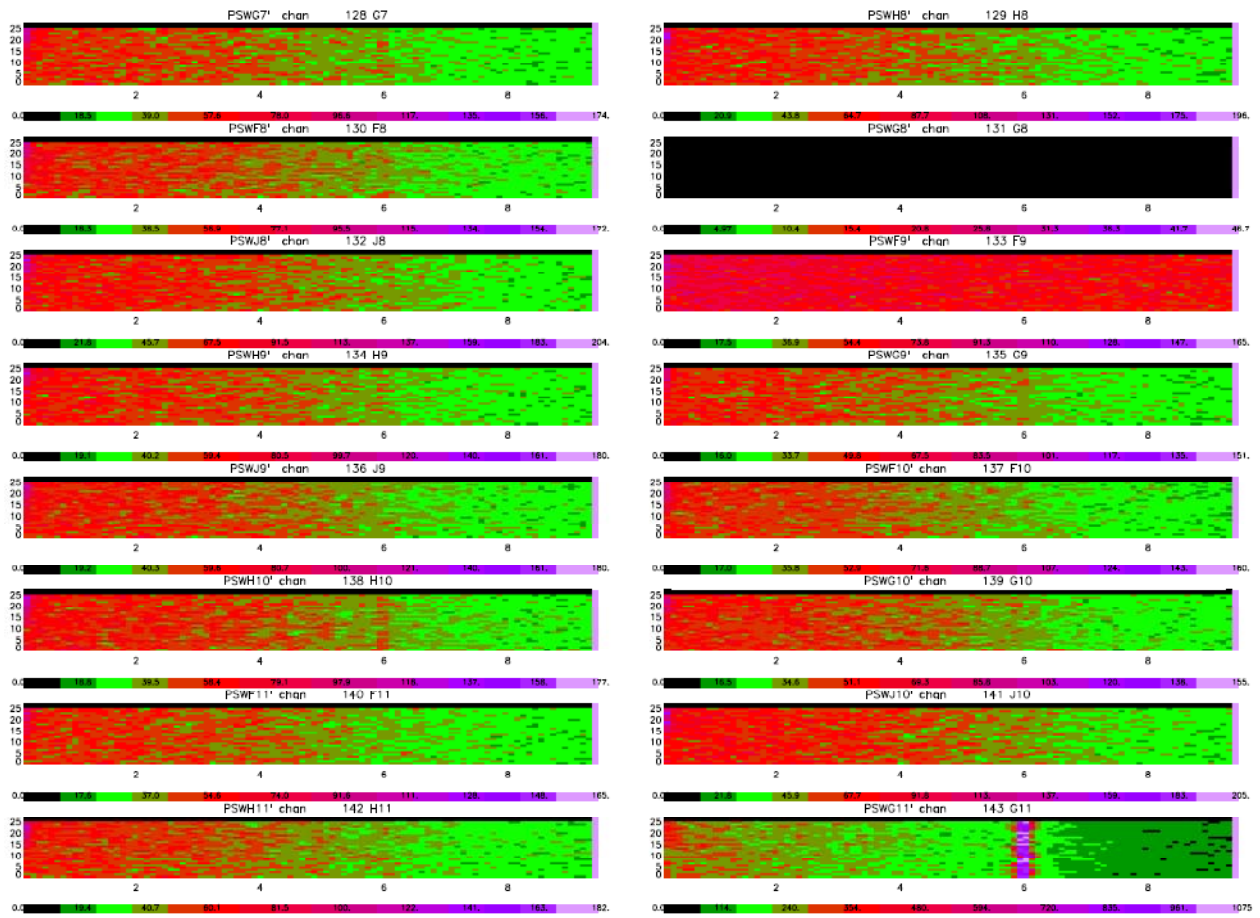


Figure 38

7.1.3 PLW Spectrogrammes

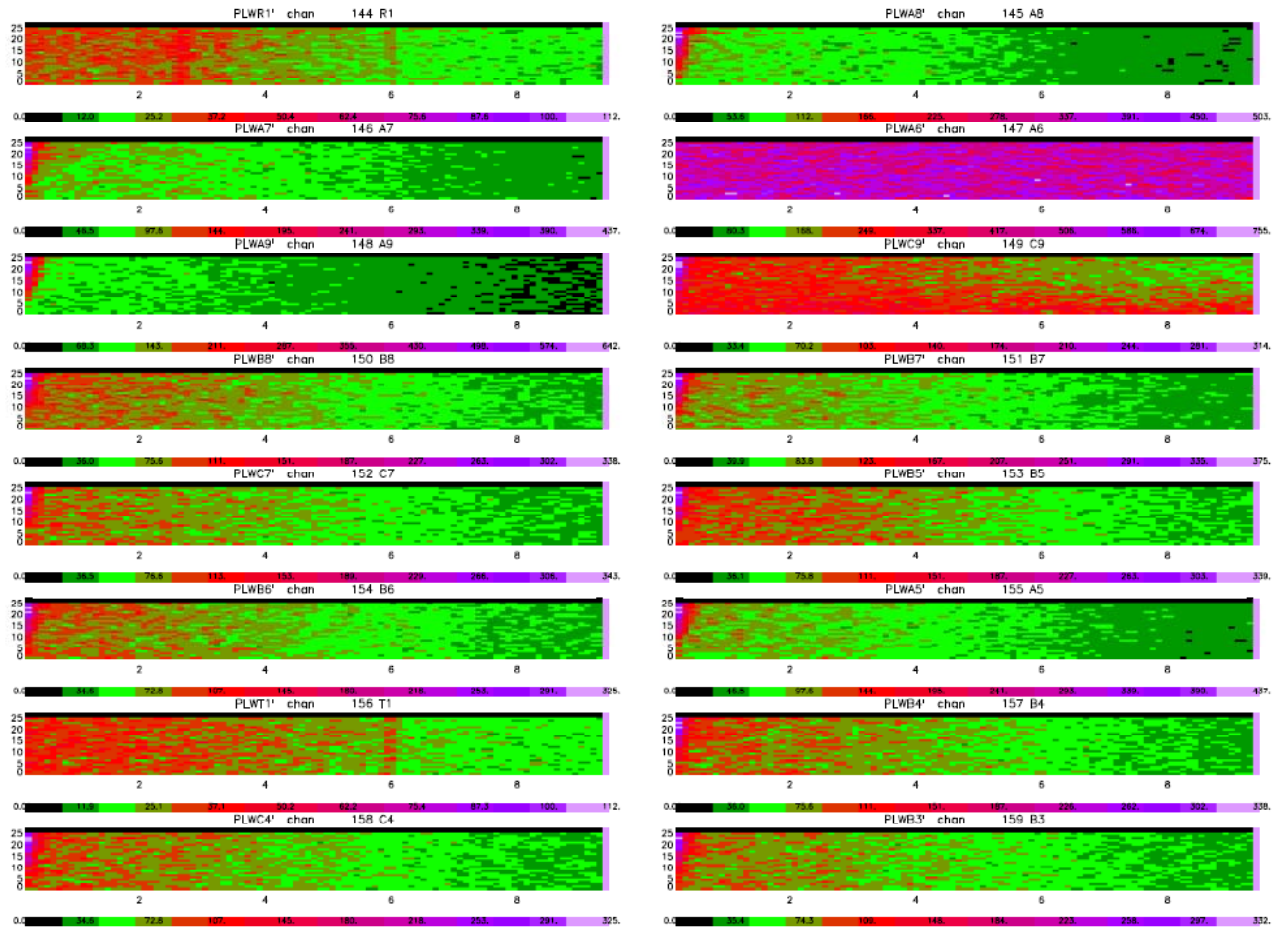


Figure 39

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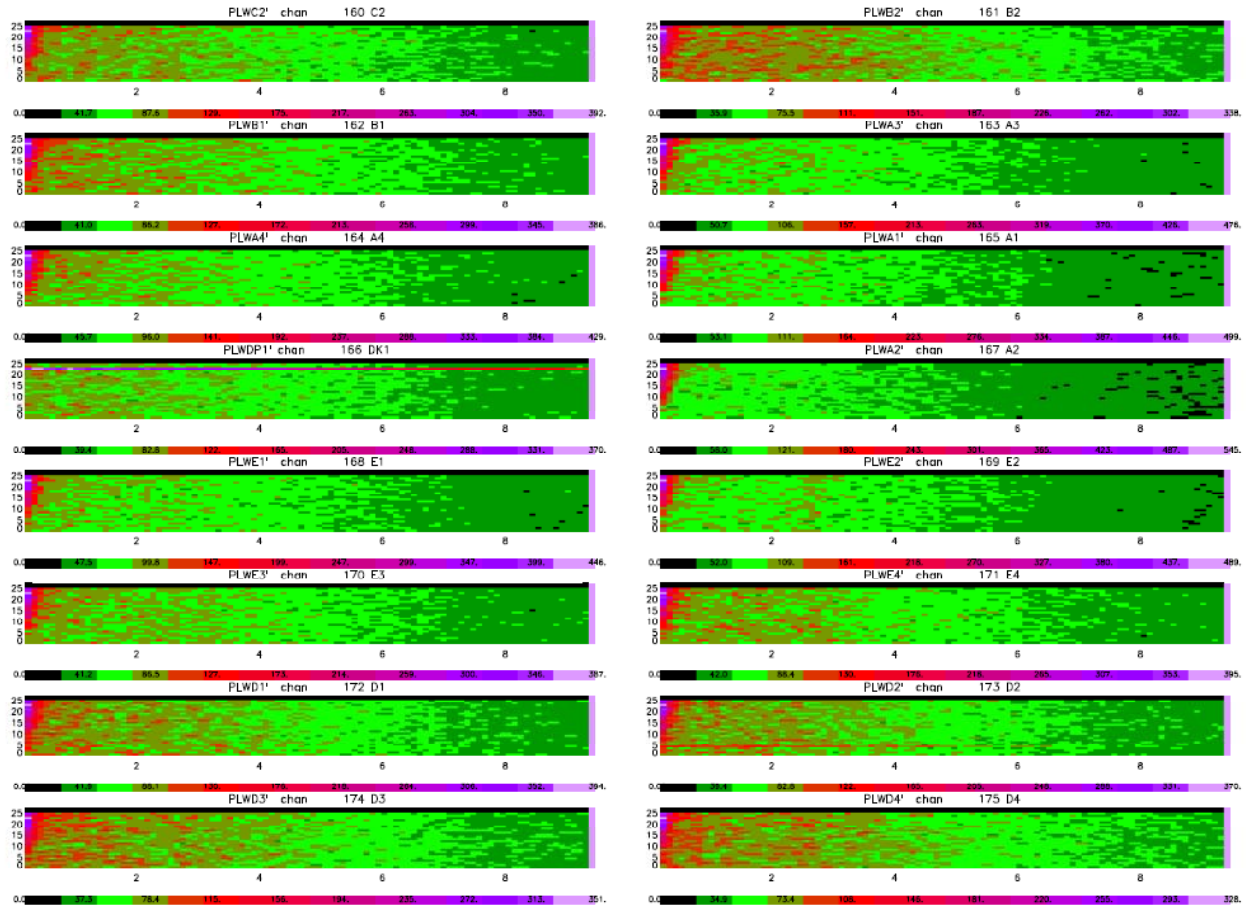


Figure 40

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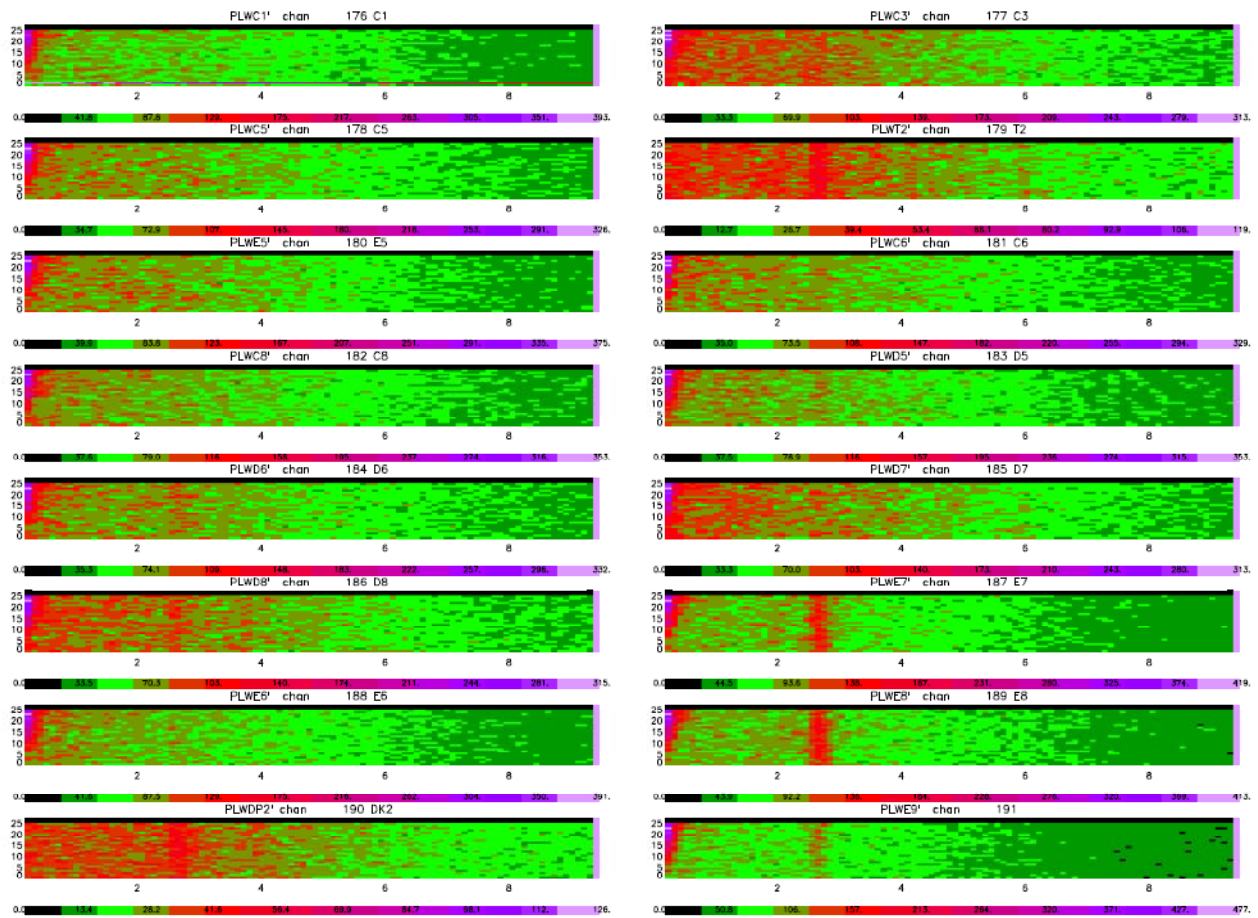


Figure 41

7.1.4 PMW Spectrogrammes

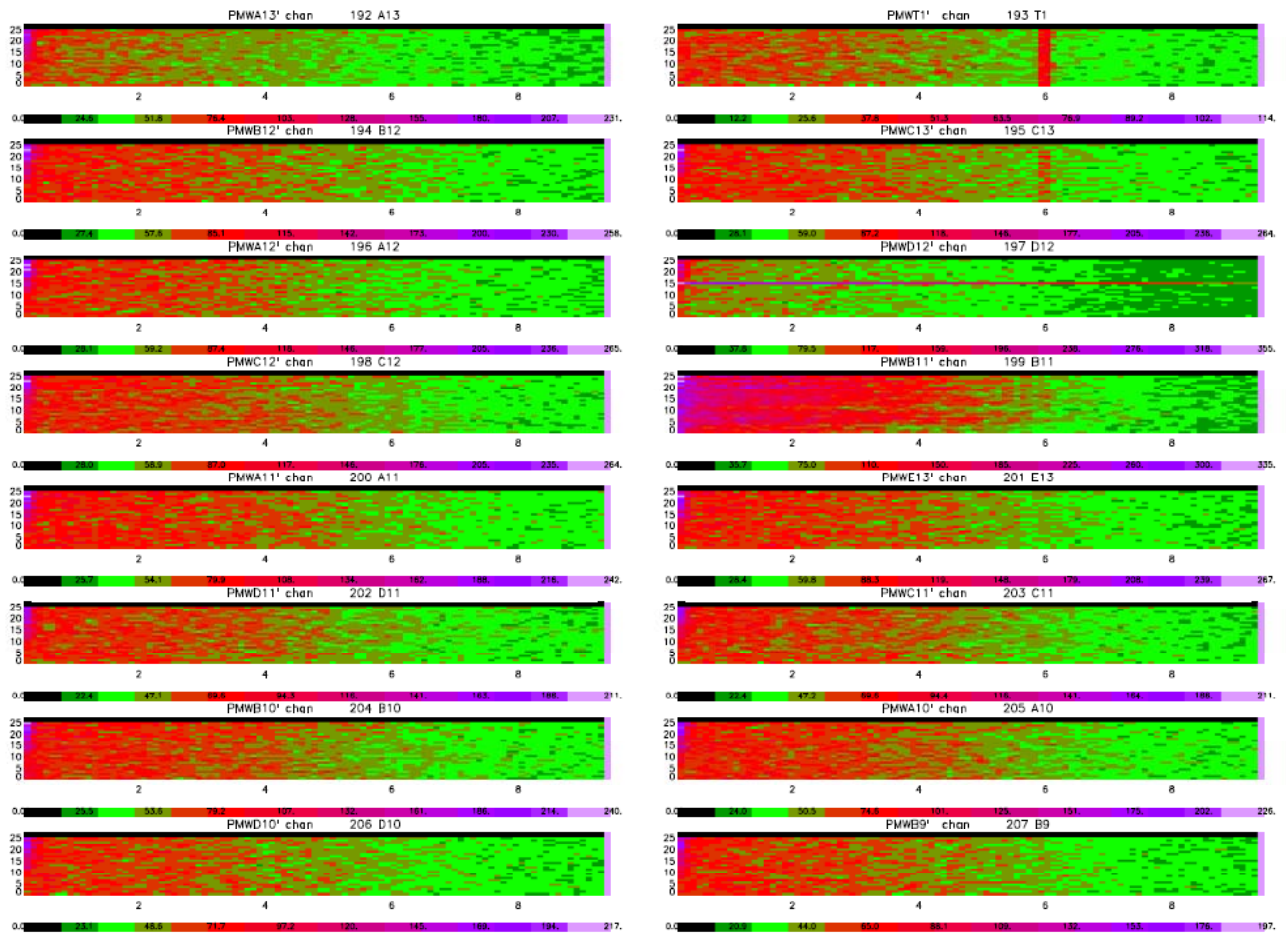


Figure 42

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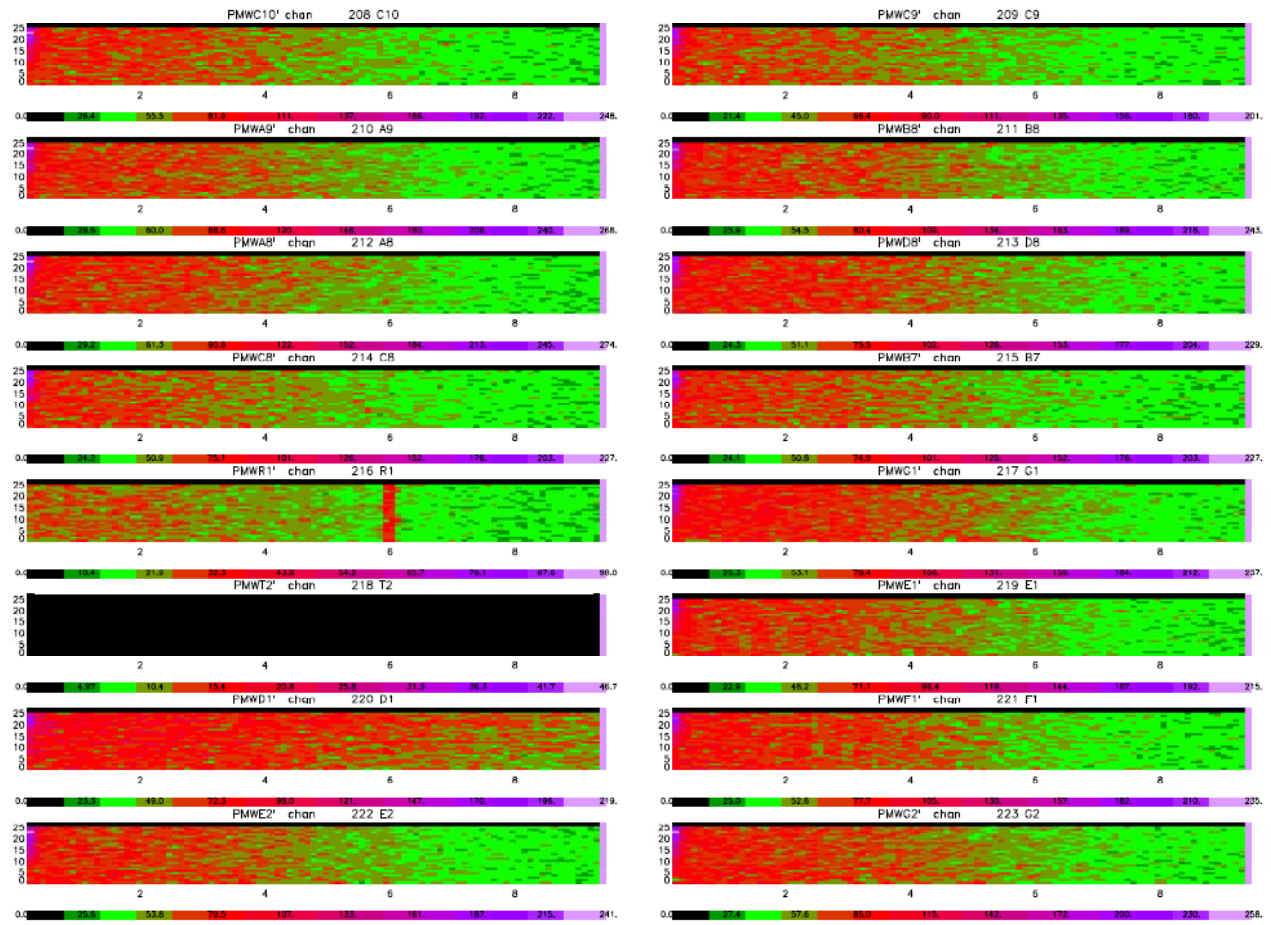


Figure 43

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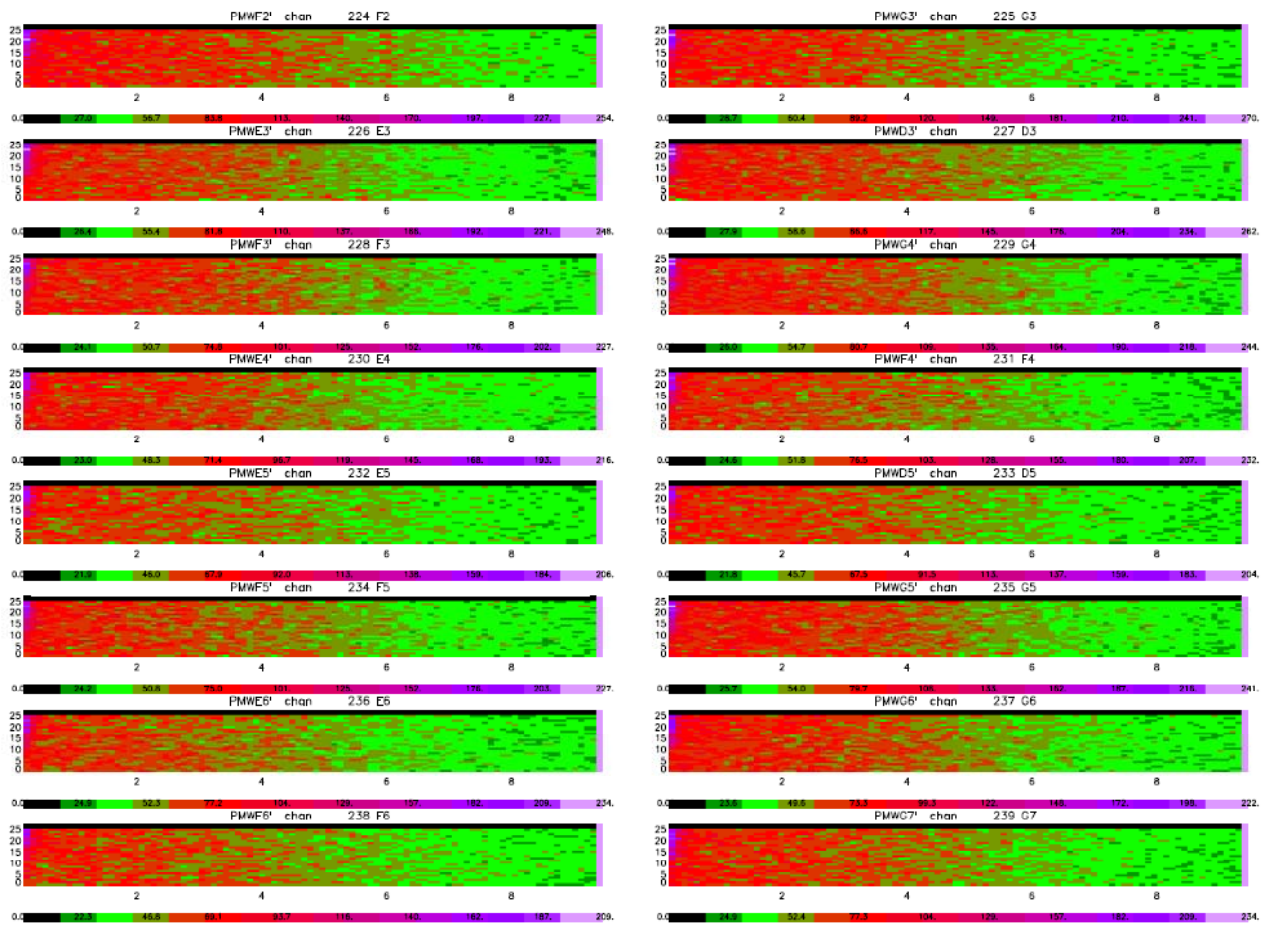


Figure 44

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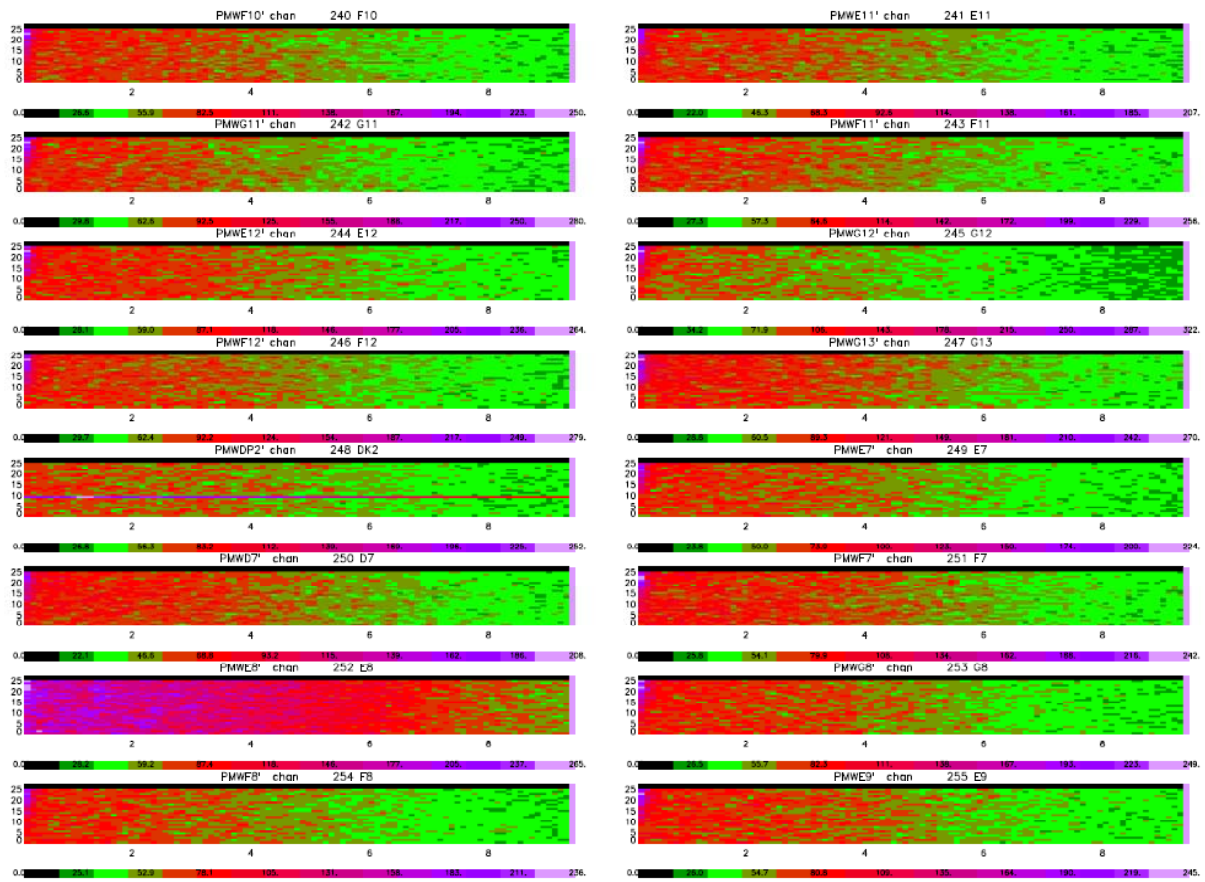


Figure 45

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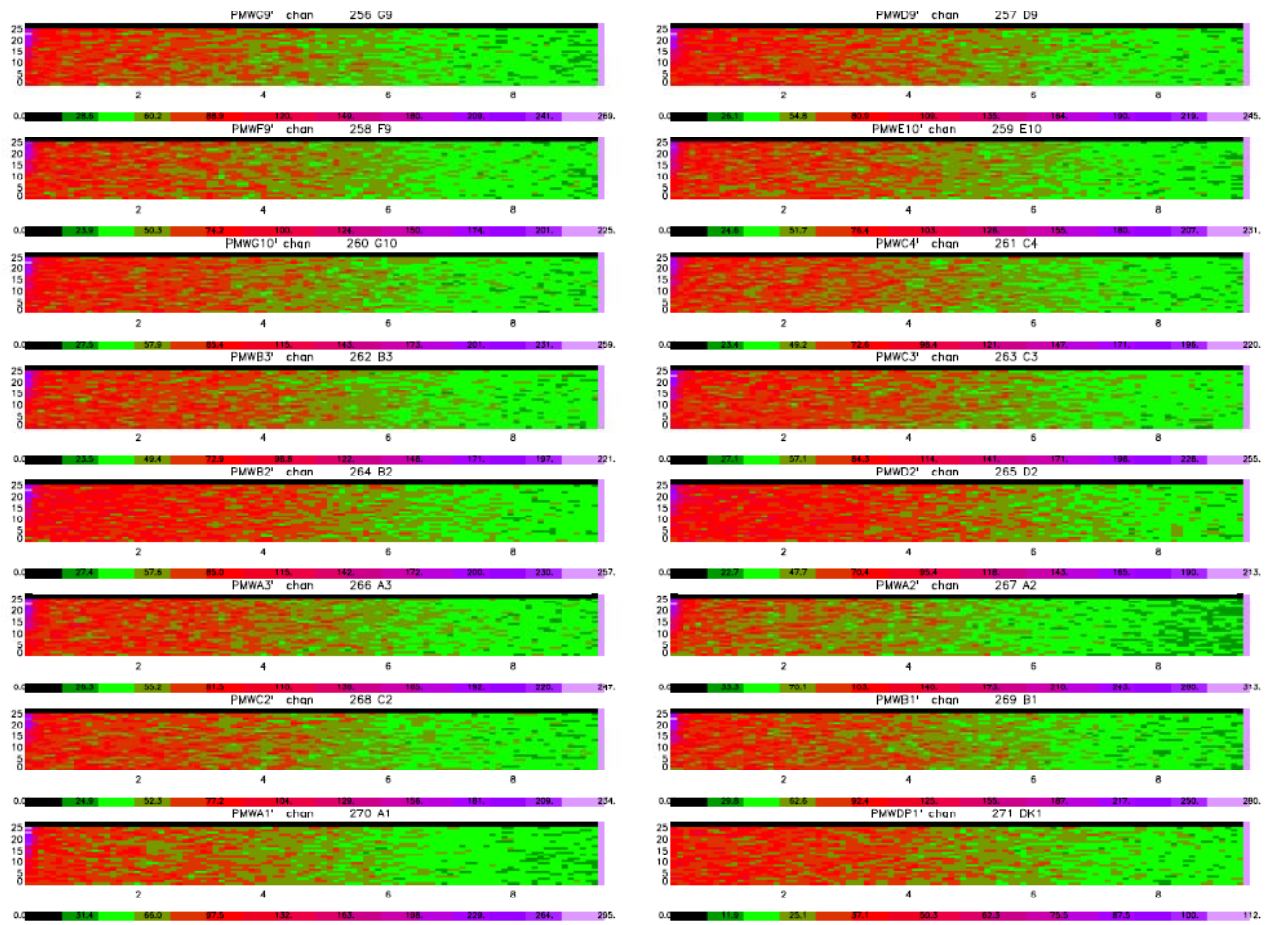


Figure 46

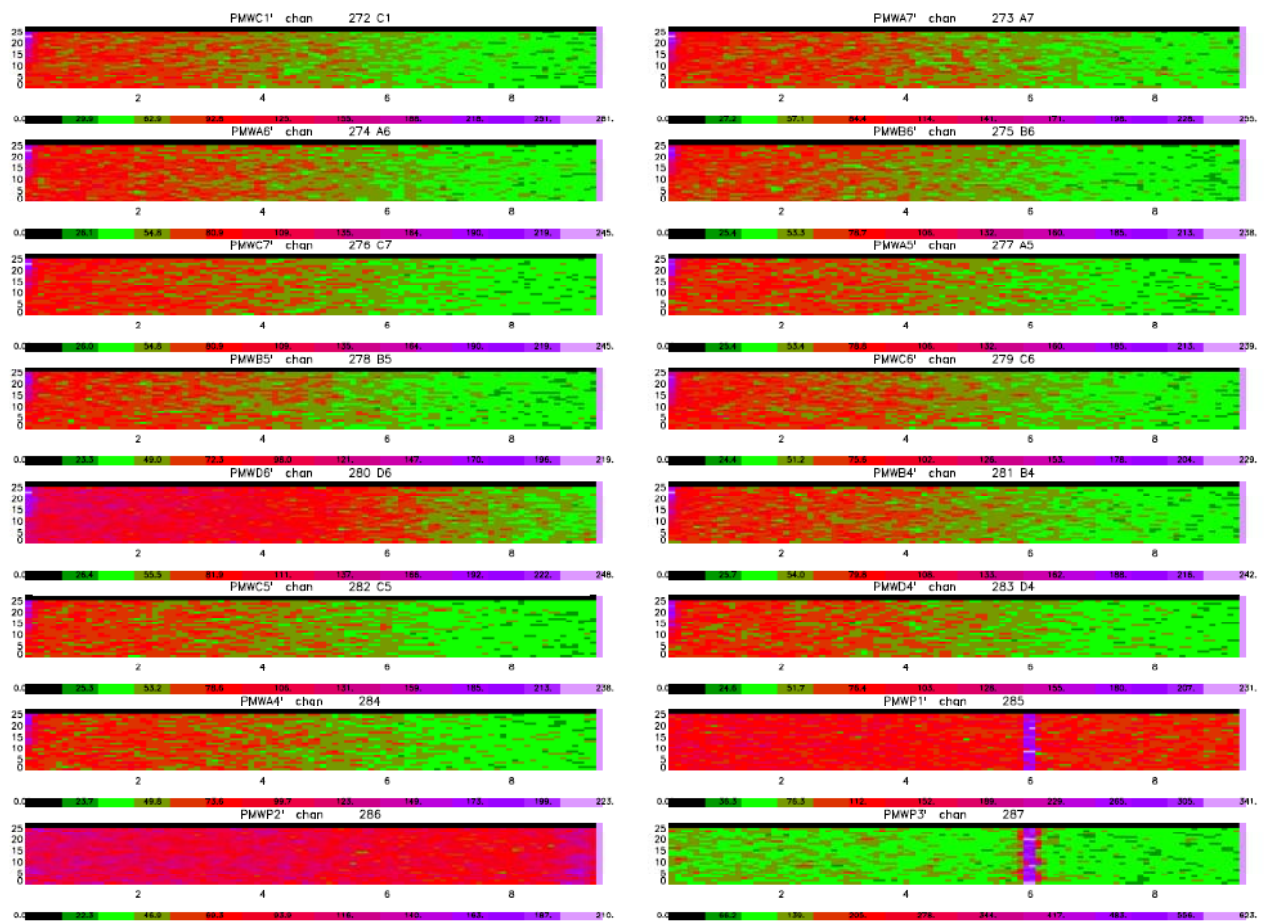
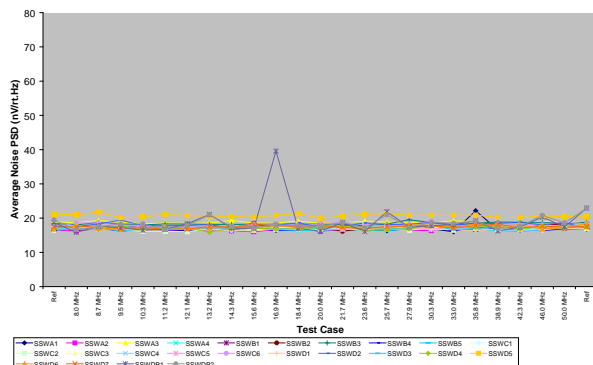


Figure 47

7.2 CS Common Mode – Spectrometer (0xB00014E1)

7.2.1 Noise PSD (using 10 seconds blocks of detector data)

SSW (A1-DP2)



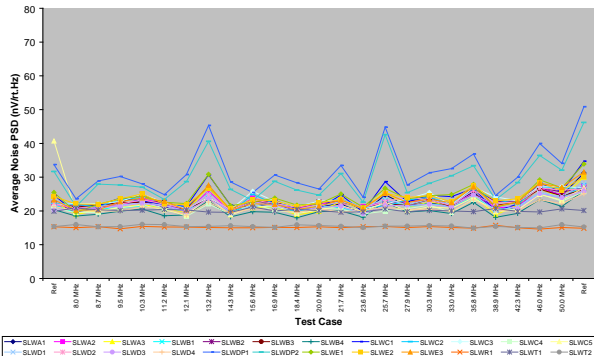
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SLW-DP1 and DP2 show highest excess noise
SLW-R1, T1 and T2 have low noise and show no apparent Frequency dependency

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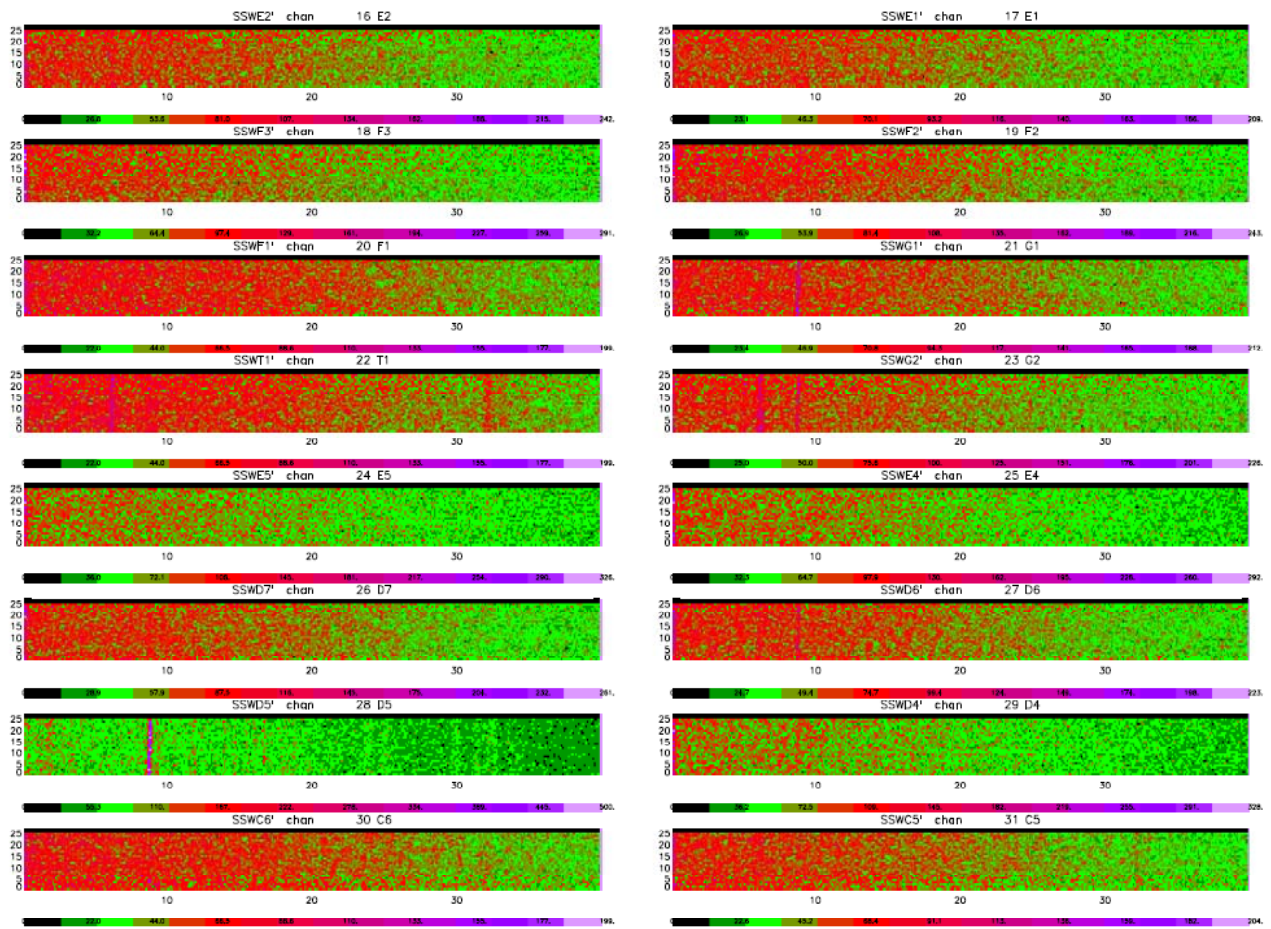


Figure 49

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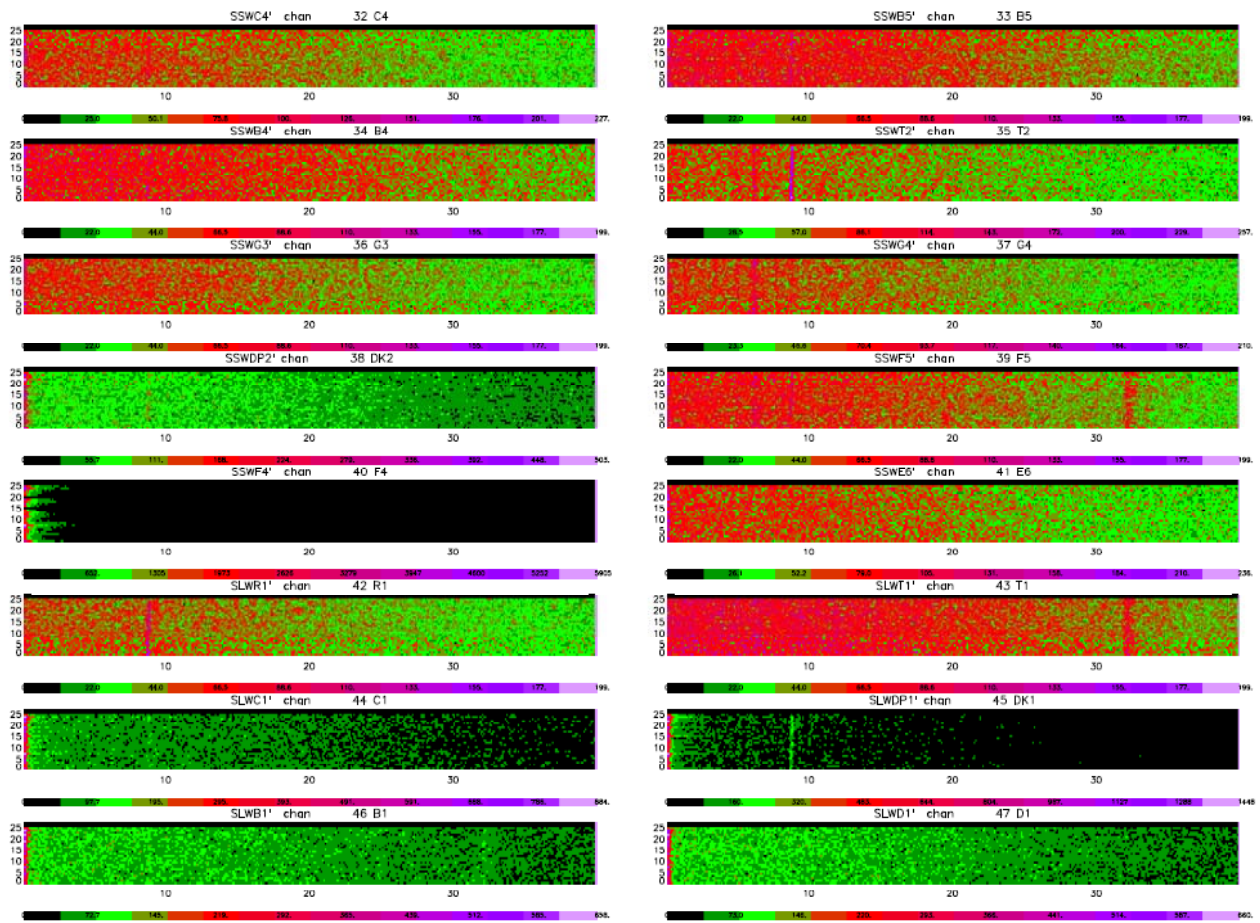


Figure 50

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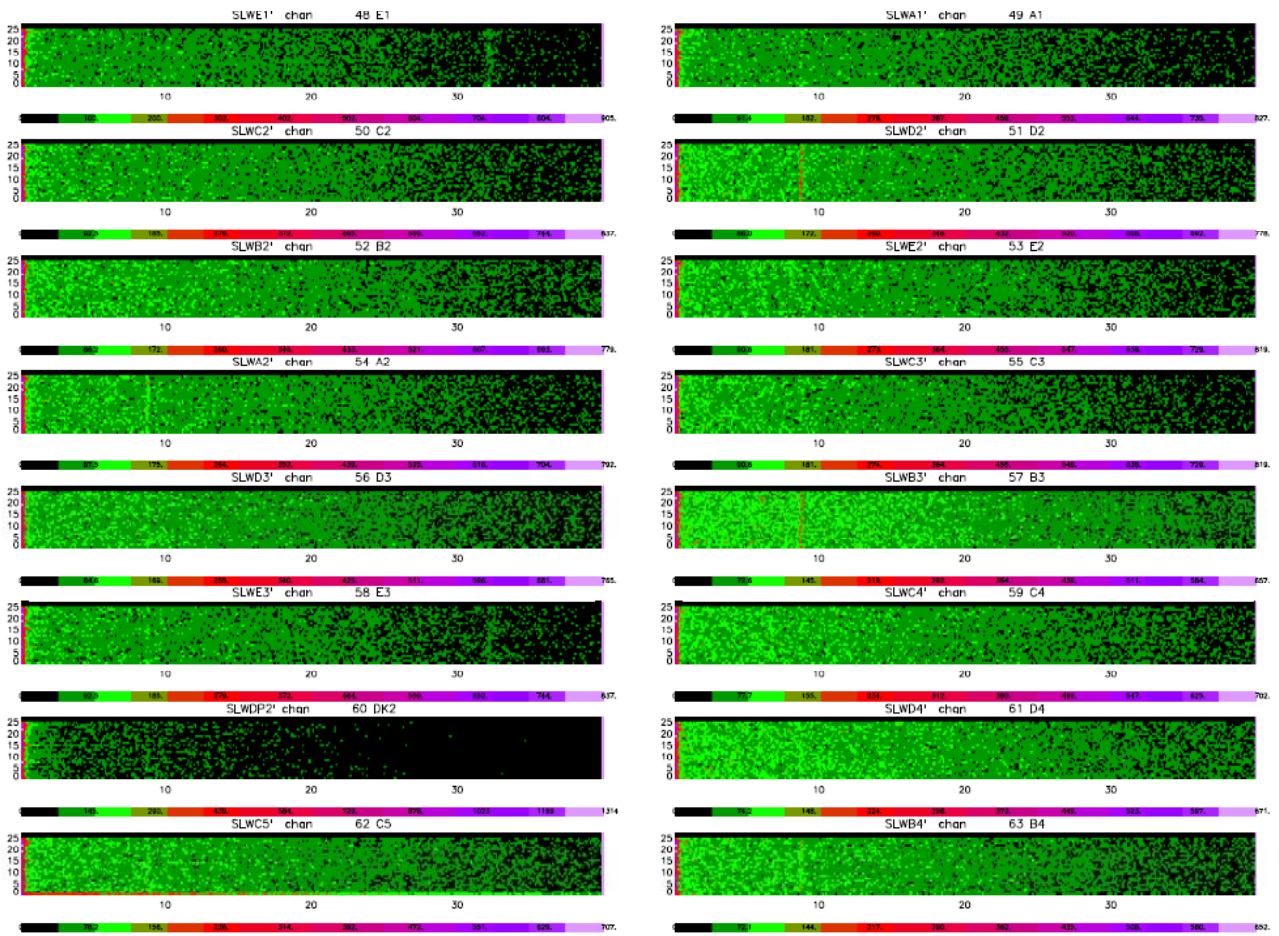


Figure 51

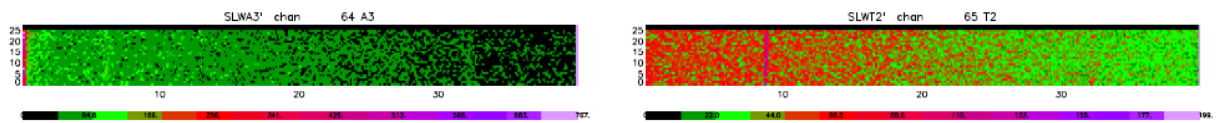


Figure 52

SPIRE SPT EMC Test Report

Ref: SPIRE-RAL-REP-003164

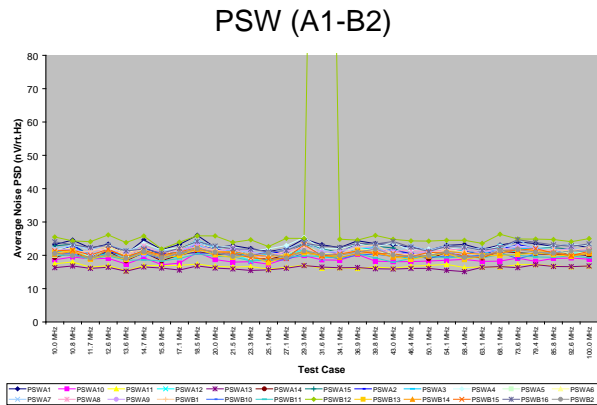
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8. Appendix 3: Radiated Susceptibility Detailed Results

8.1 RS – Photometer: V-Polarization (0xB00014EB Step 1)



PSW B12 "spikes"

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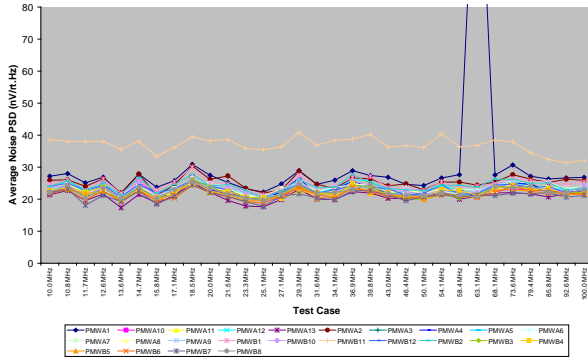
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PMW (A1-B8)



PMW-B11 shows excess noise @ ~ 35nV/√Hz
PMW-A1 “spikes”

8.1.1 PSW Spectrogrammes

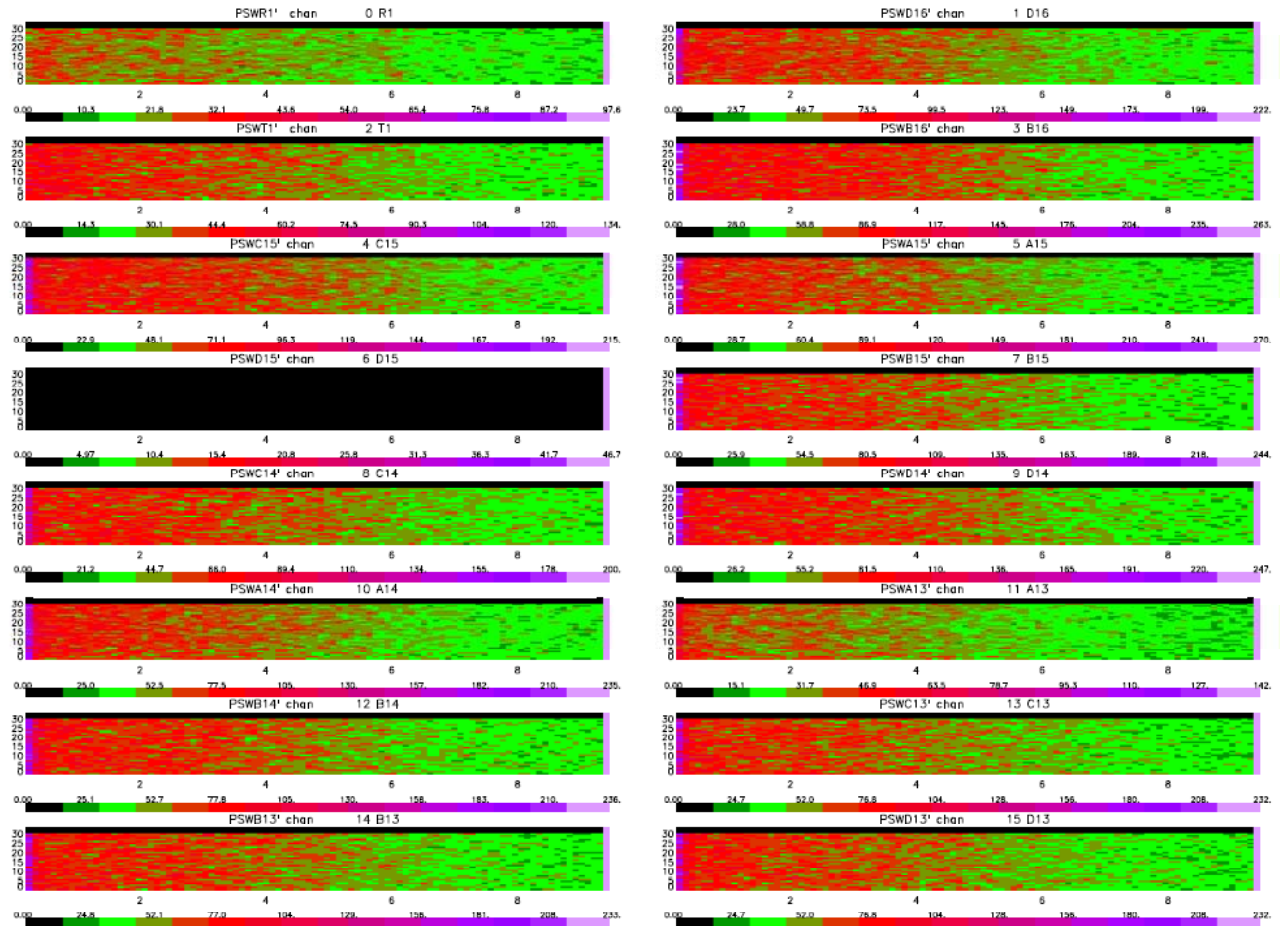


Figure 53

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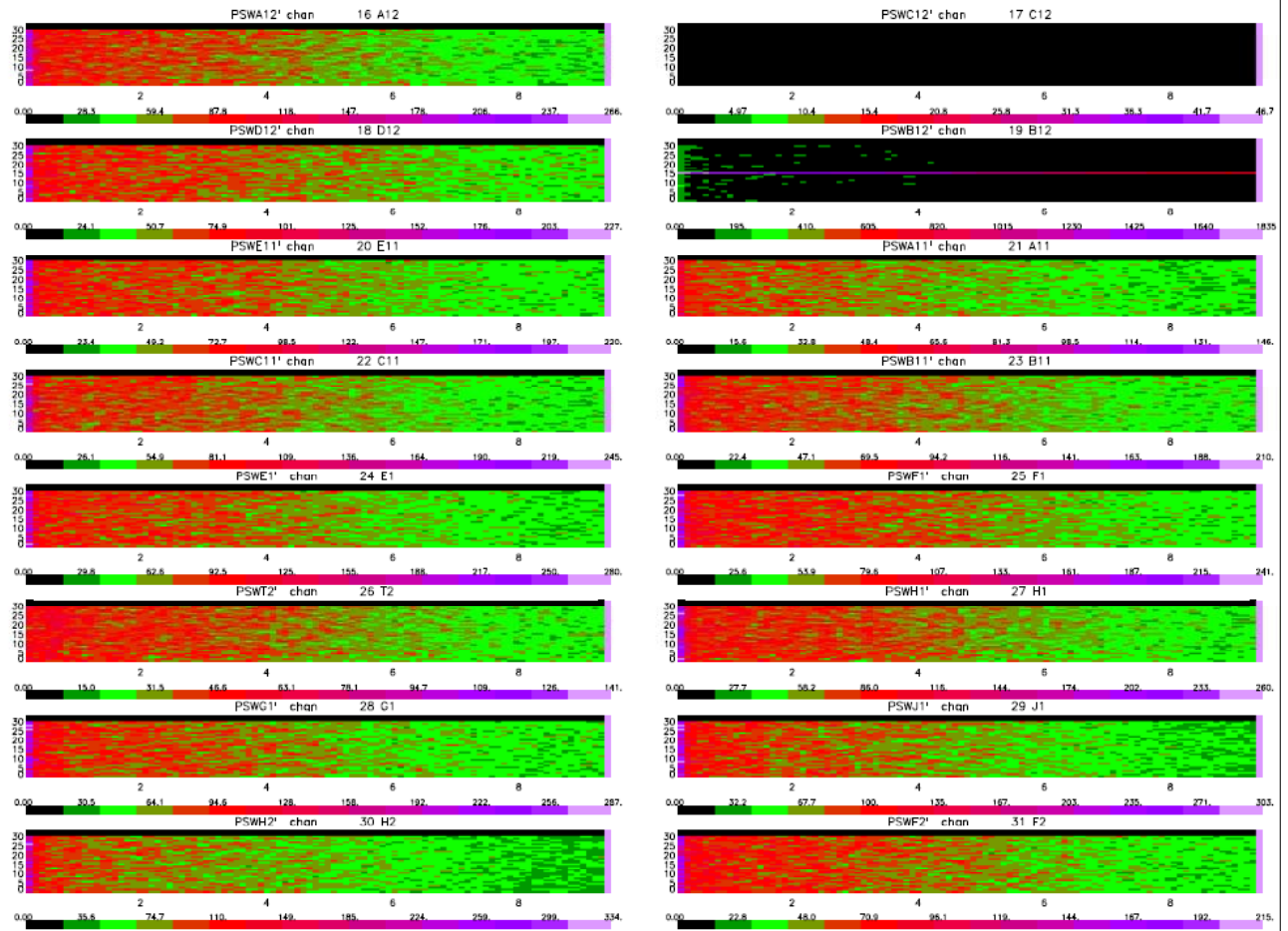


Figure 54

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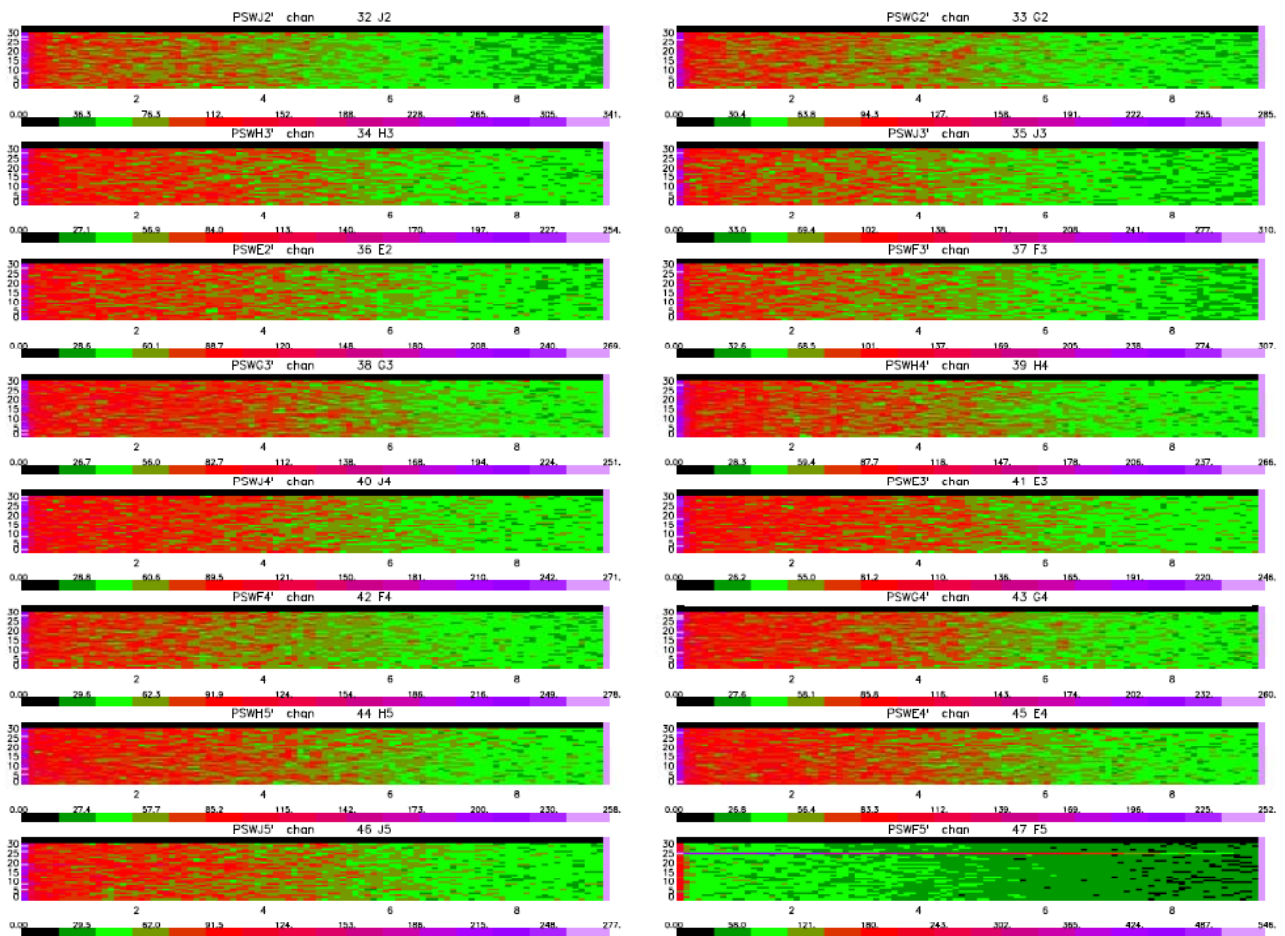


Figure 55

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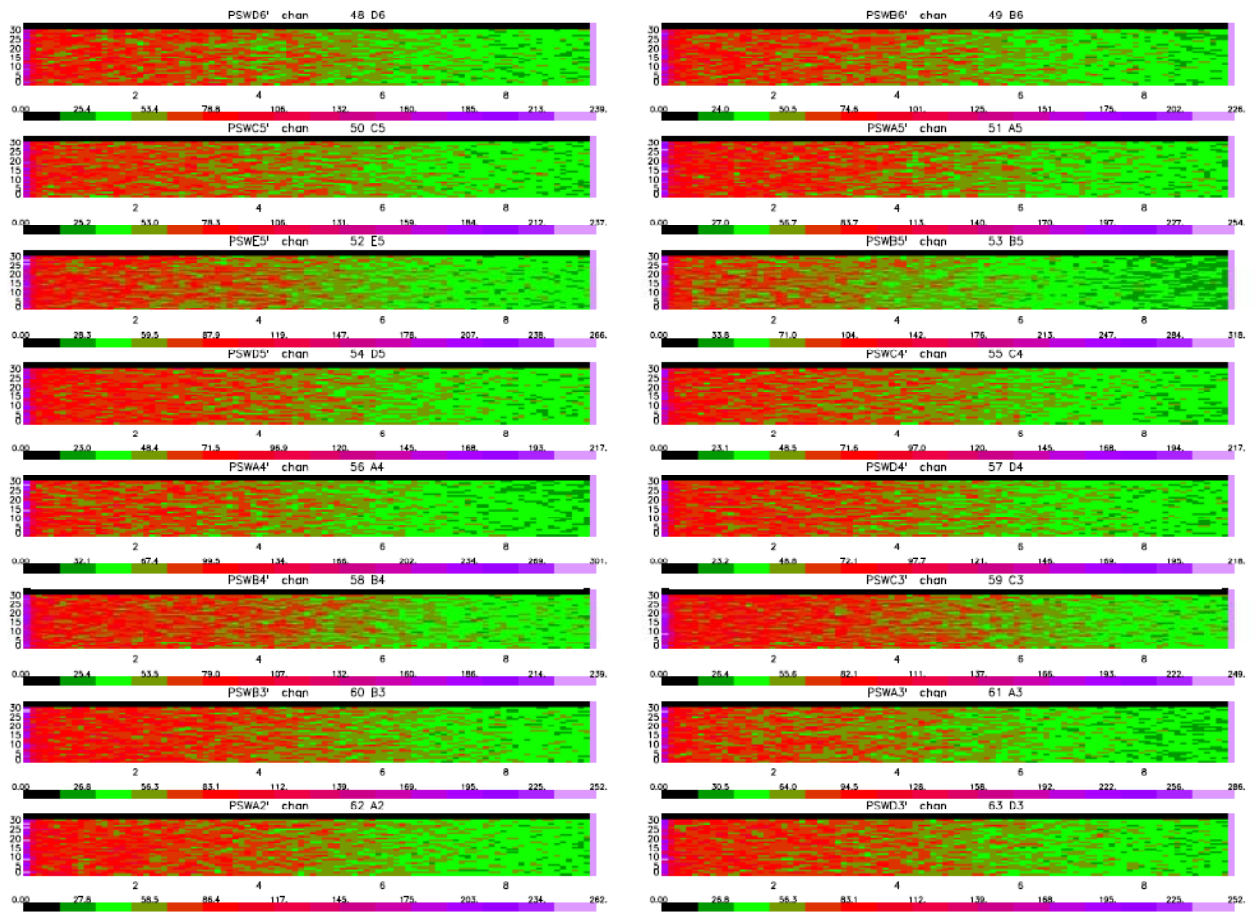


Figure 56

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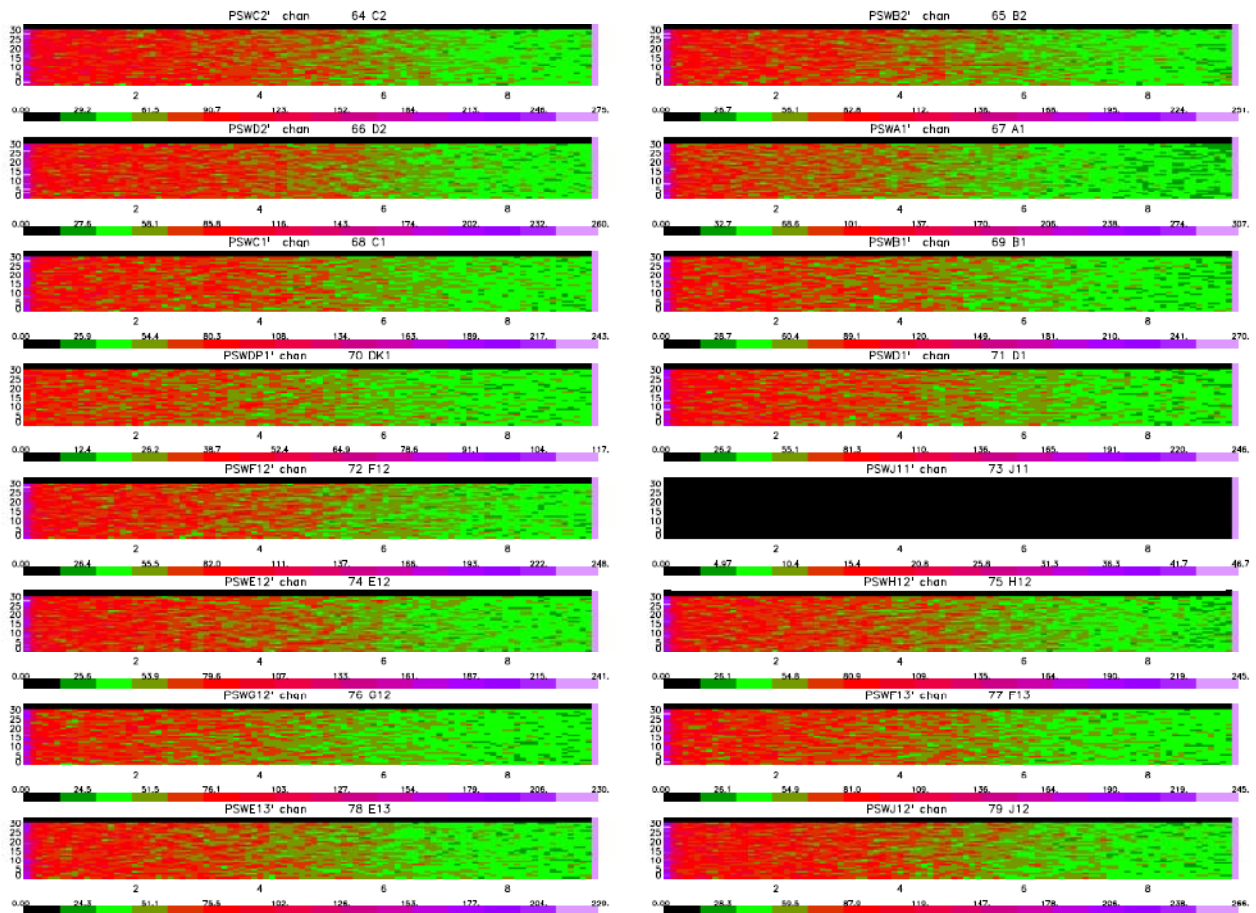


Figure 57

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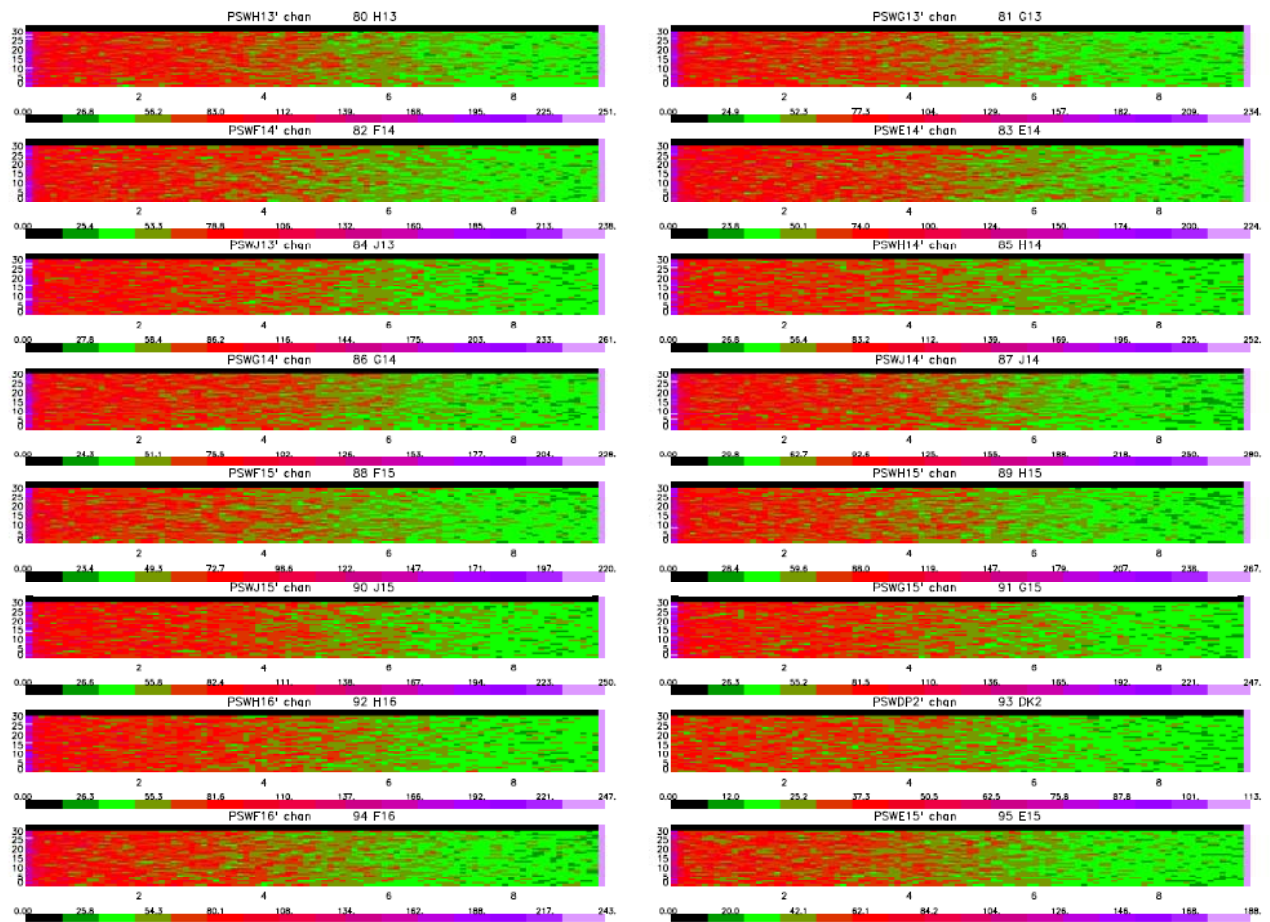


Figure 58

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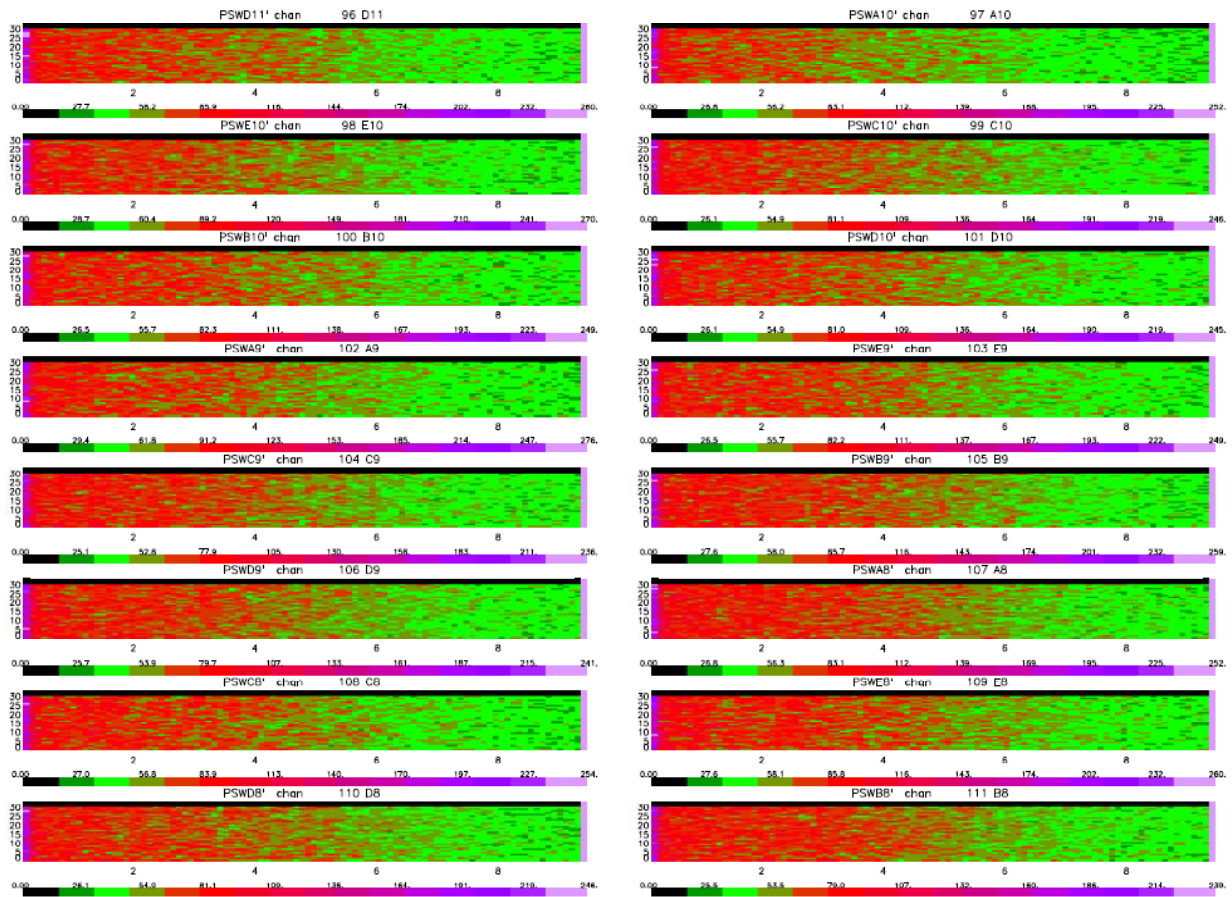


Figure 59

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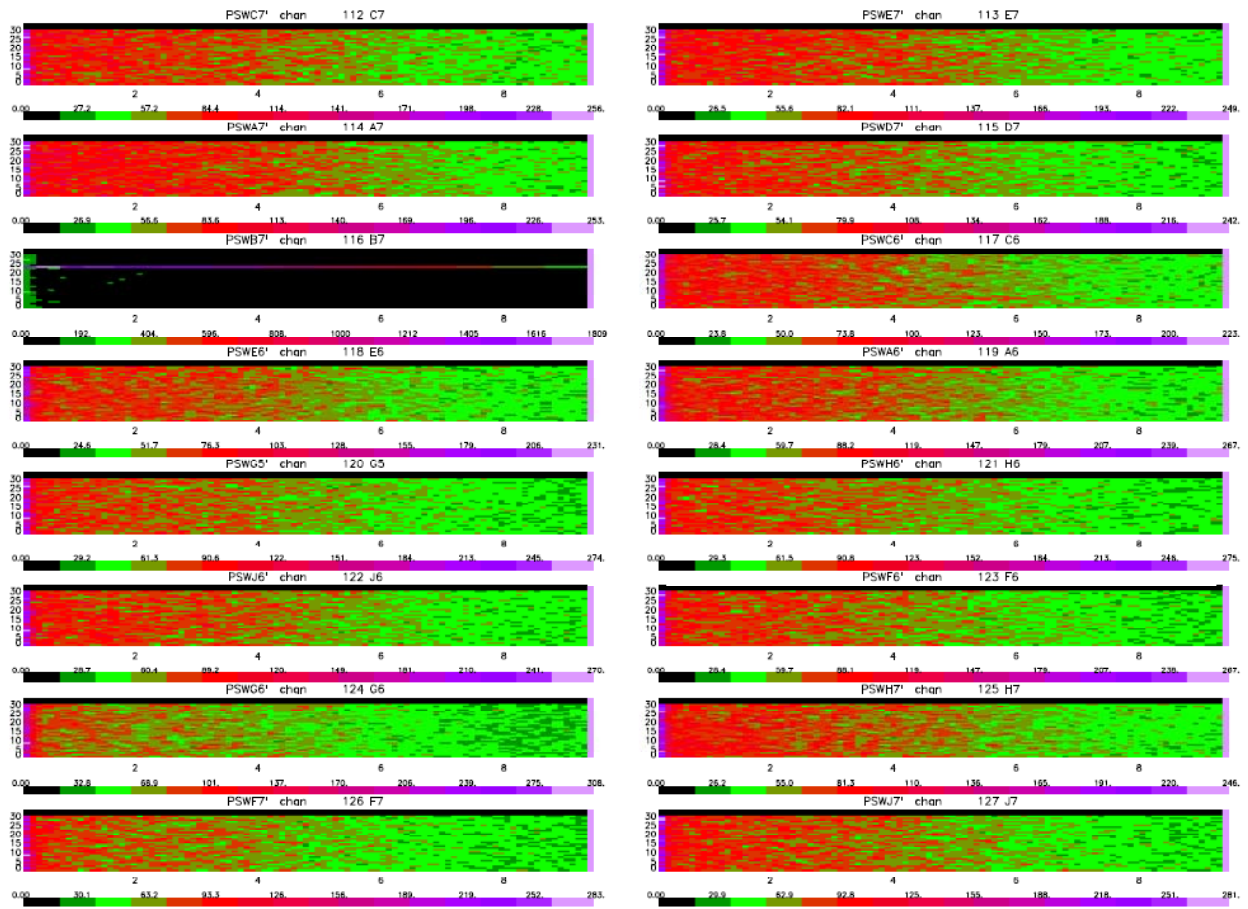


Figure 60

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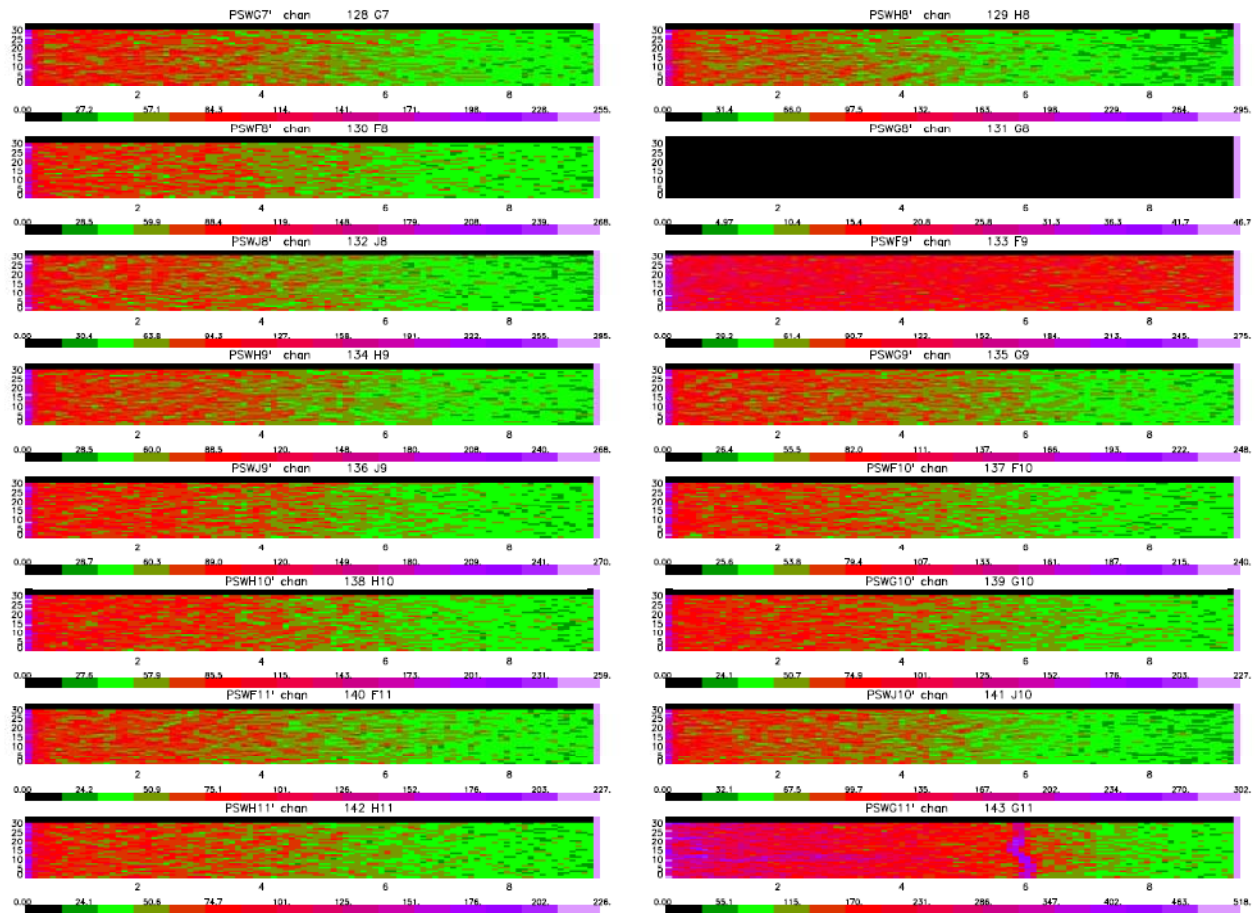


Figure 61

8.1.2 PLW Spectrogrammes

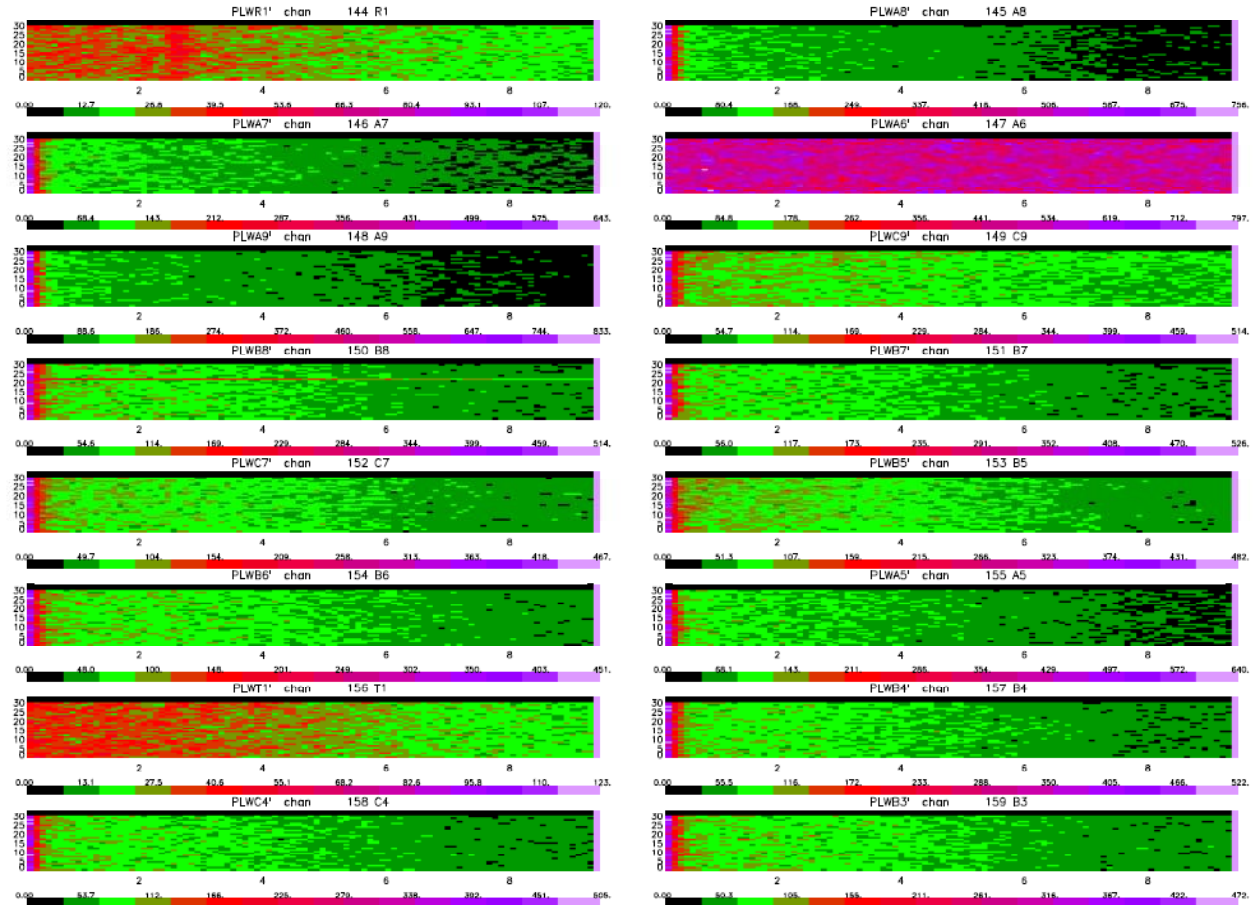


Figure 62

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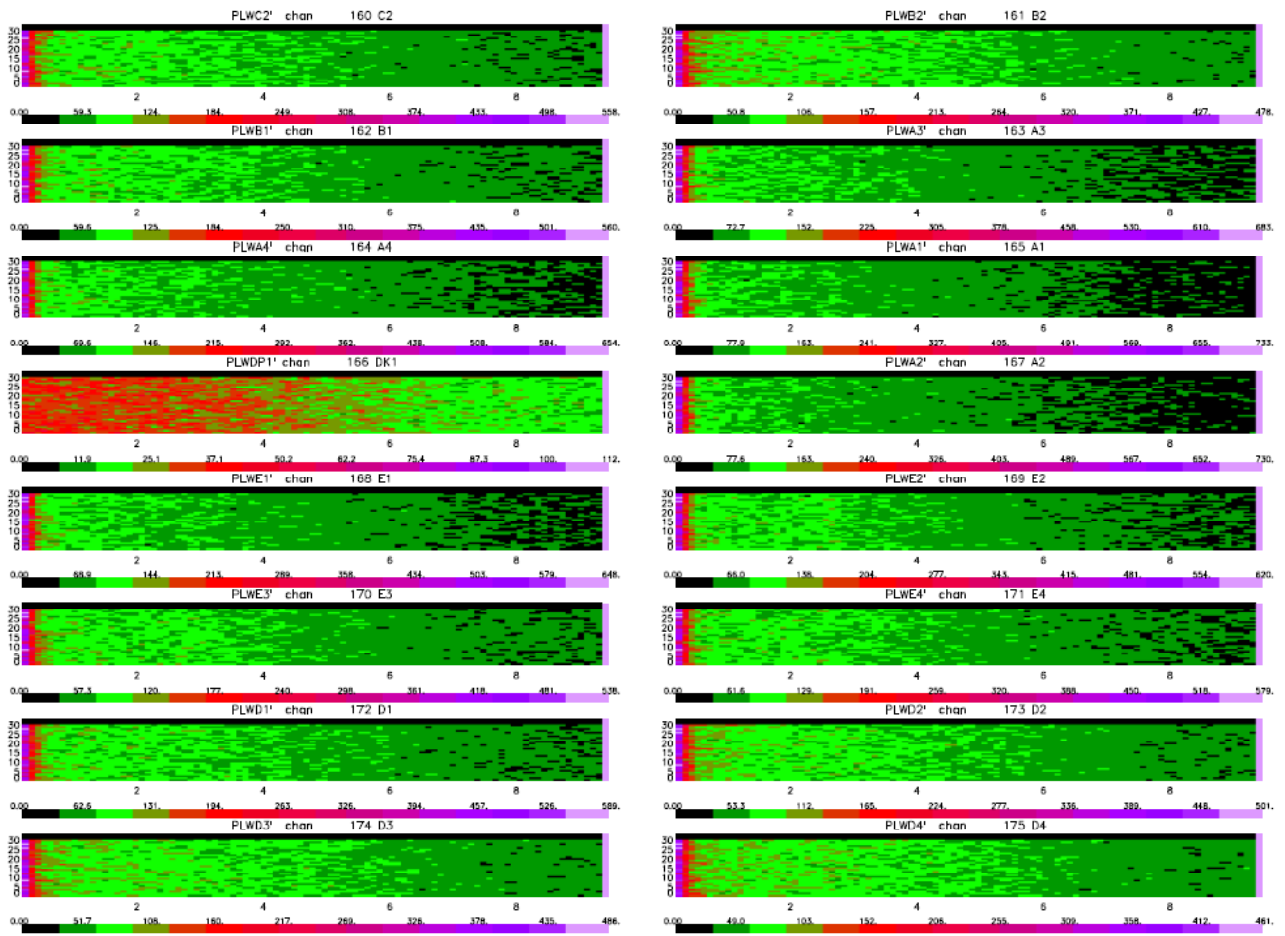


Figure 63

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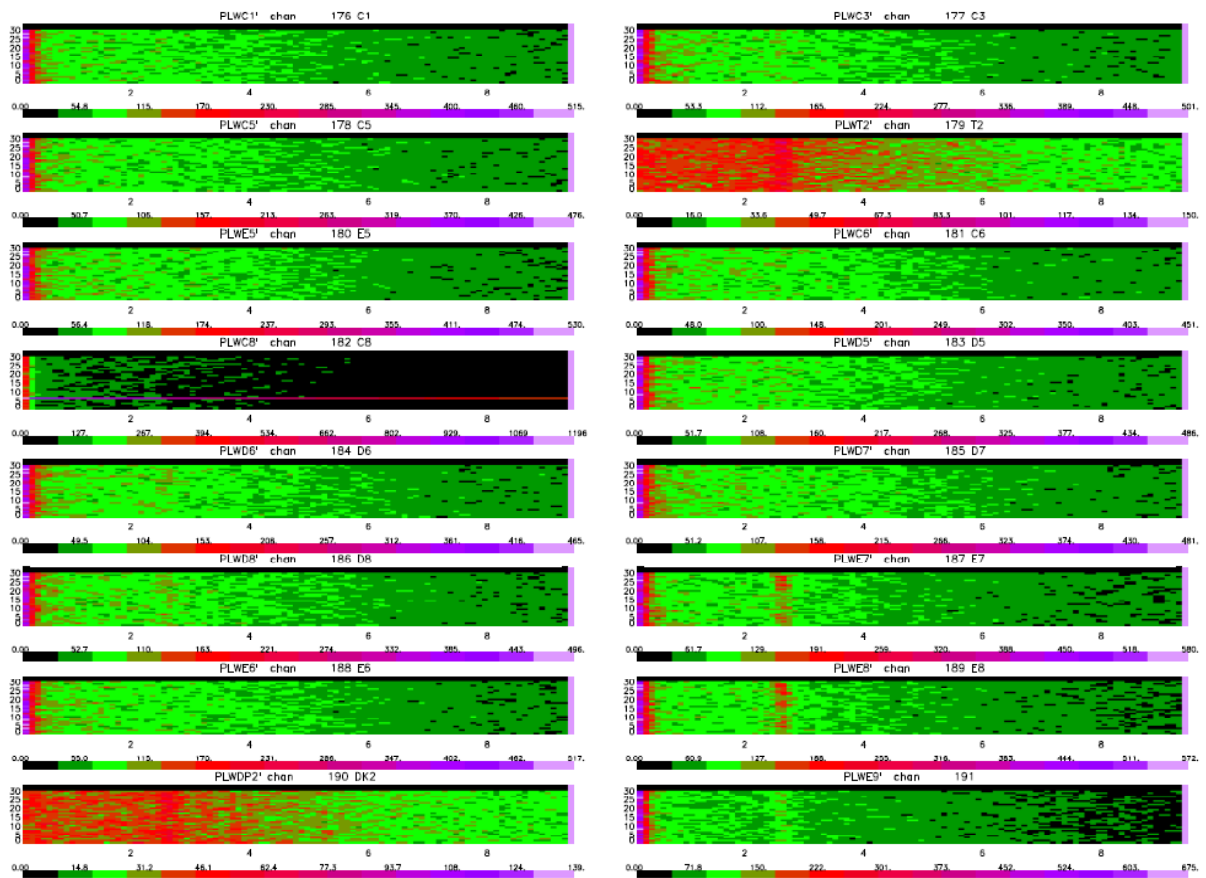


Figure 64

8.1.3 PMW Spectrogrammes

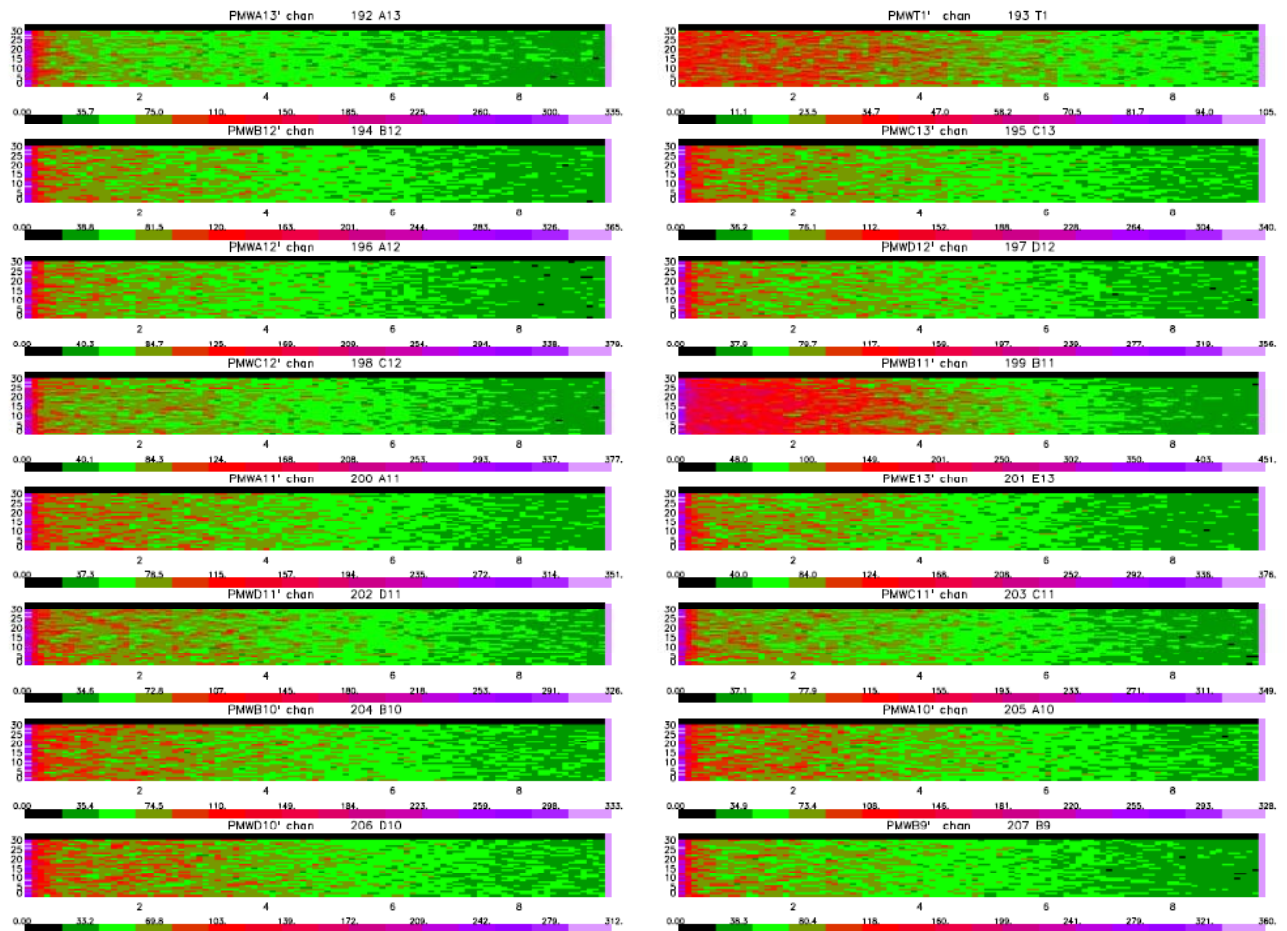


Figure 65

SPIRE SPT EMC Test Report

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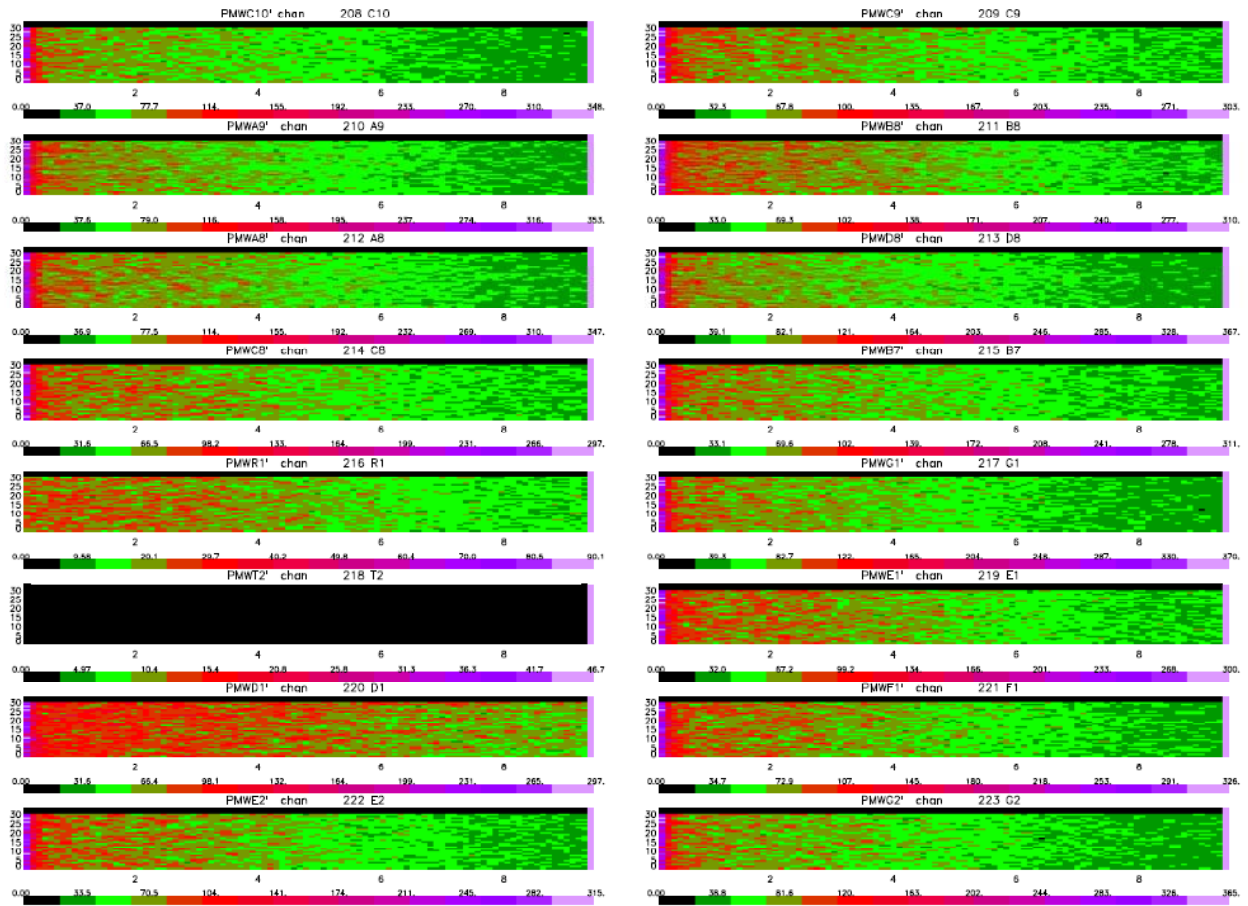


Figure 66

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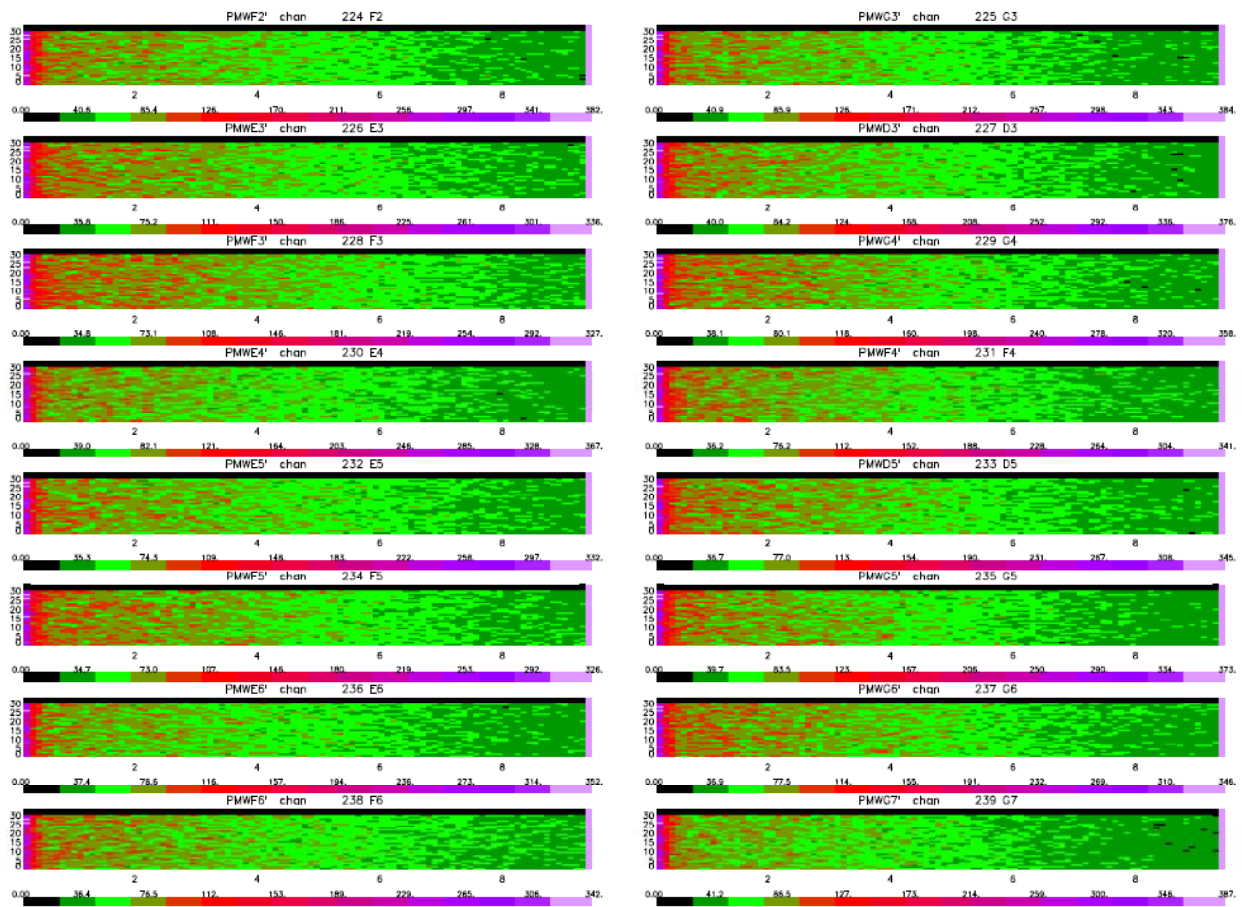


Figure 67

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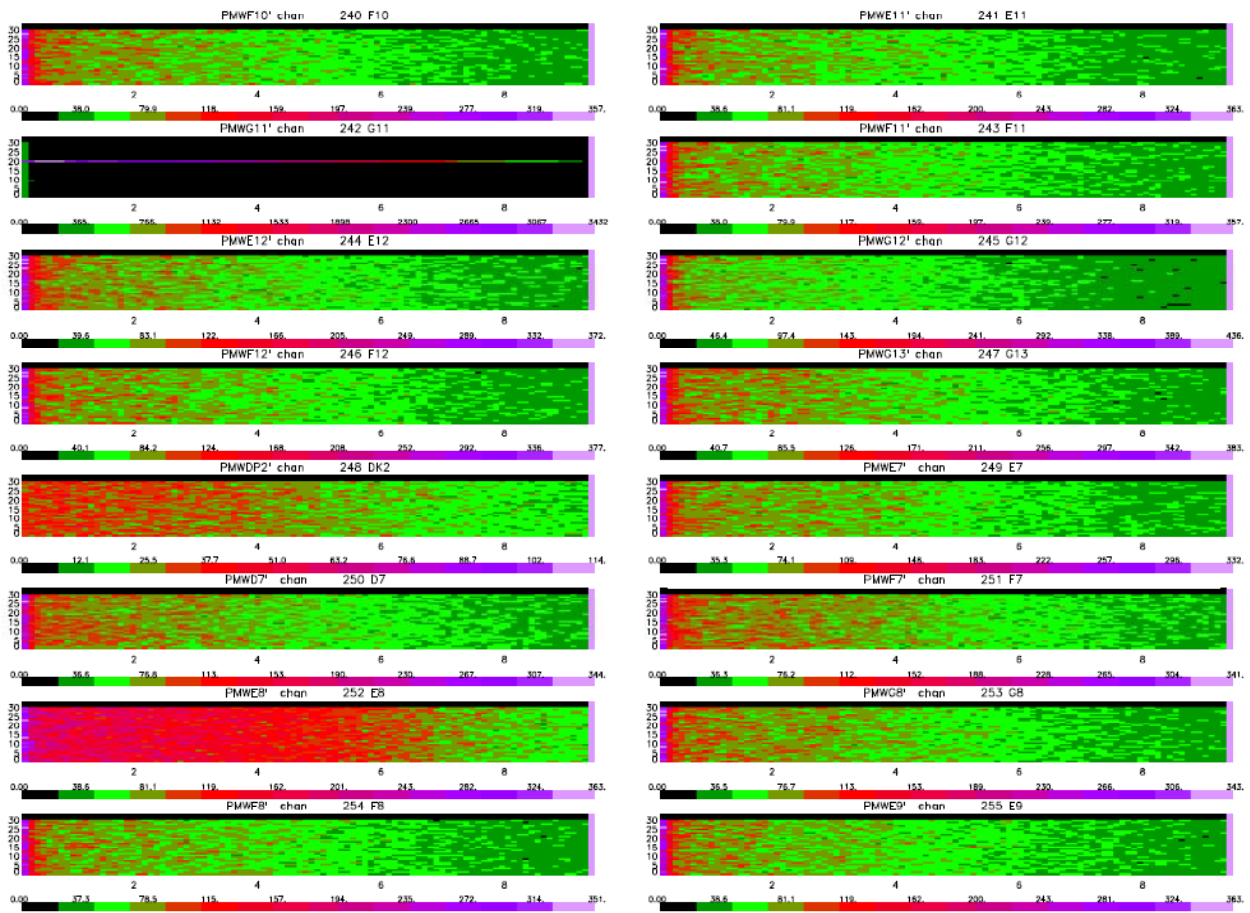


Figure 68

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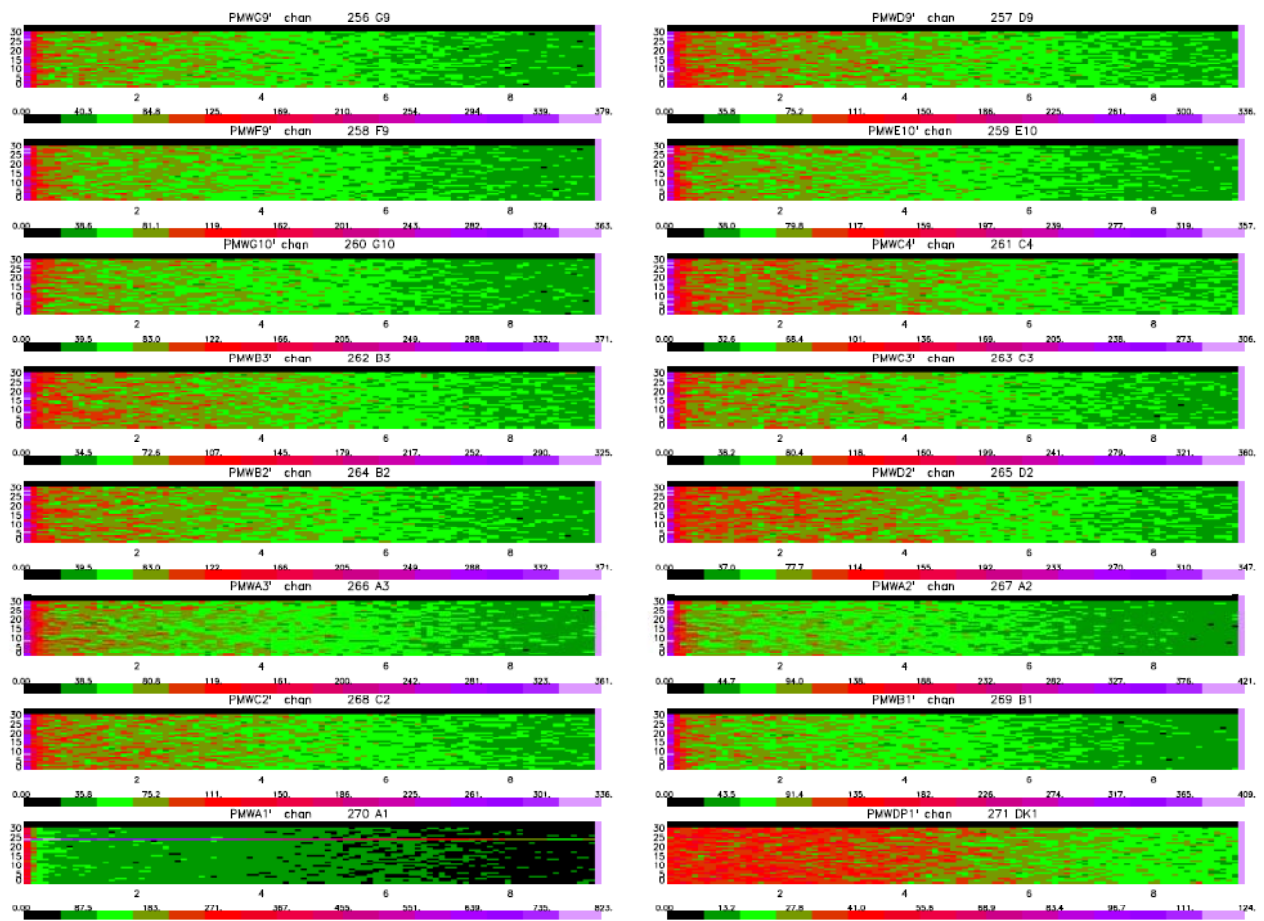


Figure 69

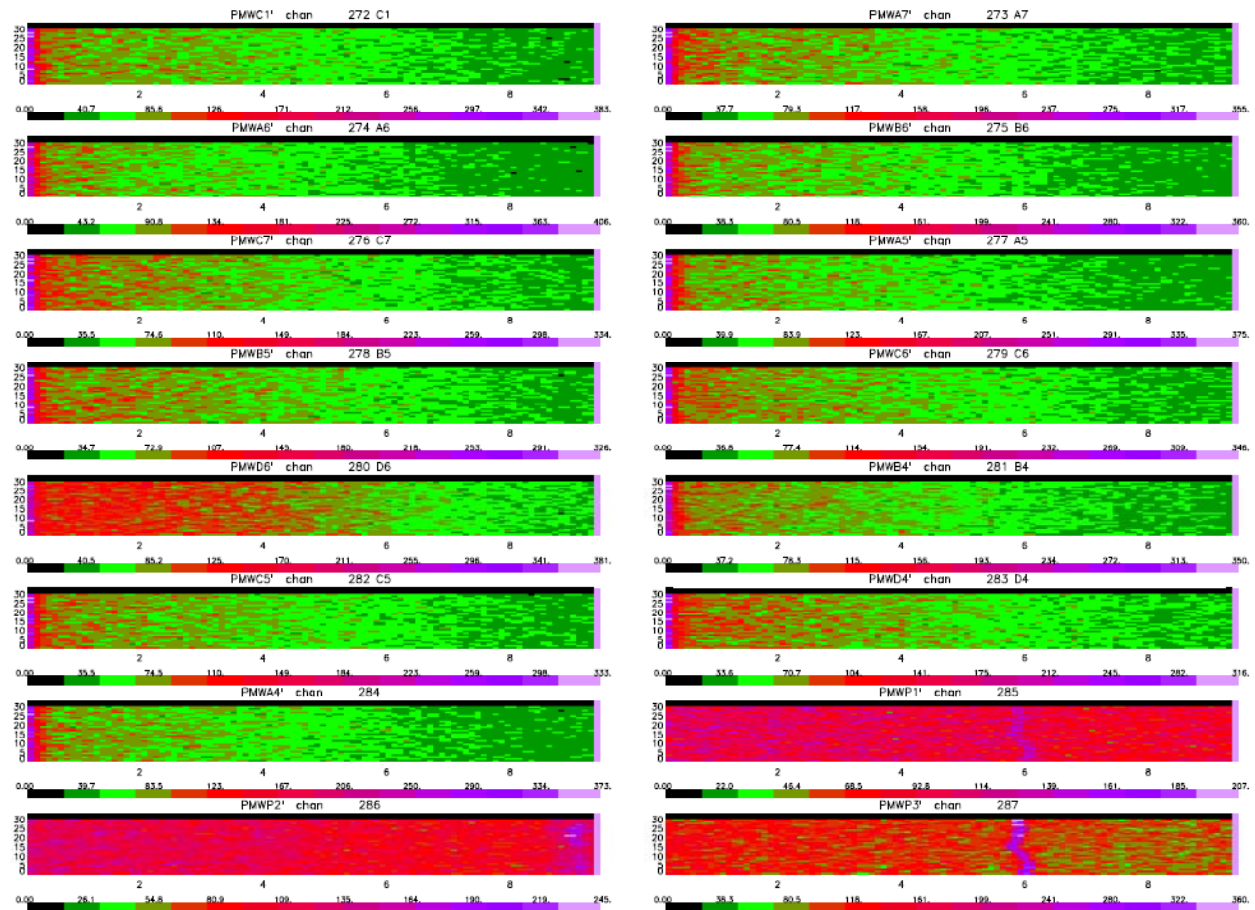
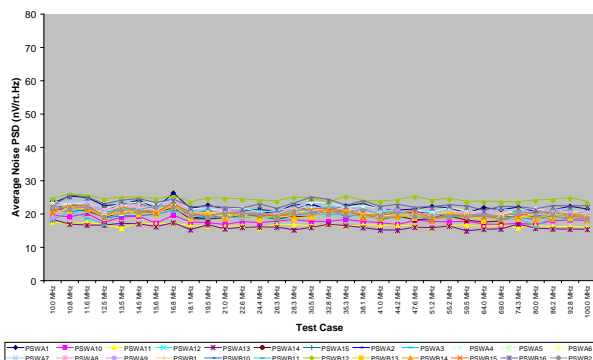


Figure 70

8.2 RS – Photometer: H-Polarization (0xB00014EB Step 2)

PSW (A1-B2)



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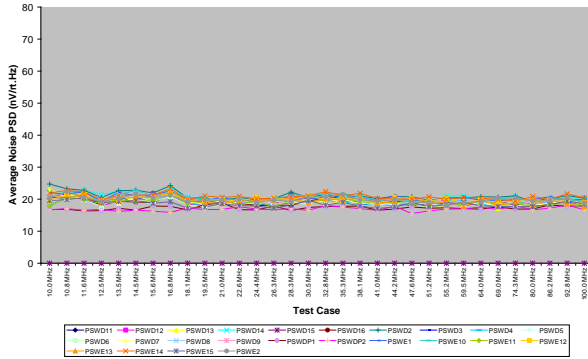
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PSW (D11-E2)



PSW DP1 and DP2 have flat noise traces

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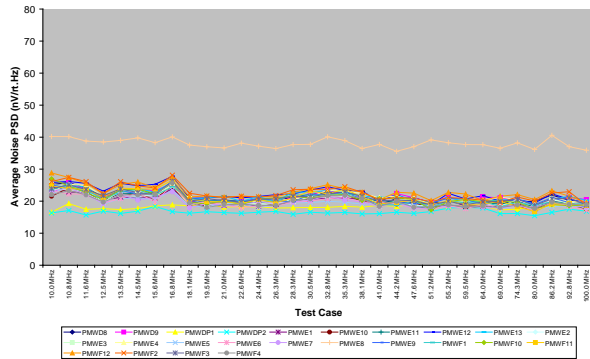
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PMW (D8-F4)



PMW-E8 shows excess noise @ $\sim 37\text{nV}/\sqrt{\text{Hz}}$
PMW DP1 and DP2 have flat noise traces

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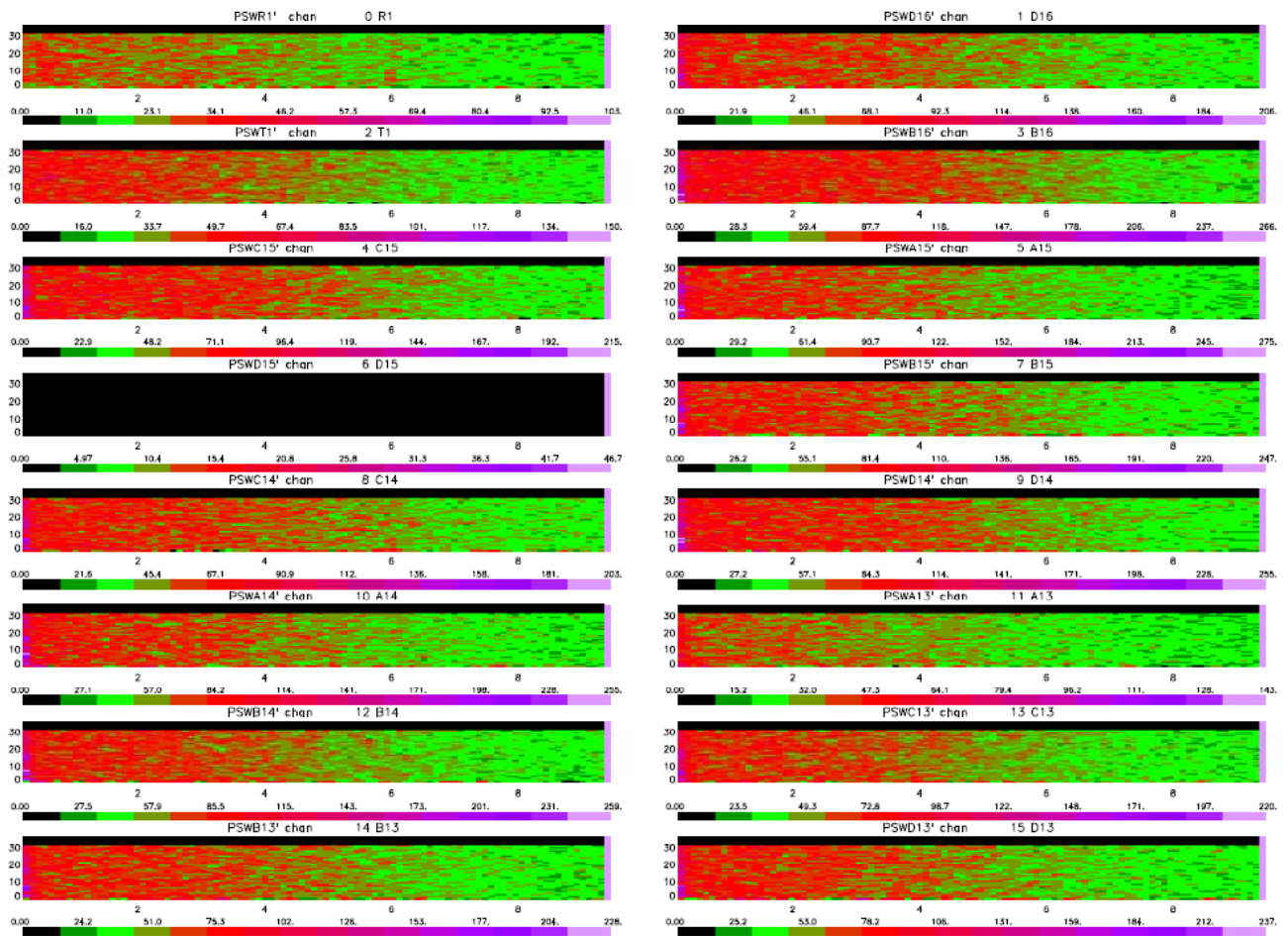


Figure 71

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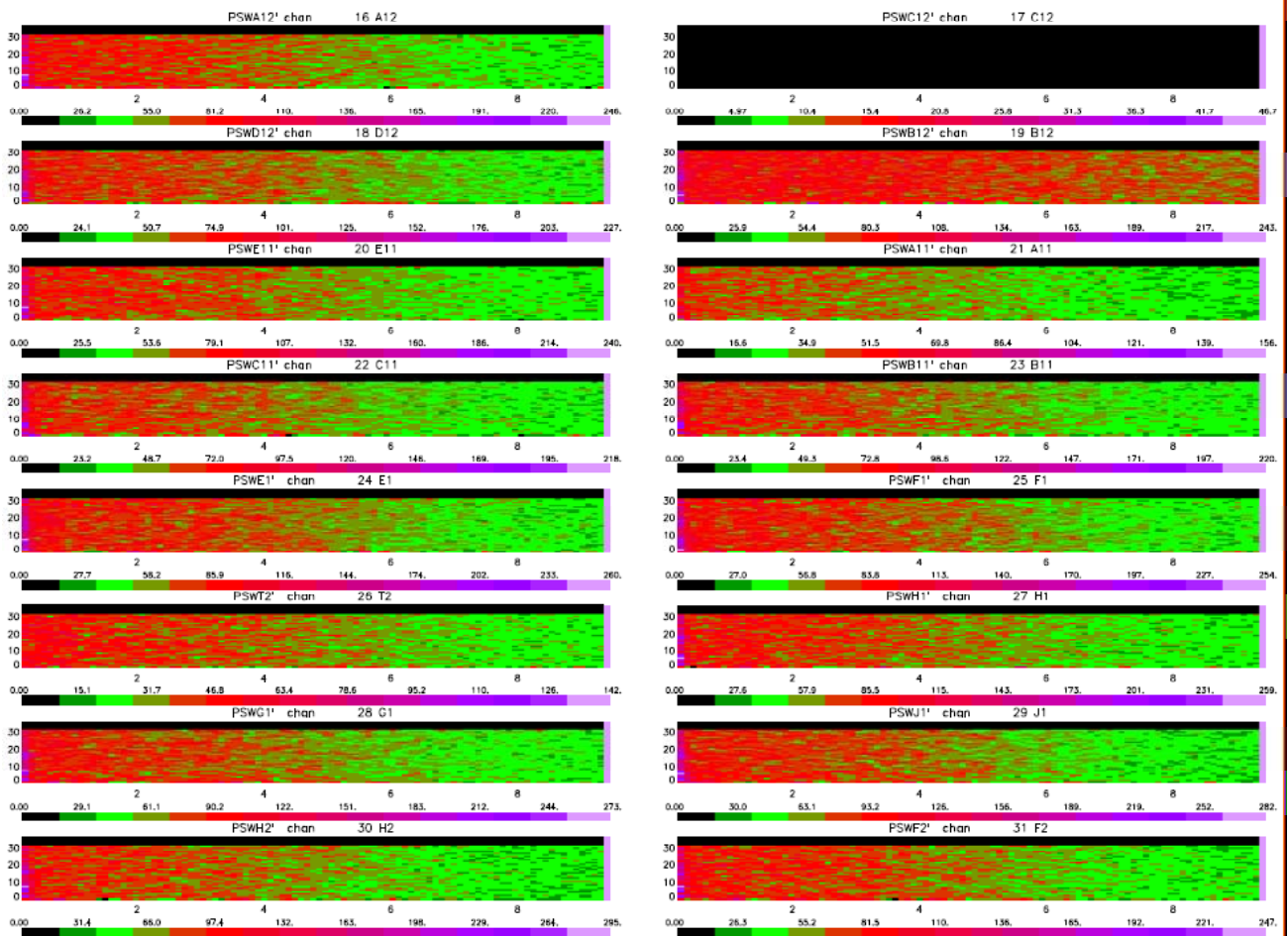


Figure 72

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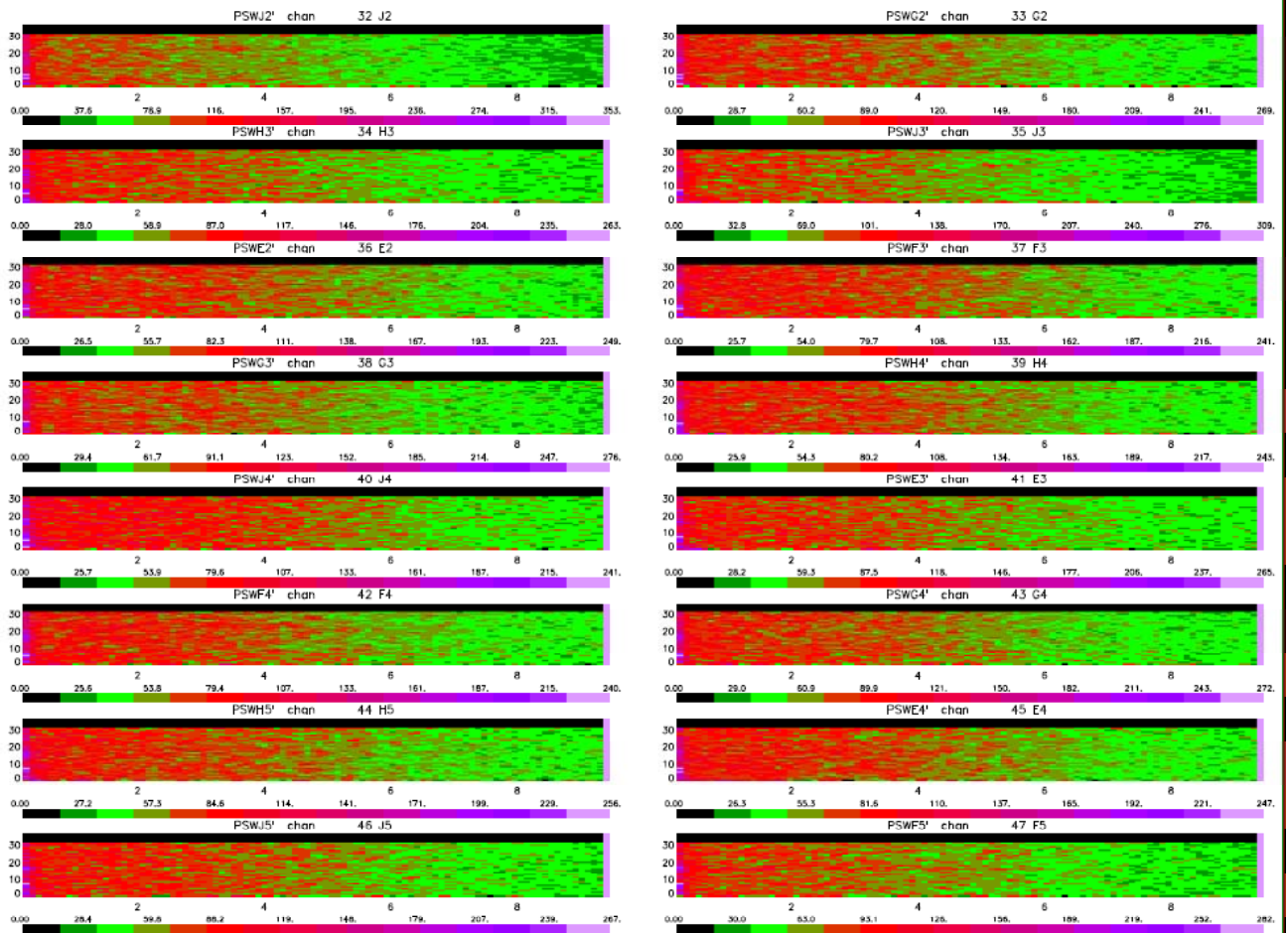


Figure 73

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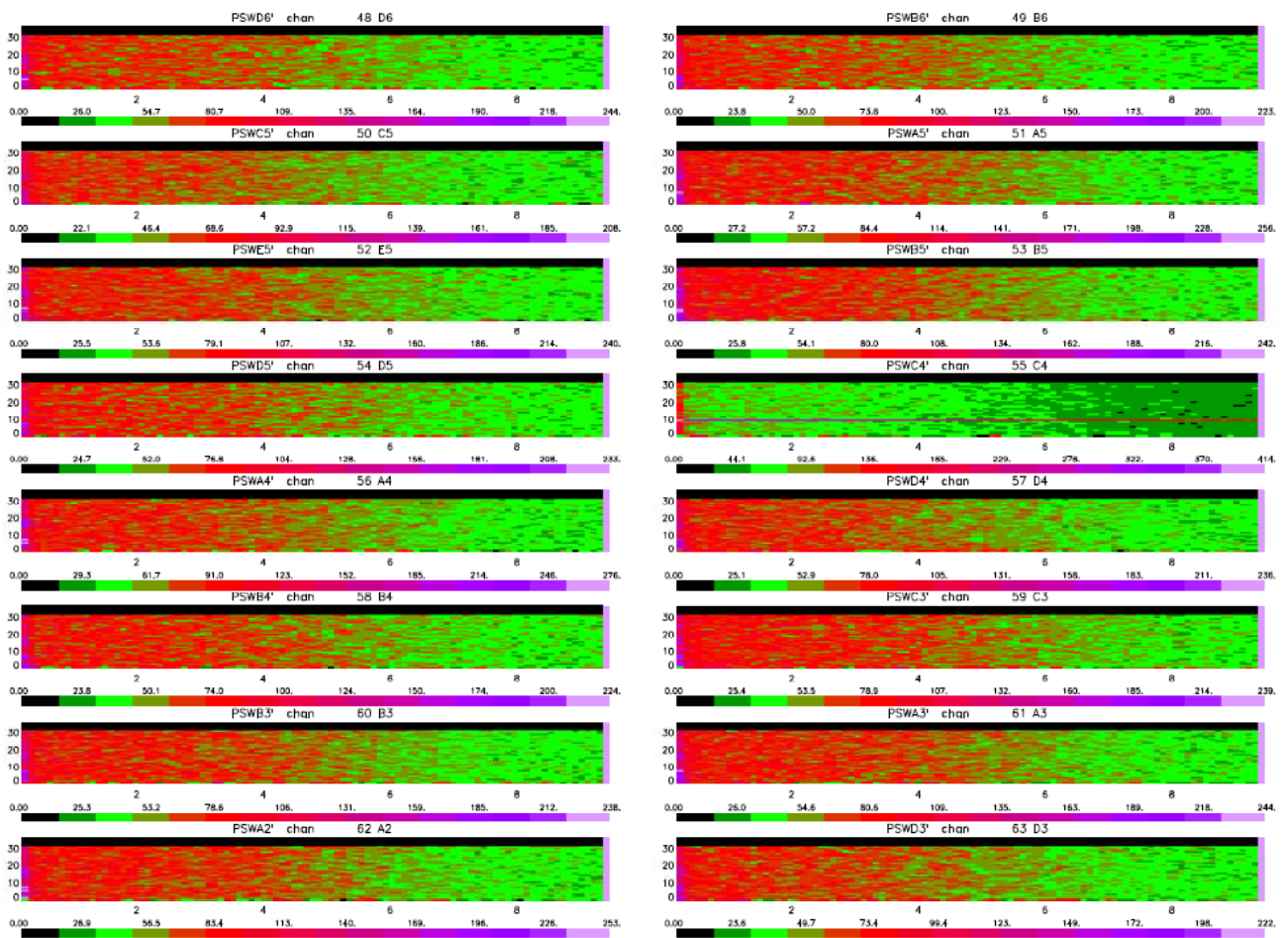


Figure 74

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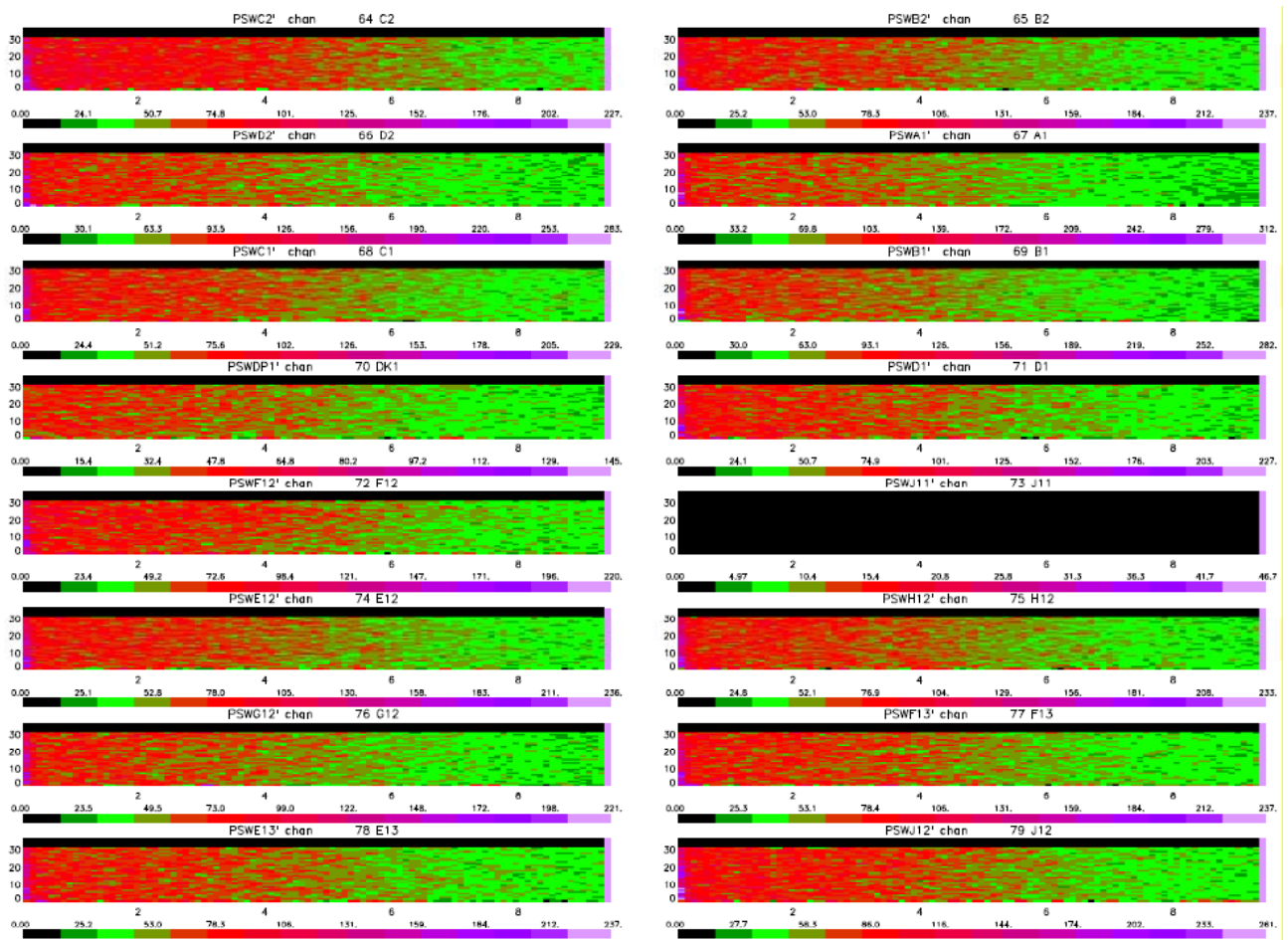


Figure 75

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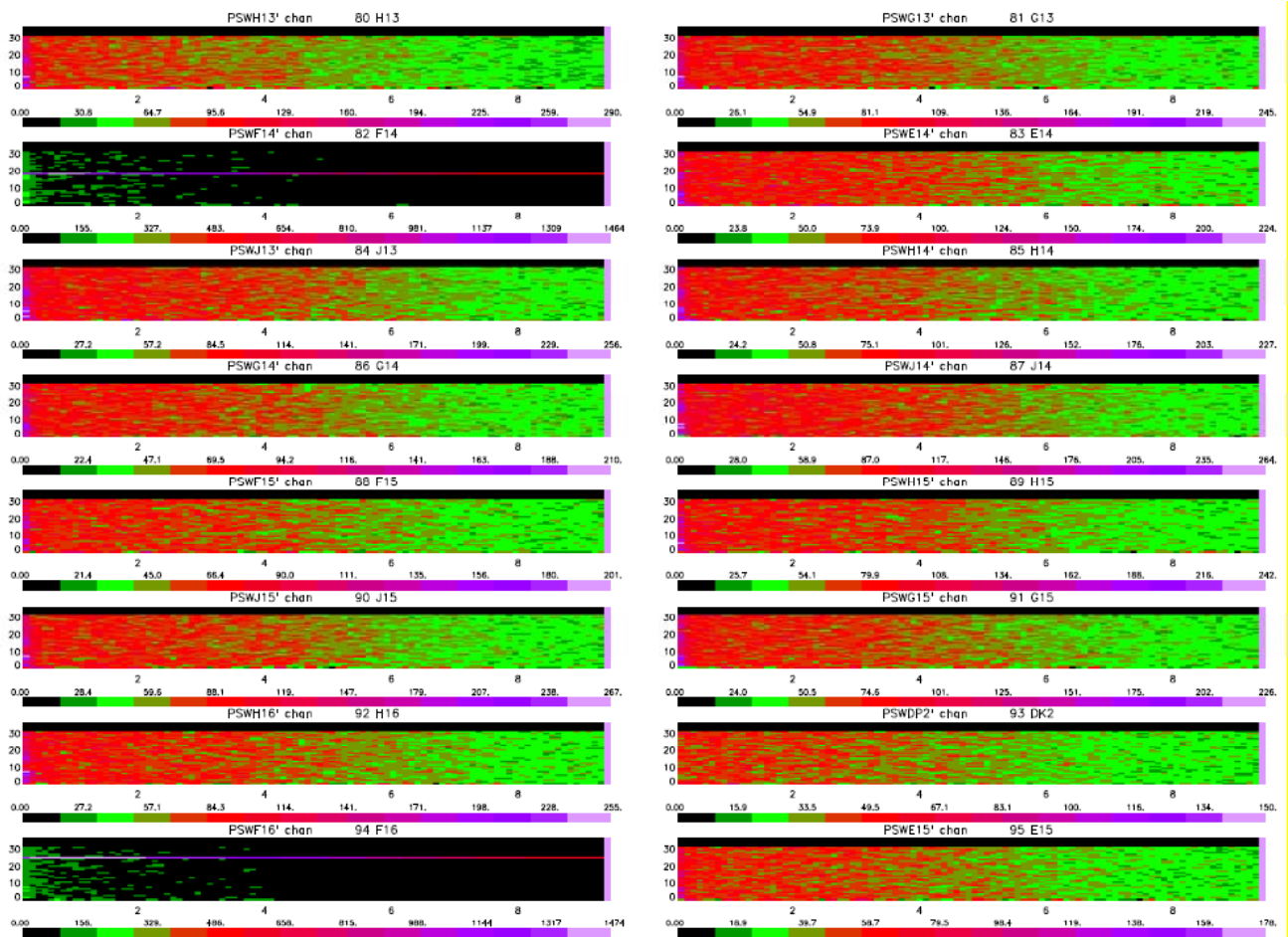


Figure 76

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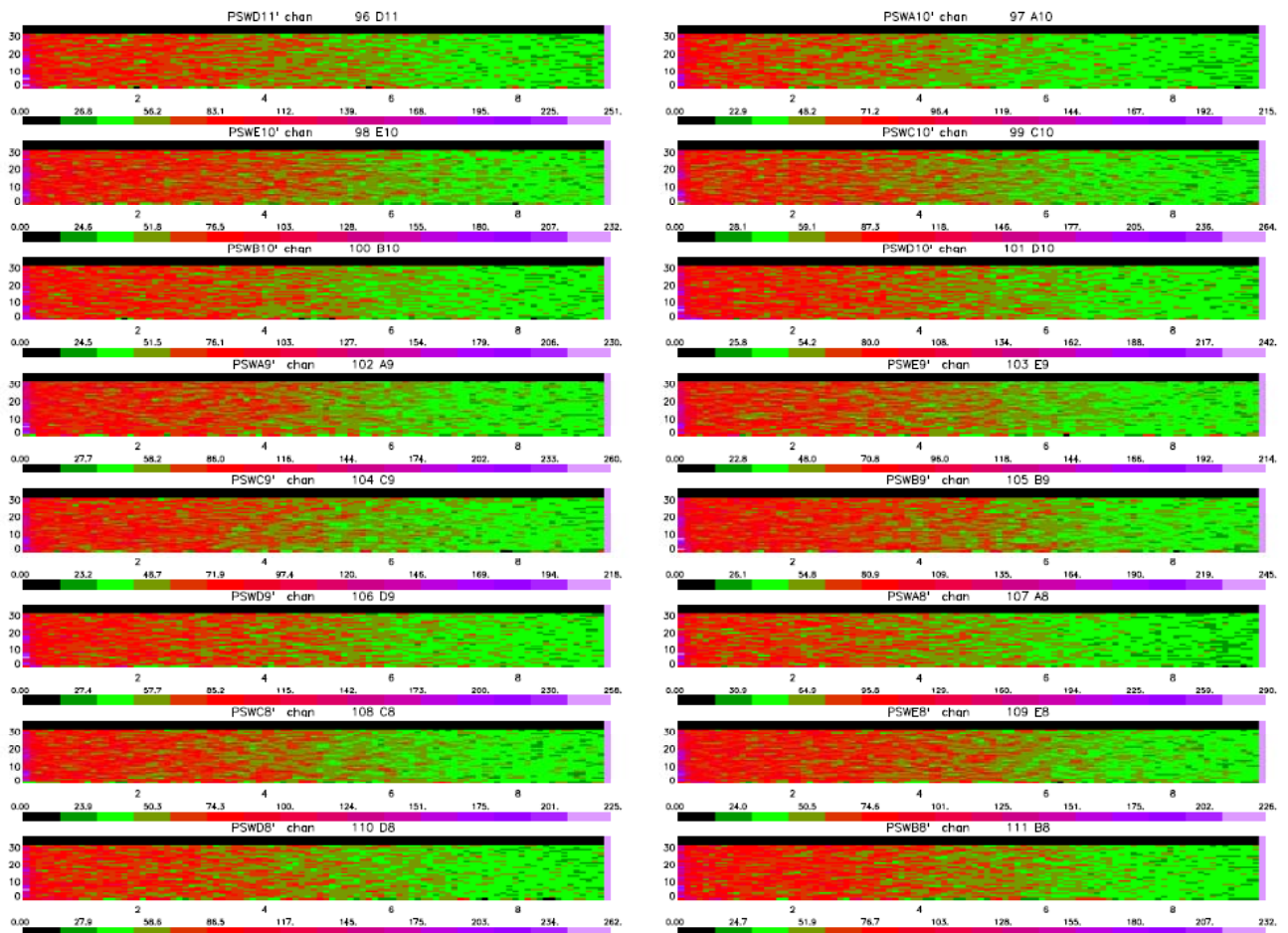


Figure 77

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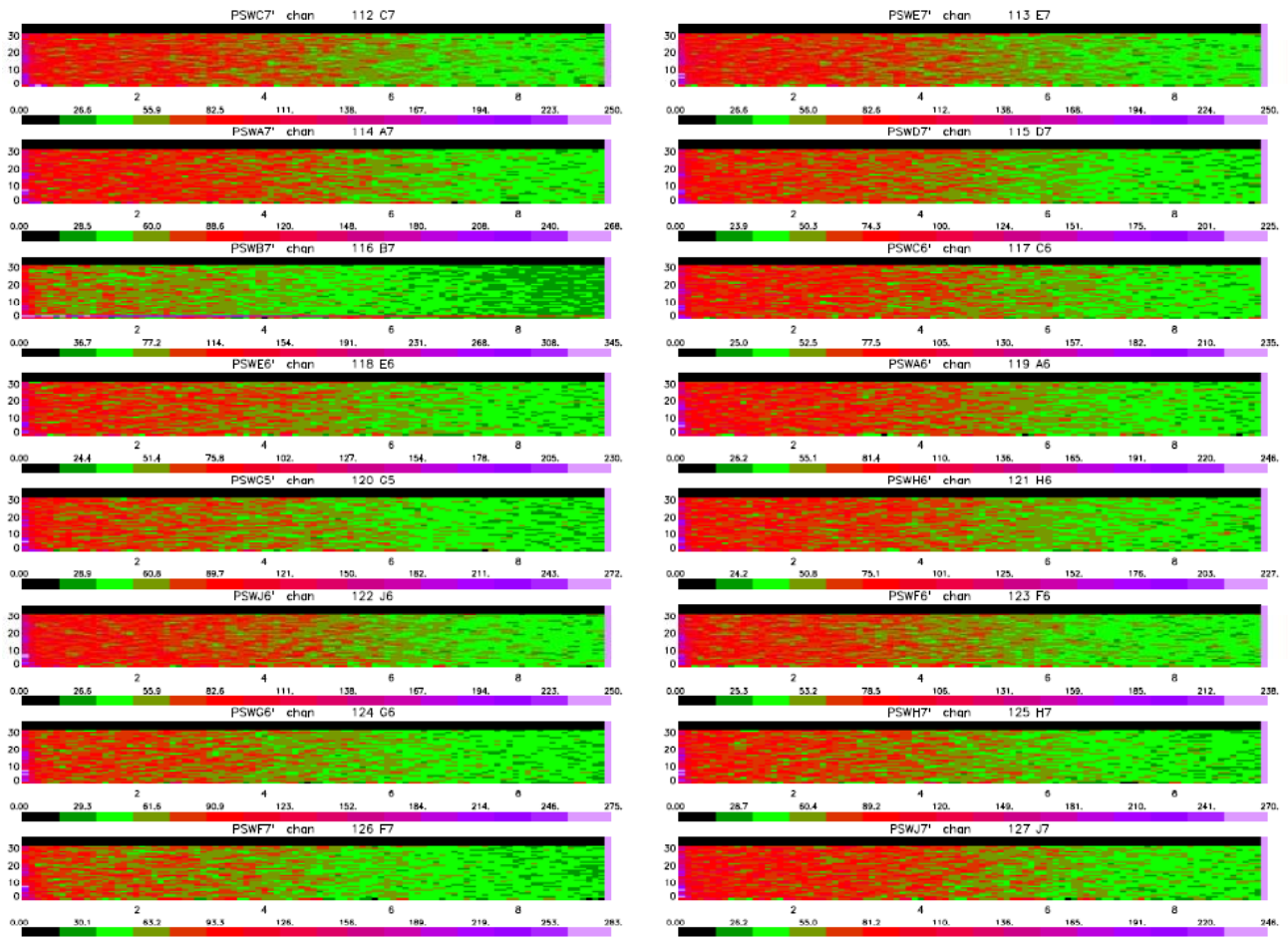


Figure 78

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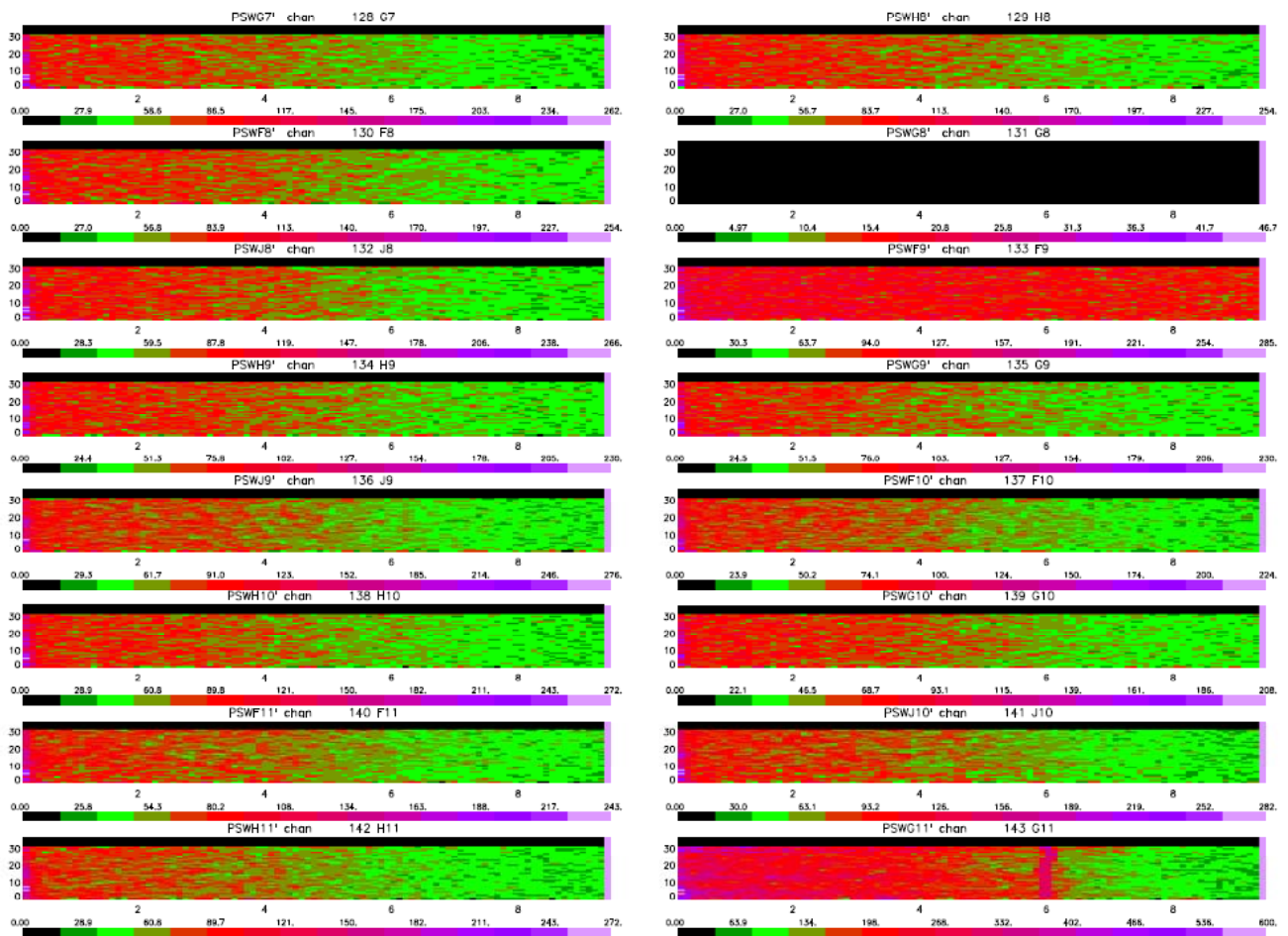


Figure 79

8.2.1 PLW Spectrogrammes

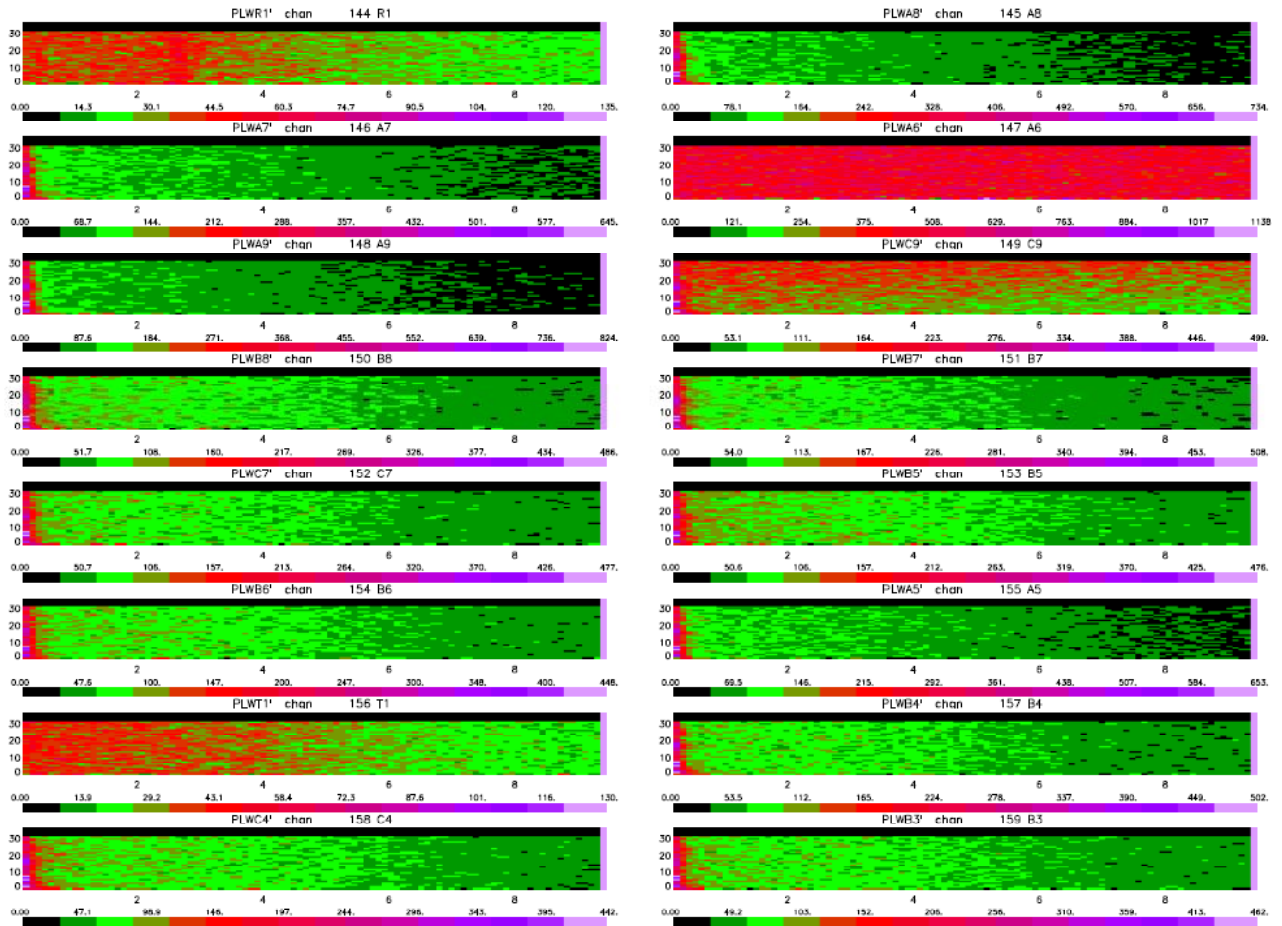


Figure 80

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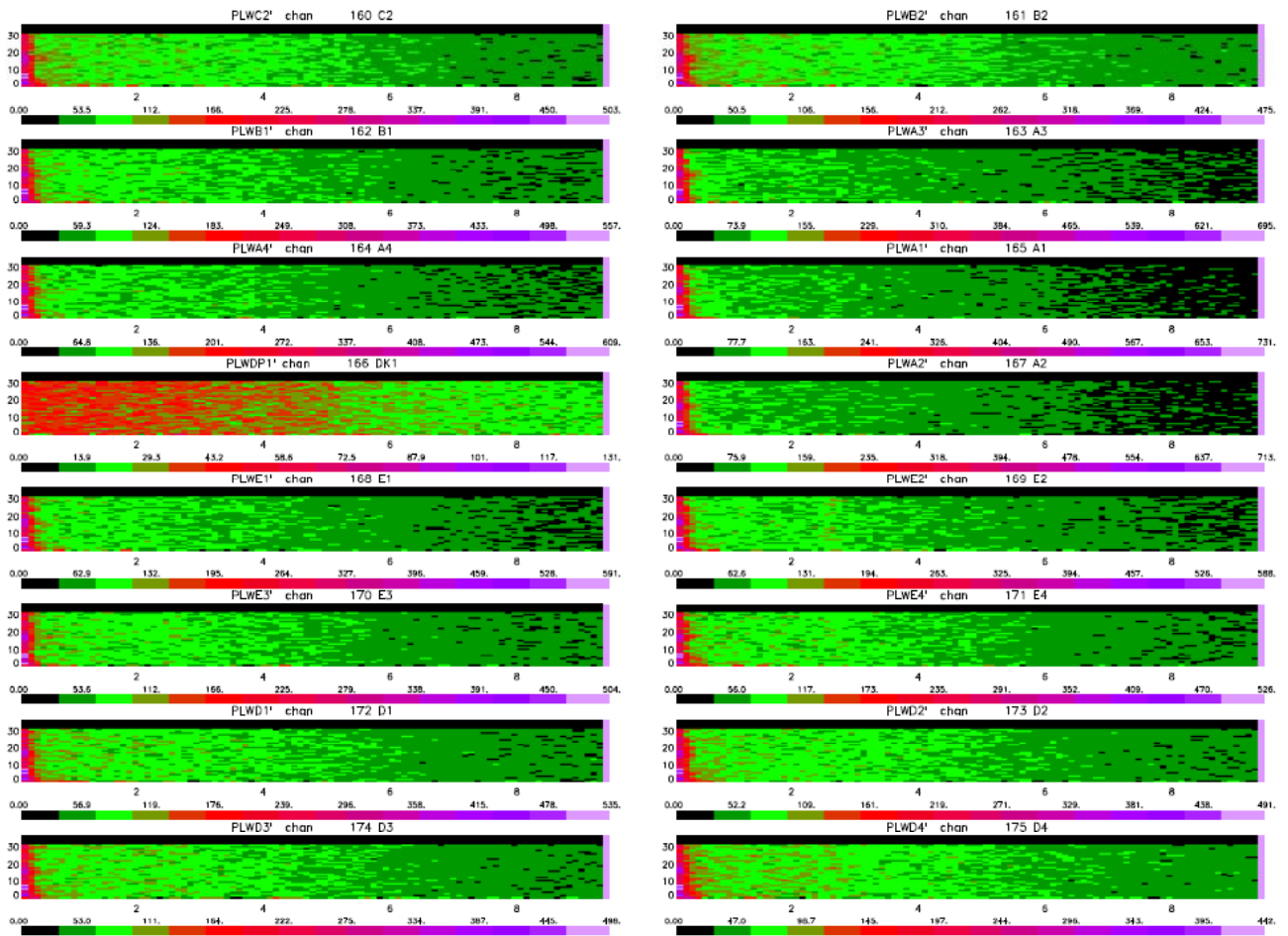


Figure 81

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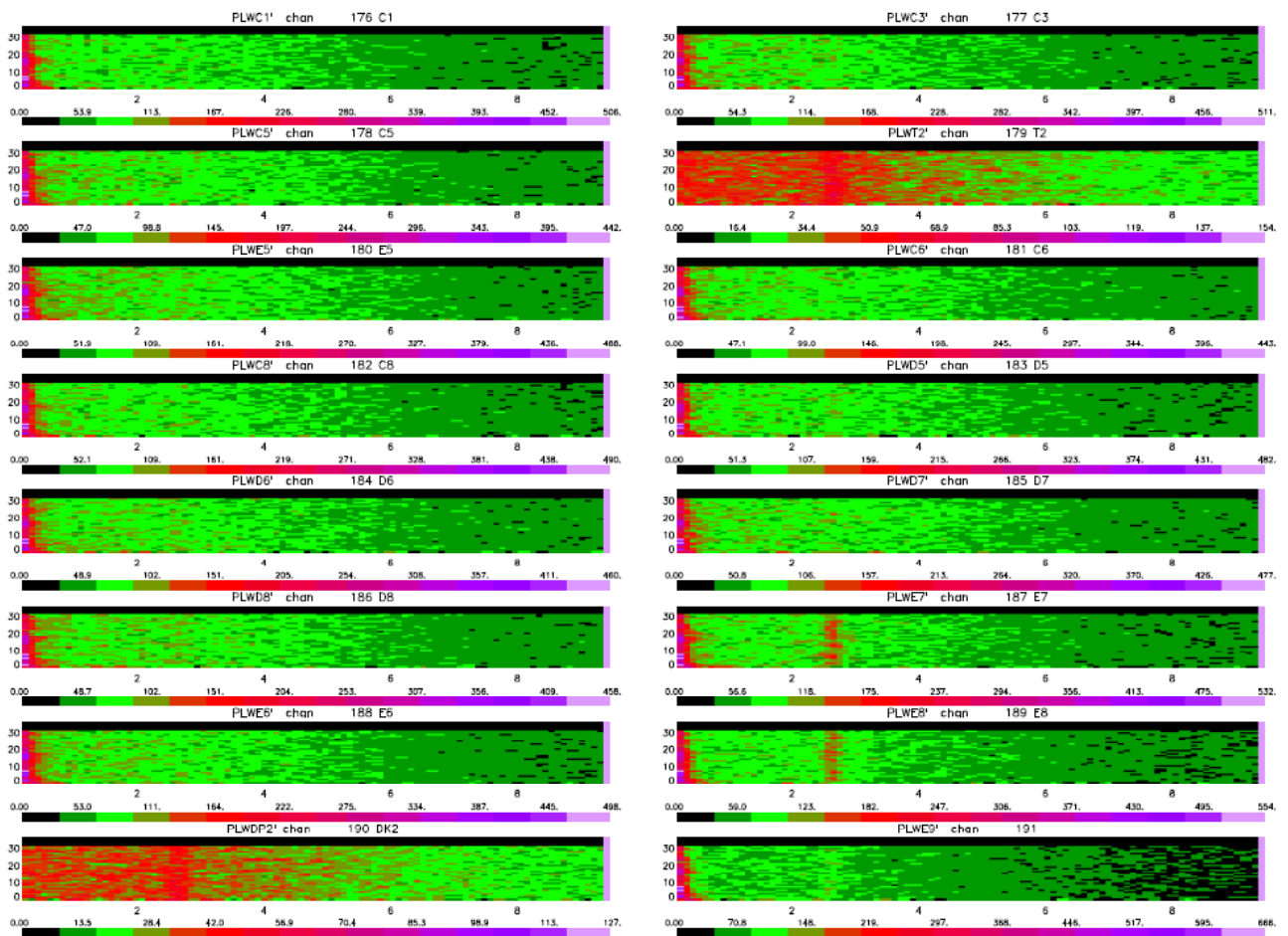


Figure 82

8.2.2 PMW Spectrogrammes

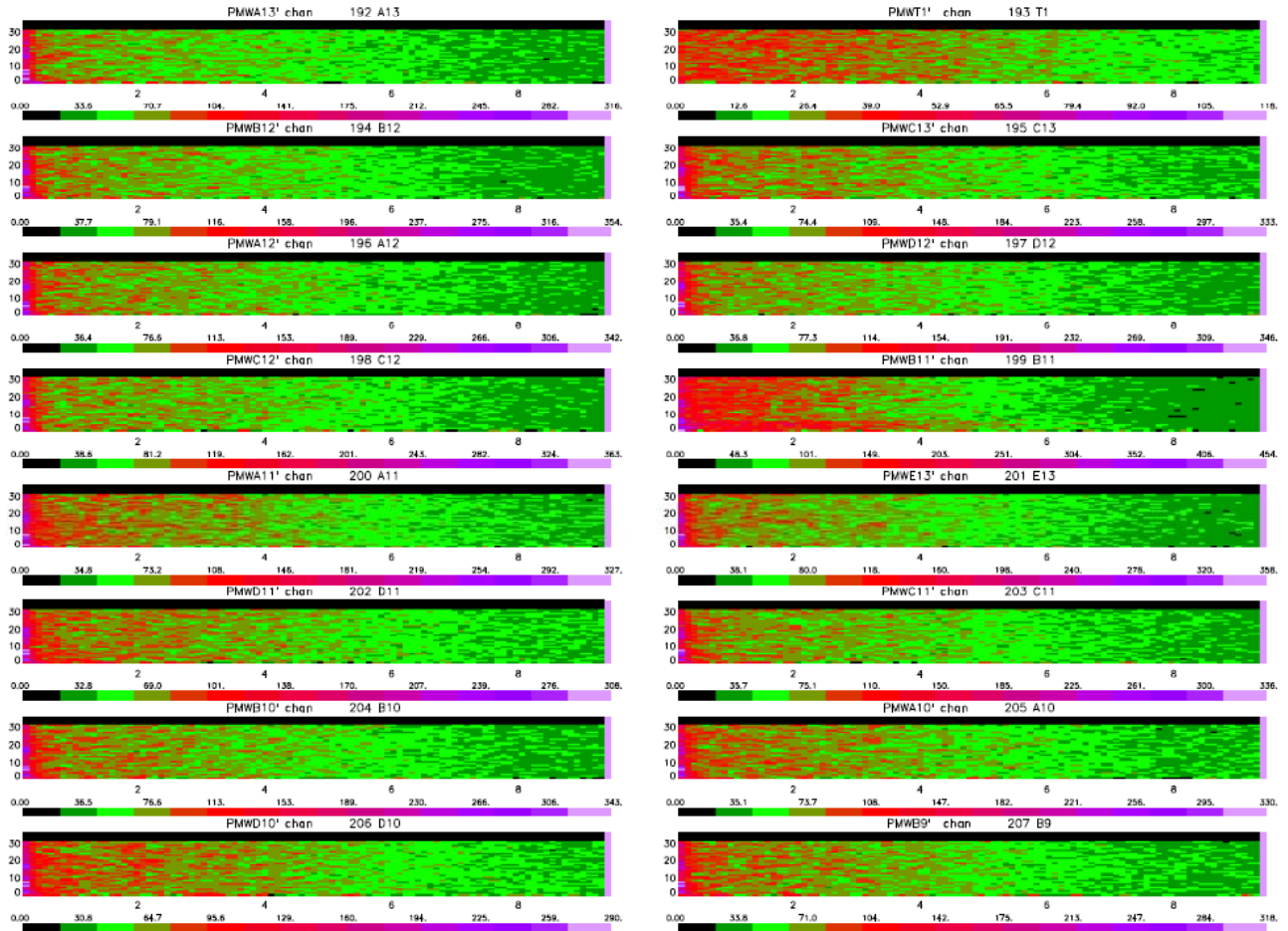


Figure 83

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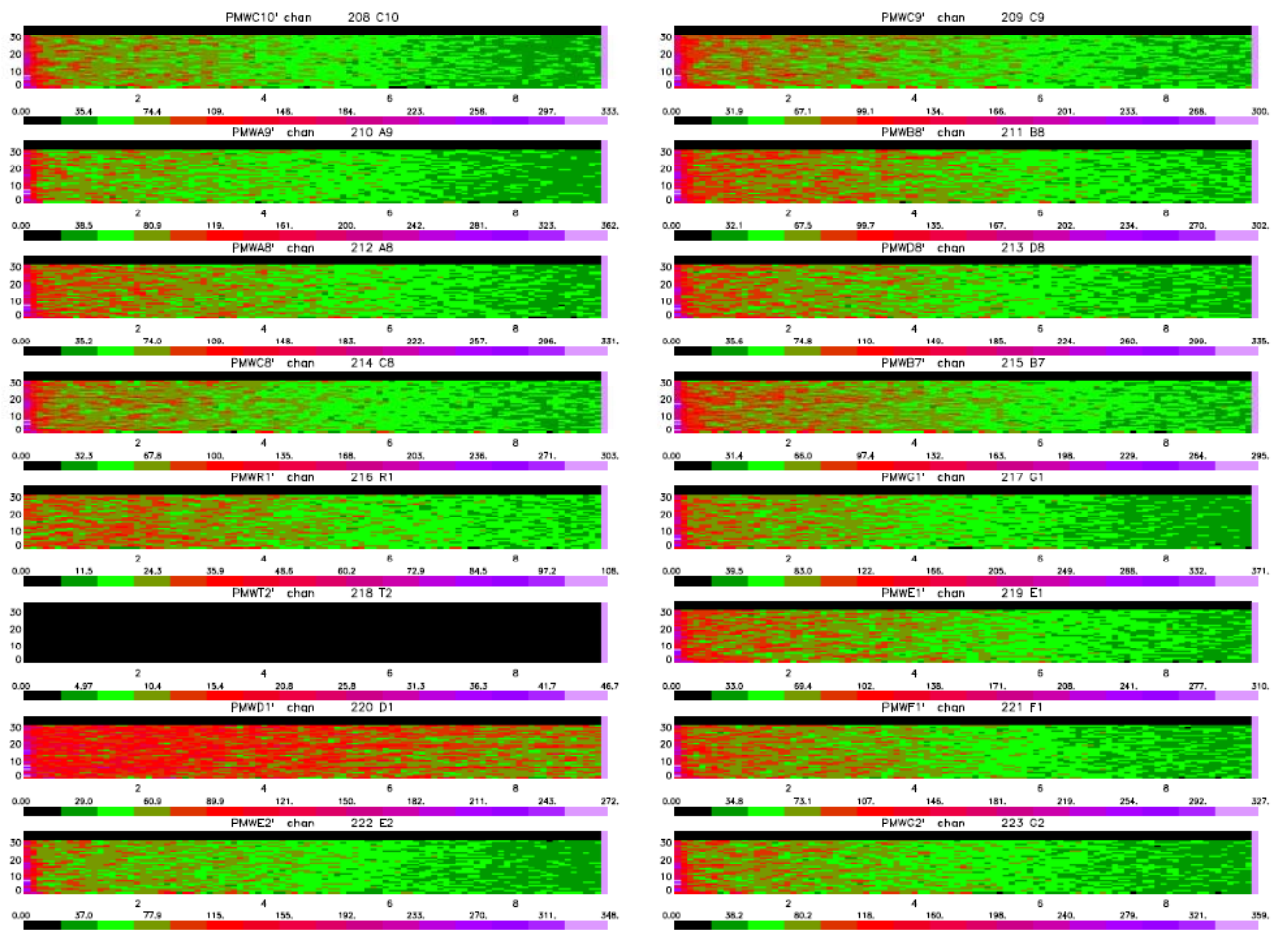


Figure 84

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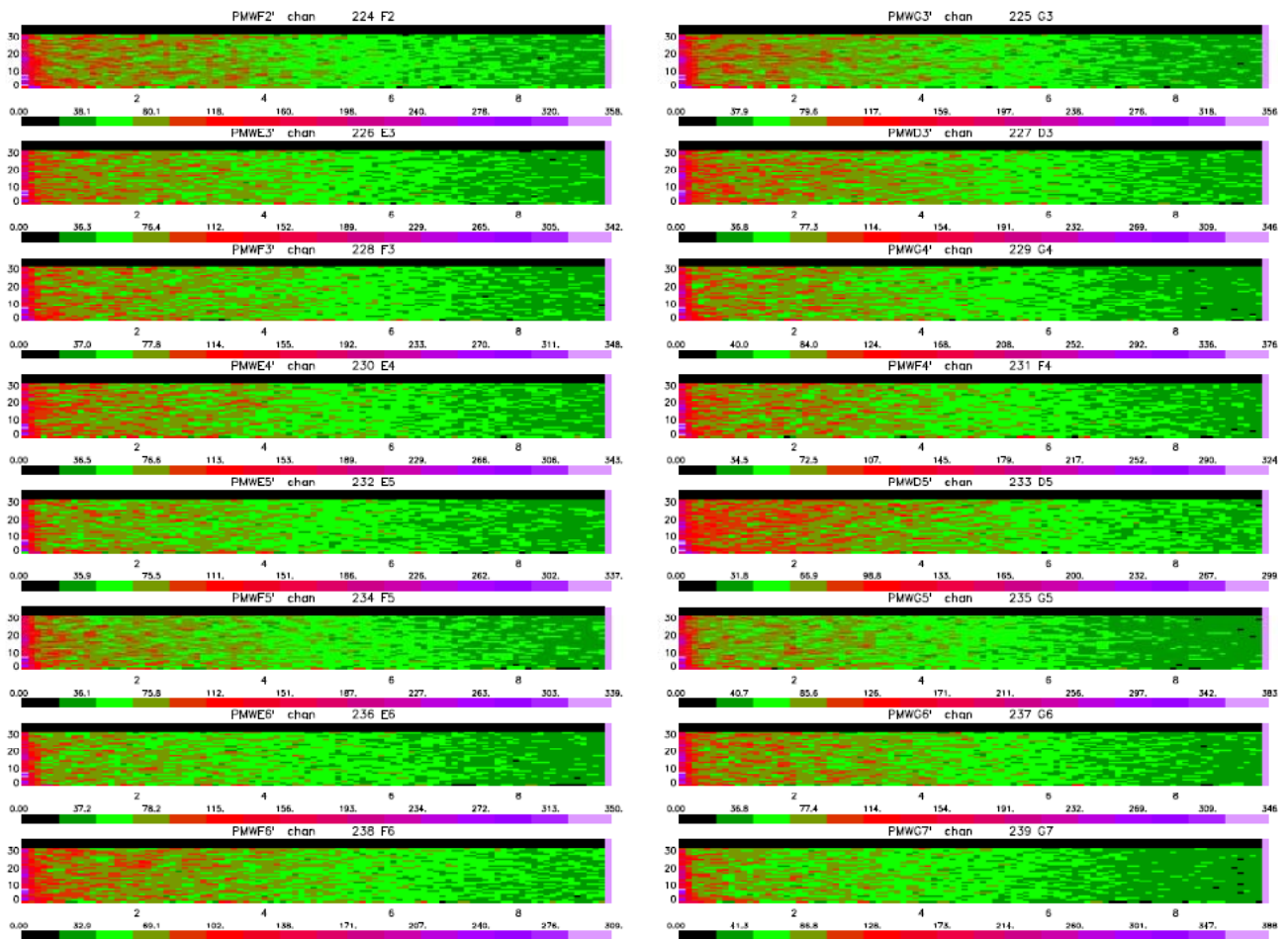


Figure 85

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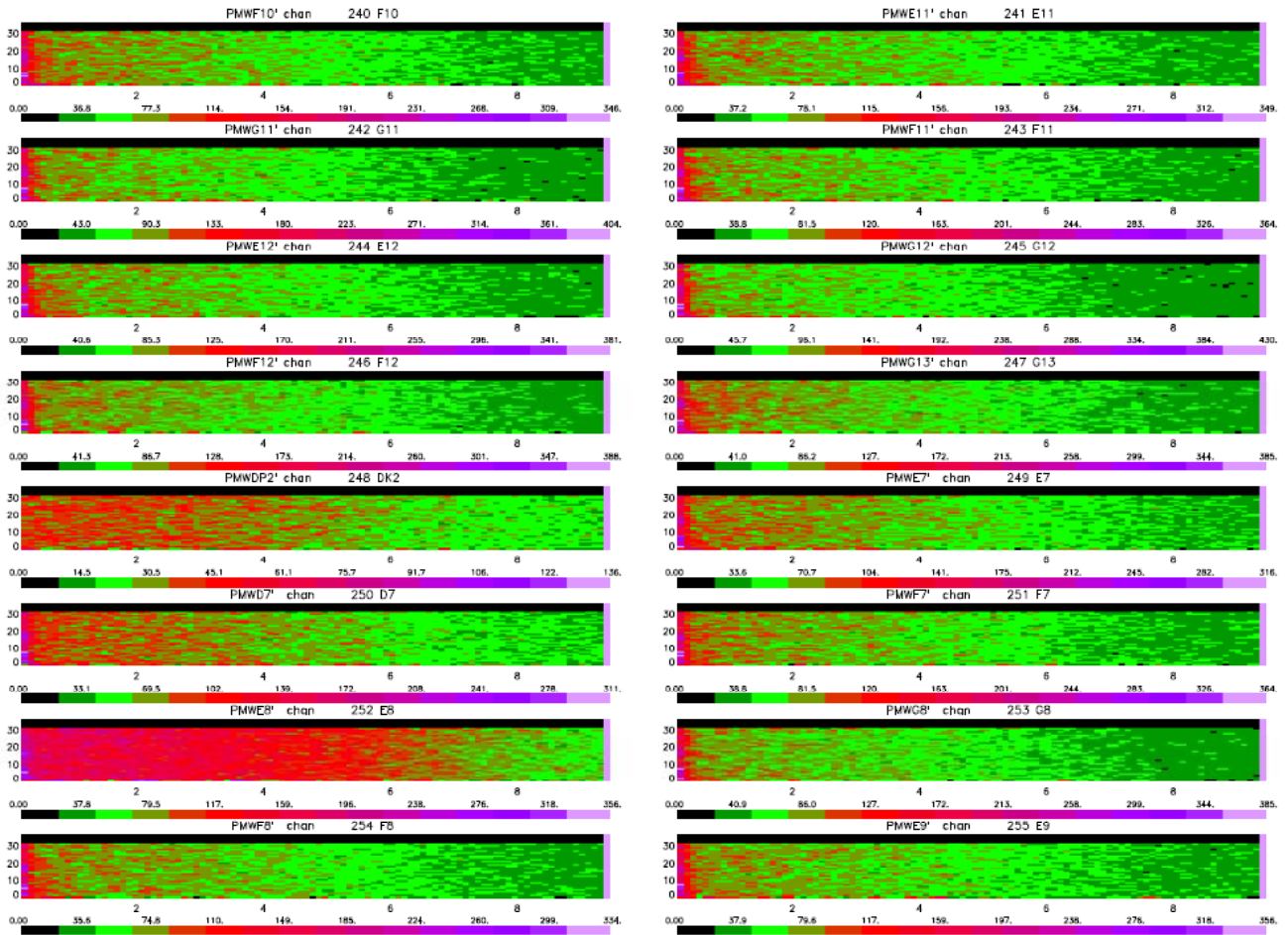


Figure 86

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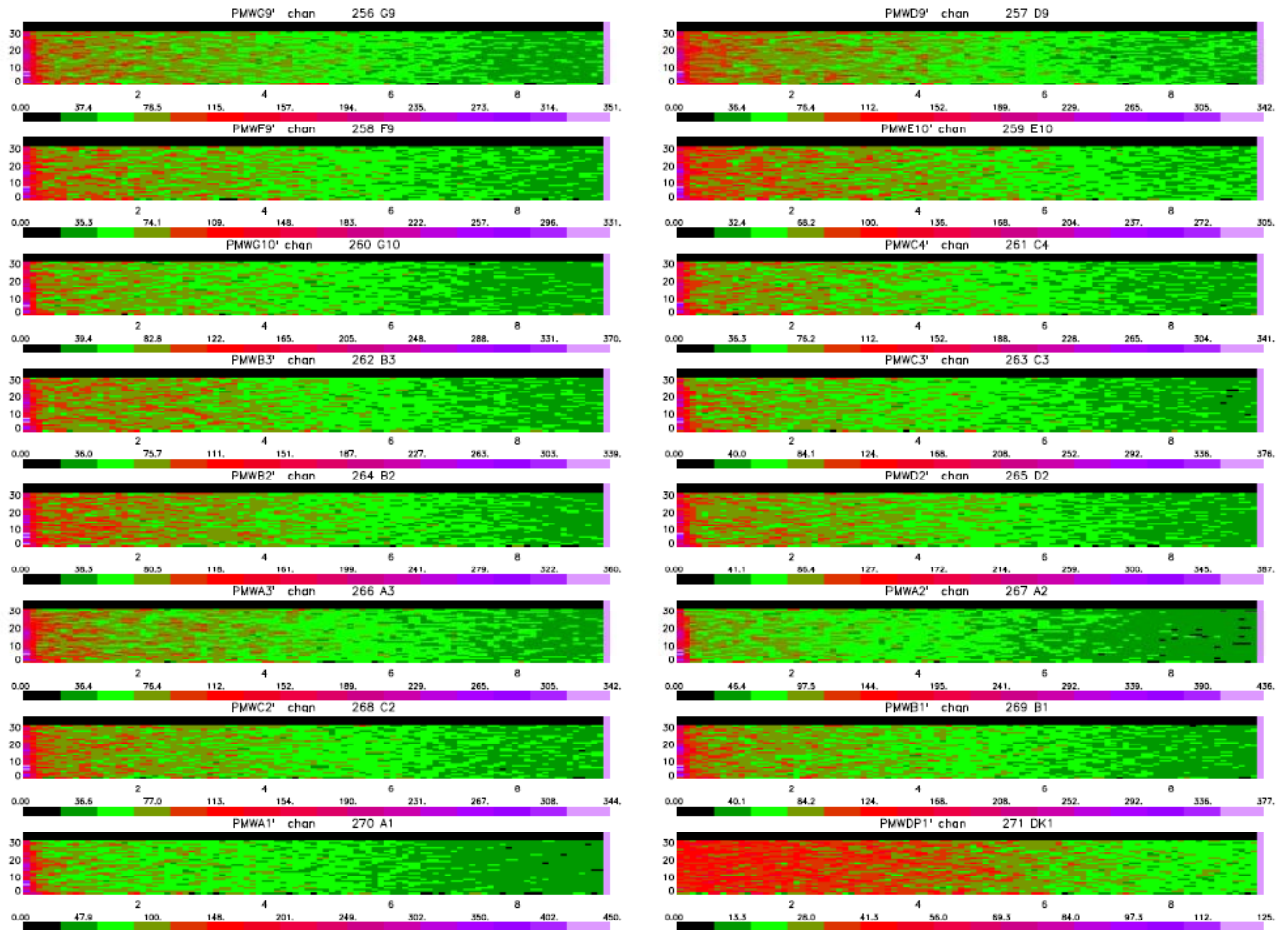


Figure 87

SPIRE SPT EMC Test Report

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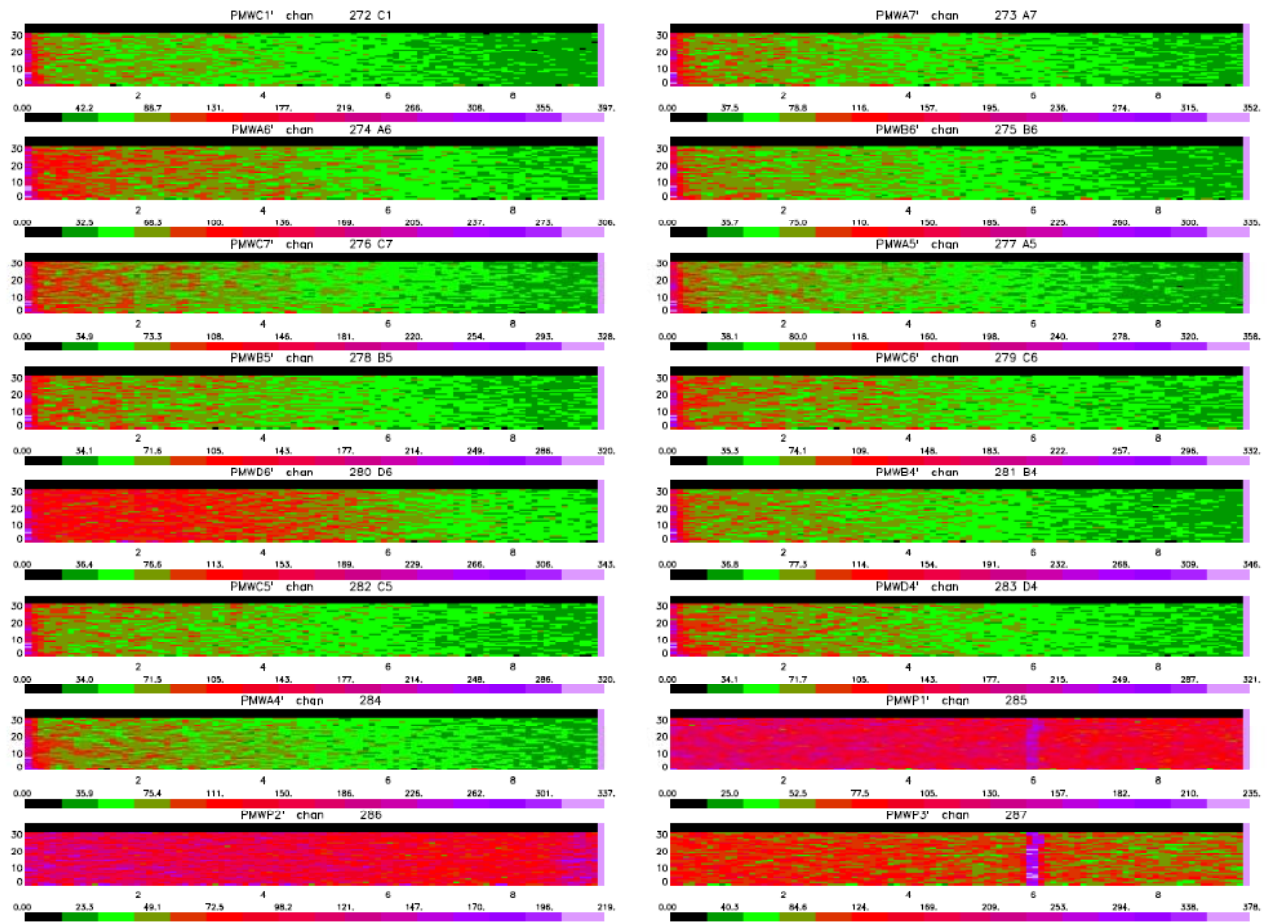


Figure 88

SPIRE SPT EMC Test Report

Ref: SPIRE-RAL-REP-003164

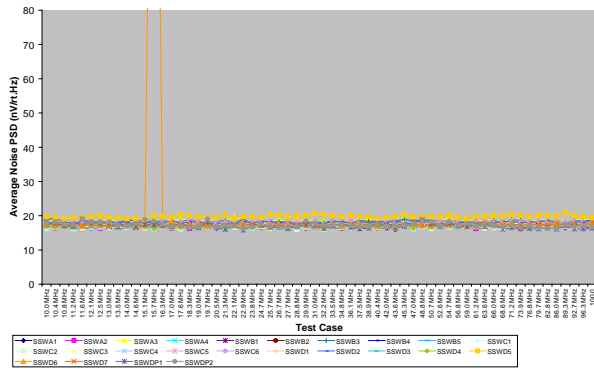
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8.3 RS – Spectrometer: V-Polarization (0xB00014E3)

SSW (A1-DP2)



8.3.1 SLW and SSW Spectrogrammes

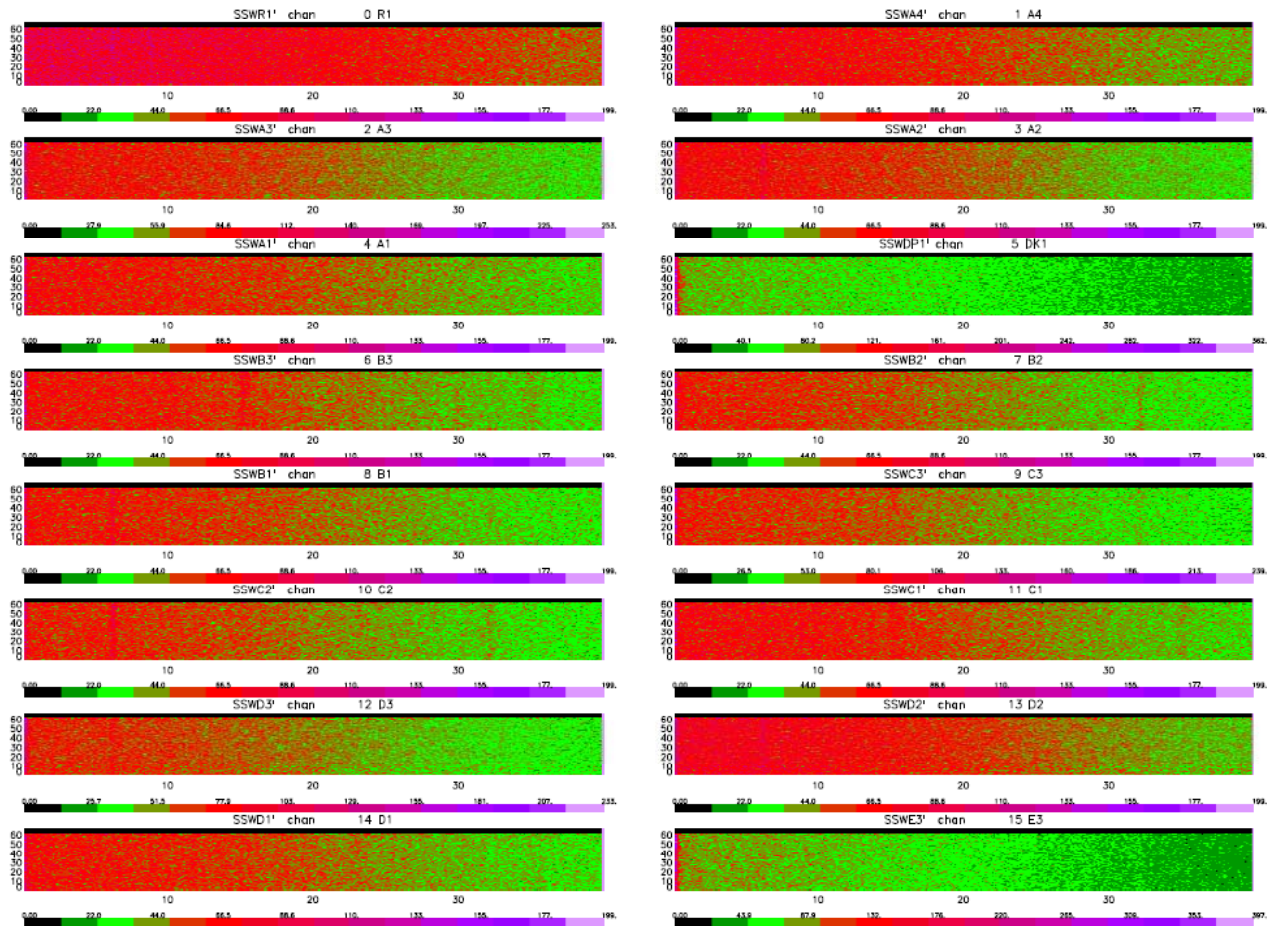


Figure 89

SPIRE SPT EMC Test Report

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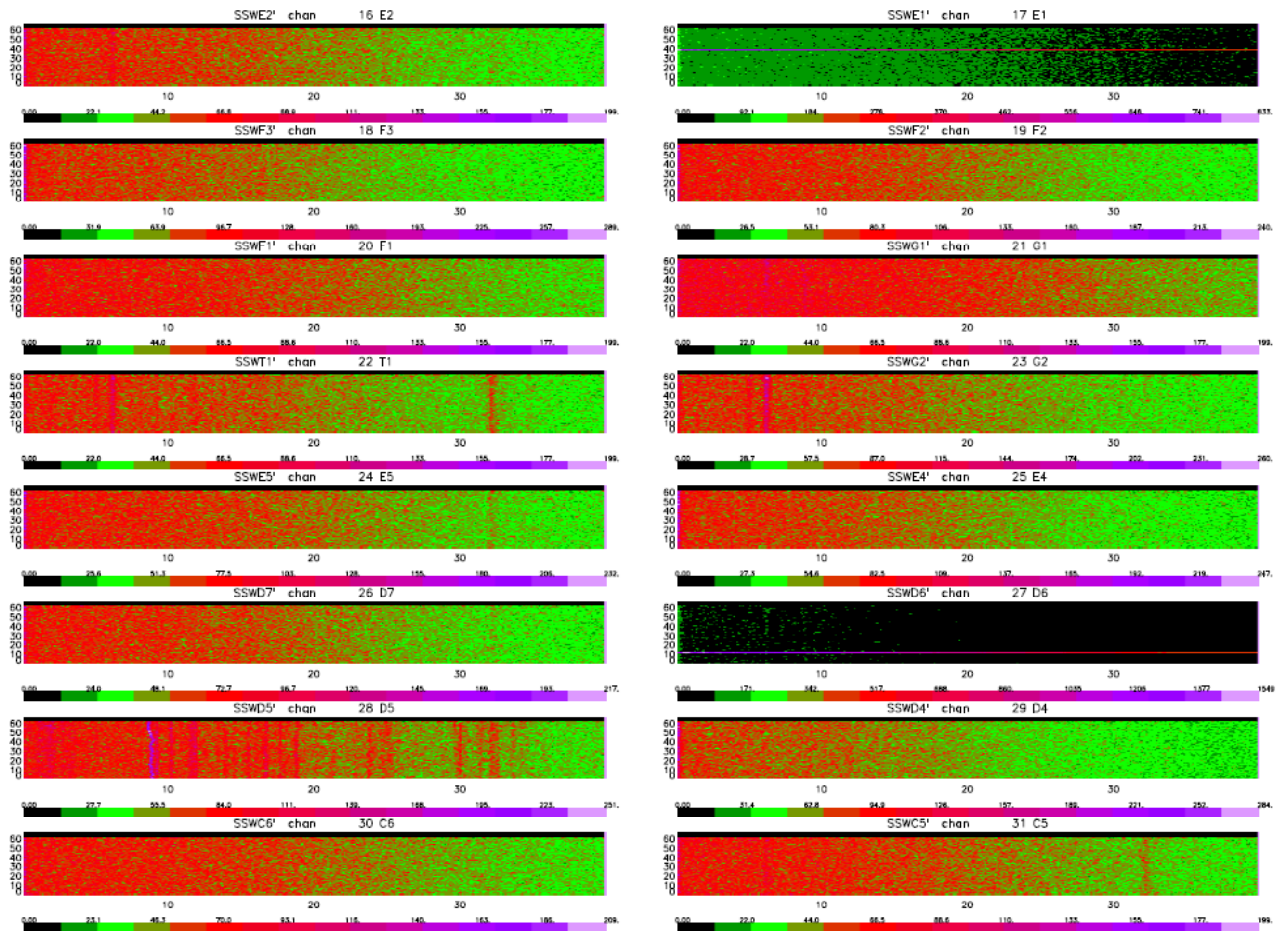


Figure 90

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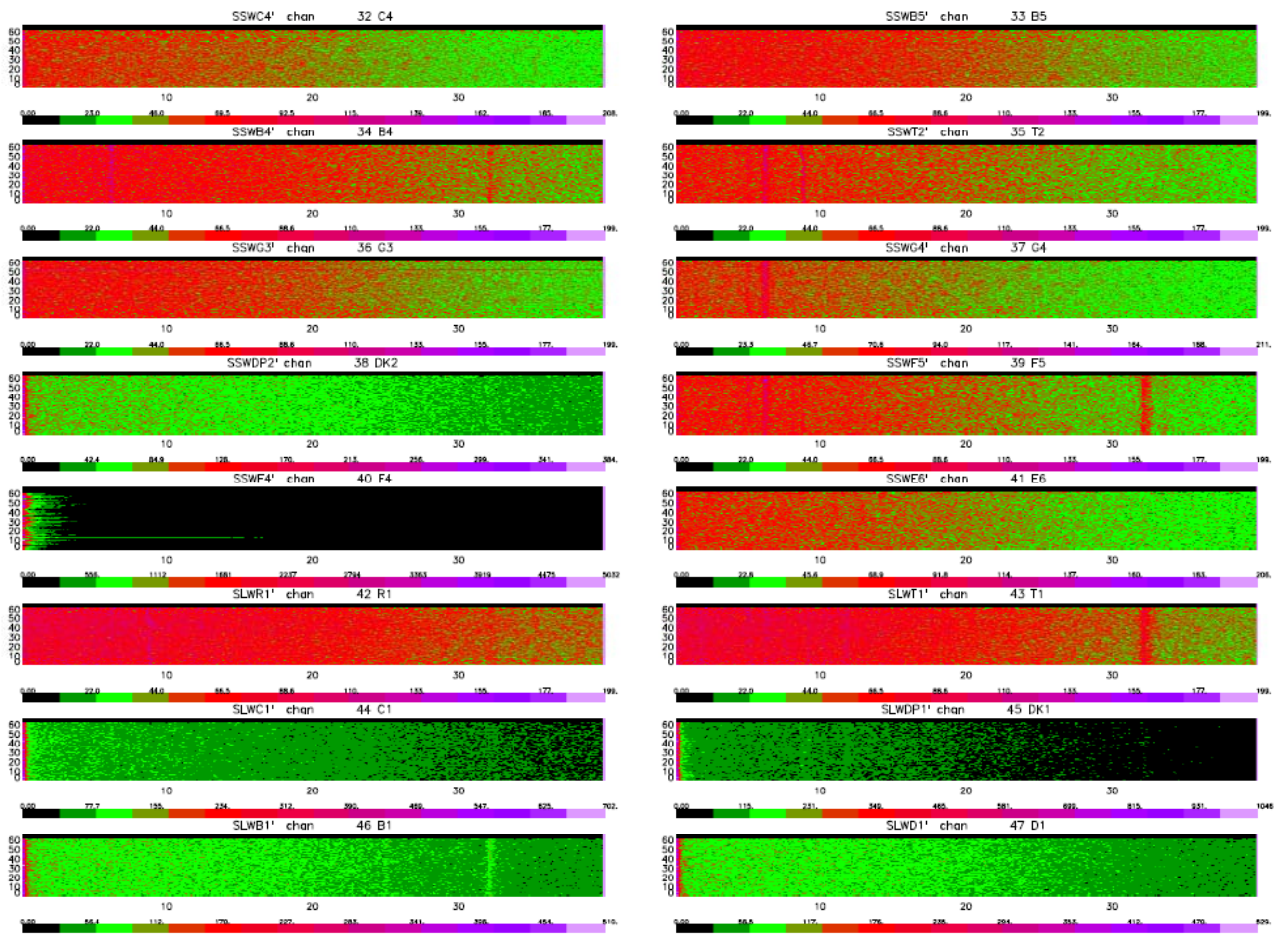


Figure 91

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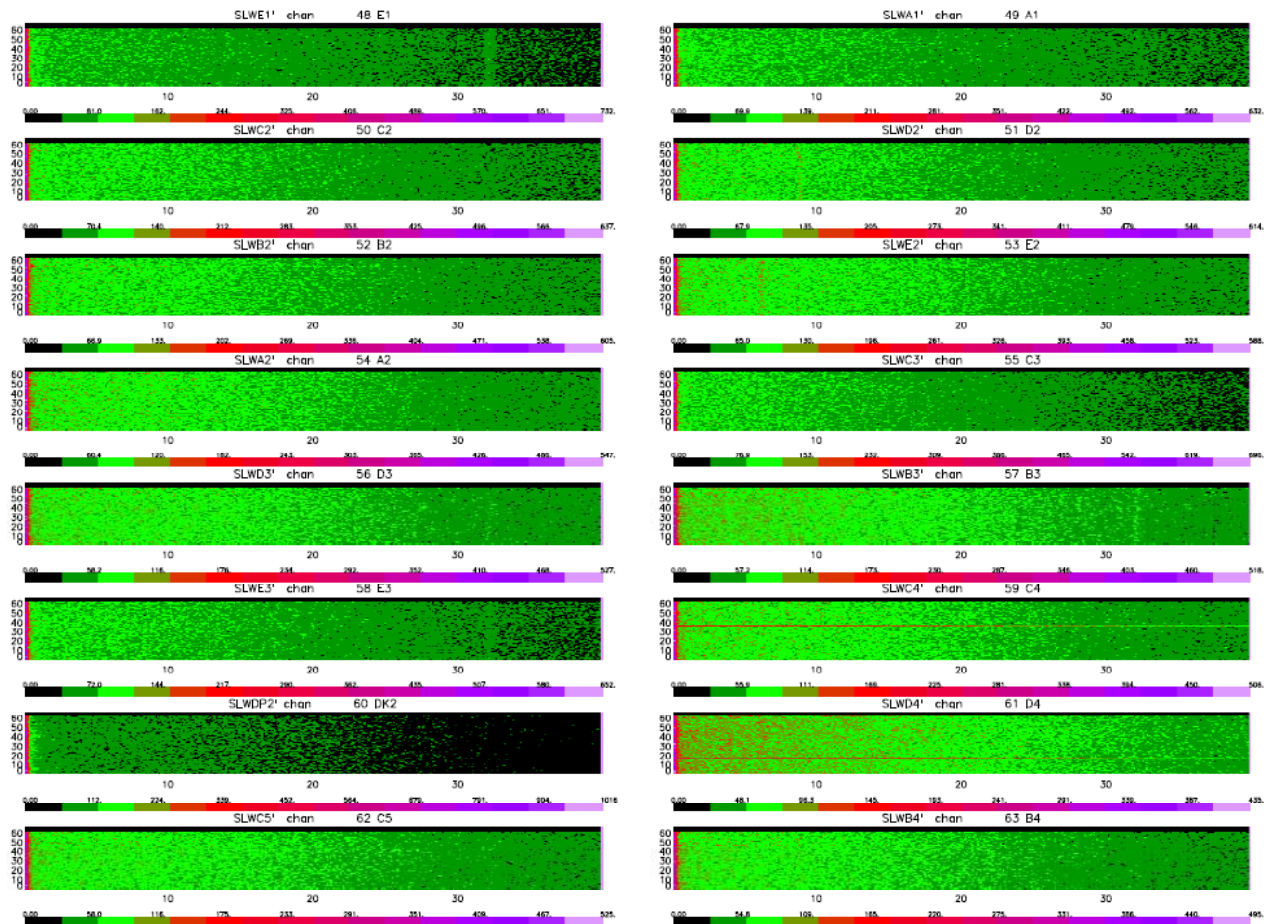


Figure 92

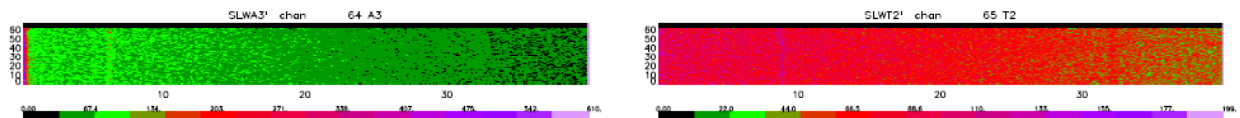


Figure 93

9. Appendix 4: RE Test Data

9.1 Key Spacecraft RE EMC Test results

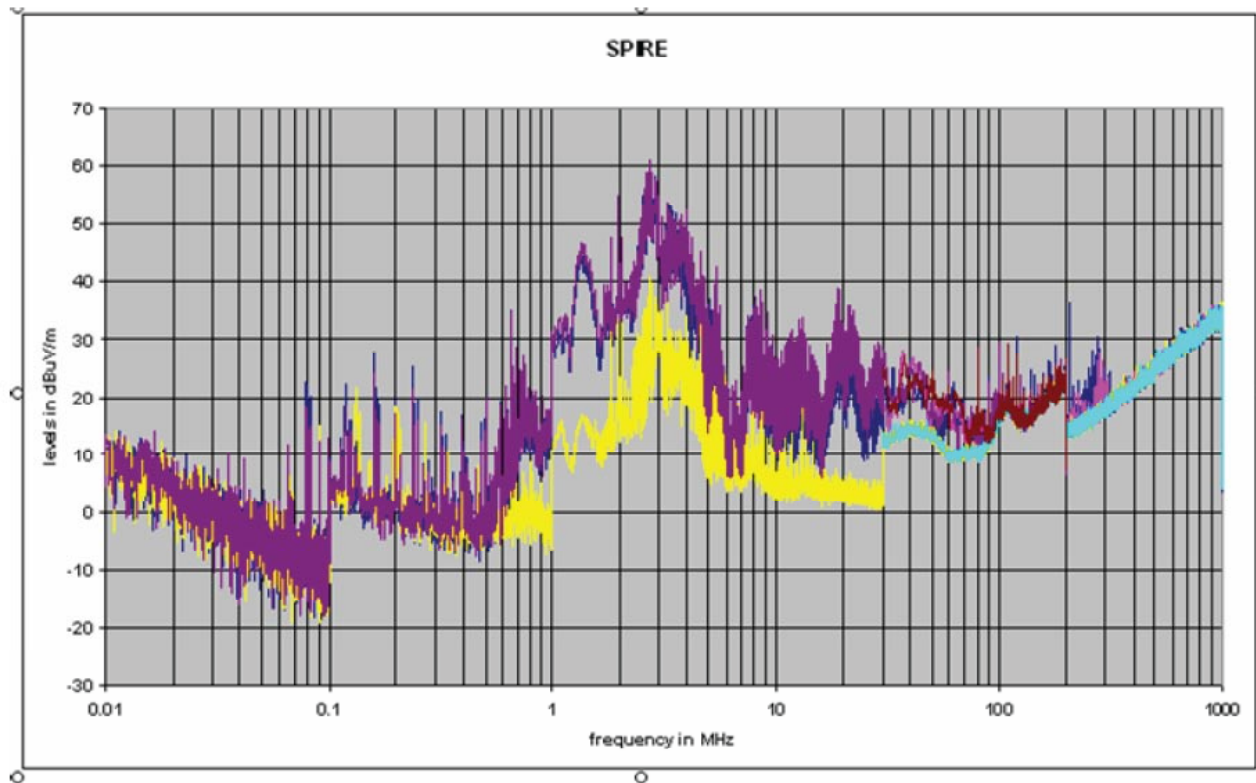


Figure 94 - RE Levels measured during the Herschel RE test in the Maxwell facility. The three traces correspond to three locations/polarizations close to the SPIRE cryoharness.

9.2 Ambient Electromagnetic Environment Monitoring

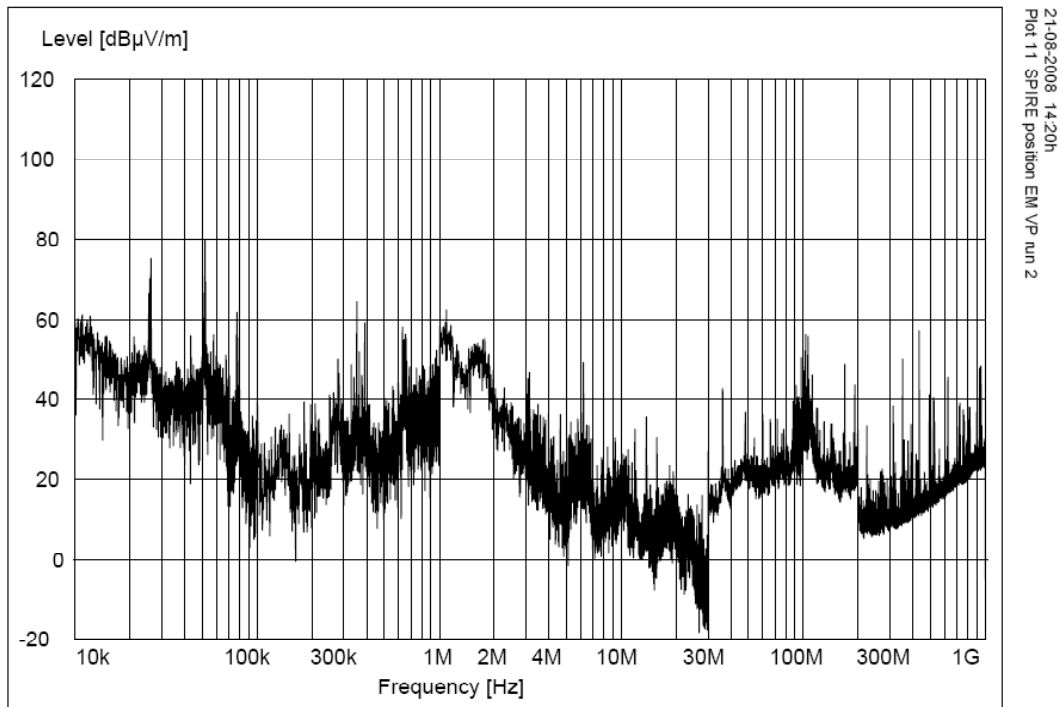


Figure 95 – E-Field ambient levels (Vertical polarization). From RD5.

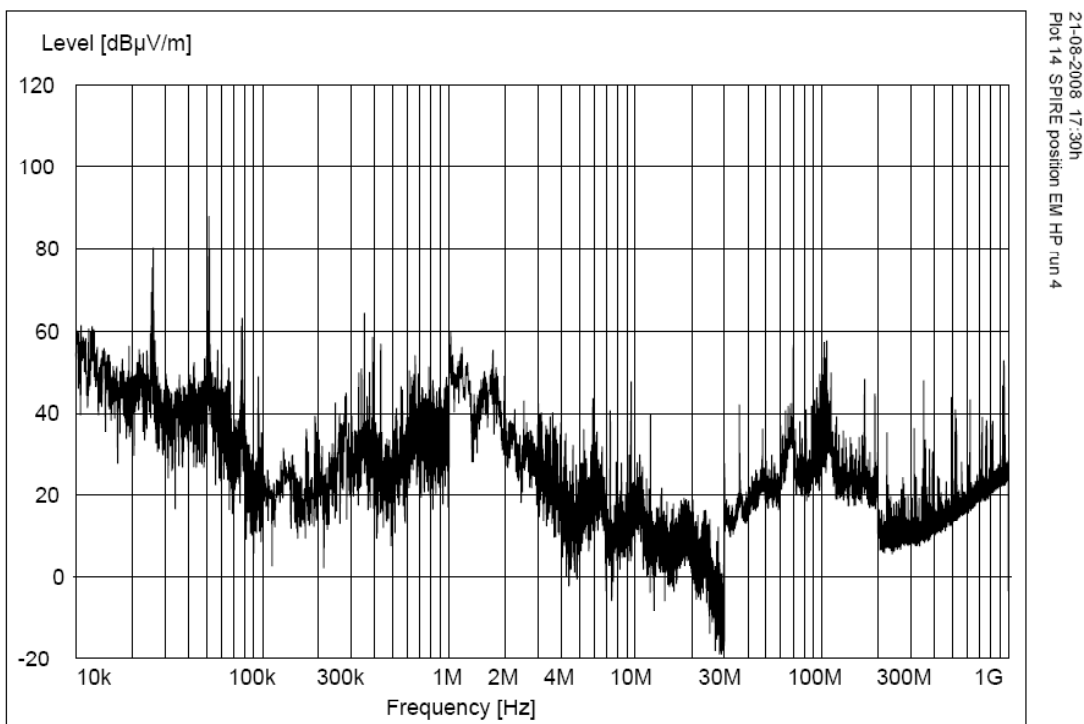


Figure 96 – E-Field ambient levels (Horizontal polarization). From RD5.

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